

Introduction to magnetometry techniques

Thomas Hauet

ESM2020, 01/10/2020



Most of the materials are magnetic

Parameters, symbols and units

$$\vec{B} = \mu_0 (\vec{H} + \vec{M}) = \underbrace{\mu_0 (1 + \chi)}_{\mu} \vec{H} \quad \text{avec} \quad \chi = \partial M / \partial H$$

Parameters : B (induction) in Tesla (= 10^4 Gauss = 10^4 Oe)
H (field) in A/m ($H = 1 \text{ A/m} \Rightarrow B = 1.256 \cdot 10^{-6} \text{ T}$)
M (magnetization) in A/m (= 10^{-3} emu/cm^3)
 μ_0 (free space permeability) = $4\pi \cdot 10^{-7} \text{ H/m}$
 χ (magnetic susceptibility)



Other material parameters : K (magnetic anisotropy energy) in J/m^3
J (magnetic exchange) in J/m
 α (damping) with no unit
 m_S , m_{orb} (spin, orbital atomic moment) in $\mu\text{B/atom}$



Your advisor needs to switch from CGS to SI : $1 \text{ emu/cm}^3 = 1 \text{ kA/m}$ $1 \text{ erg/cm}^3 = 0.1 \text{ J/m}^3$

Magnetometry

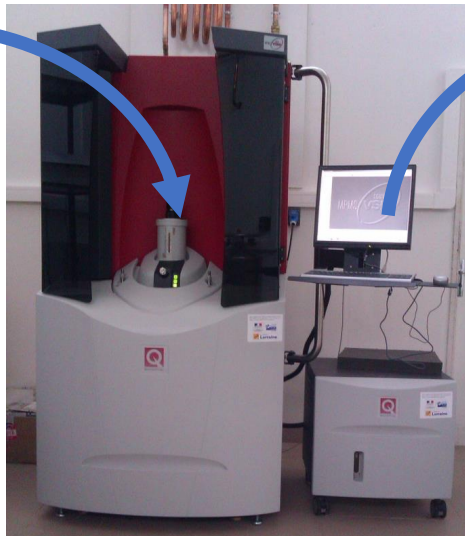
Measure of physical parameters

- Magnetic moment
- Magnetic susceptibility
- Electrical resistance
- Specific heat
- Ferromagnetic resonance...

.... as a function of external parameters

- DC or AC magnetic field
- Temperature
- Pressure
- Electric field
- Light...

Material/system



**Physical parameters as a function
of external parameters**

Magnetometry : before to start

What type of sample ? Nanoparticles, molecules, liquids, bulk, thin film, devices, ...

Which properties am I interested in ? Magnetic moment, susceptibility, spin or orbital moment, non-uniform configuration, damping, anisotropy, ...

Which resolution do I need ?

Which excitation do I want to study ? Magnetic field, temperature, electric field, light, pressure, ...

Under which static condition ? Temperature, vacuum, oxidant atmosphere, pressure, magnetic field, ...

Which time scale ? (excitation & measurement) Femtosecond, second, million years, ...

Which space scale ? (sample size & measurement) Nanometer, meter, hundred meter, milliliters...



Space and time scales

Space scale

1 cm

1 mm

100 μm

10 μm

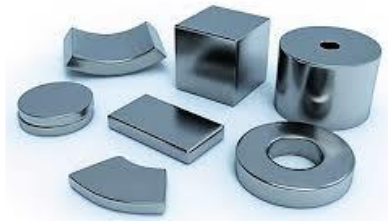
1 μm

100 nm

10 nm

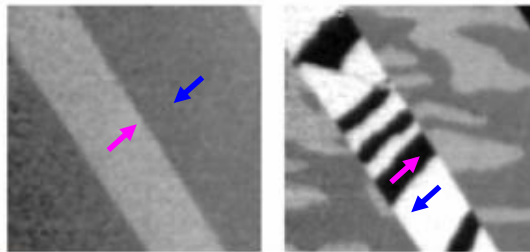
1 nm

100 pm

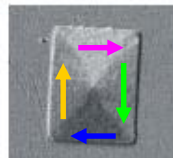


Macroscopic systems

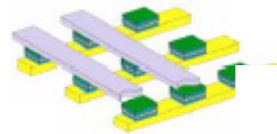
Magnetic domains



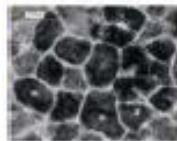
Micro/Nano-structures



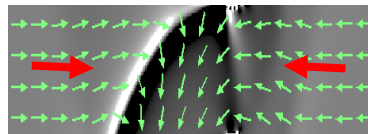
Memories and sensors



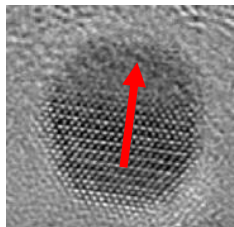
magnetic media



Domain wall



Nanoparticle, molecules



Time scale

100 ns

10 ns

1 ns

100 ps

10 ps

1 ps

100 fs

10 fs

1 fs

100 as

Domain wall motion

Thermal activation

Magnetic relaxation

Electronic spin precession

lattice

spin

electron

Magnetism - Lattice interaction

Spin-orbit interaction

Exchange interaction

Magnetometry : Outline

Vibrating sample magnetometry

Magneto-optical Kerr effect

Heat capacity measurement

Superconducting quantum interference device

Torque magnetometry

X-ray circular dichroism

ballistic electron magnetic microscopy

susceptometry

Ferromagnetic Resonance measurement

magnetic force microscopy

photoemission spectroscopy

magnetoresistivity

magnetic resonance force microscopy

N-V magnetometry

magnetic transmission X-ray microscopy

scanning electron microscopy with polarization analysis

scanning near field optical microscopy

spin polarized low energy electron microscopy

spin polarized scanning tunneling microscopy

scanning transmission X-ray microscopy

X-ray photoemission electron microscopy

Neutron diffraction



Outline : 1h30 talk

Vibrating sample magnetometry

Magneto-optical Kerr effect

Heat capacity measurement

Superconducting quantum interference device

Torque magnetometry

X-ray circular dichroism

ballistic electron magnetic microscopy

susceptometry

Ferromagnetic Resonance measurement

magnetic force microscopy

photoemission spectroscopy

magnetoresistivity

magnetic resonance force microscopy

N-V magnetometry

magnetic transmission X-ray microscopy

scanning electron microscopy with polarization analysis

scanning near field optical microscopy

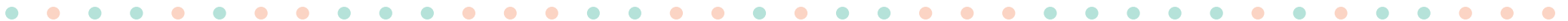
spin polarized low energy electron microscopy

spin polarized scanning tunneling microscopy

scanning transmission X-ray microscopy

X-ray photoemission electron microscopy

Neutron diffraction



Many available data in ESM library

Fichier Édition Affichage Historique Marque-pages Outils Aide

AC susceptometry - Recherche X A simple torque magnetometer X European School on Magnetism X +

magnetism.eu/esm/repository-topics.html

Rechercher

Les plus visités Débuter avec Firefox Authentification auto... Web of Science [v.5.30...]

[2003] Self-organization on surfaces: an overview: [U. FRUCHART](#) [[Abstract](#) | [Slides](#)]

[2003] Chemical synthesis of magnetic metal nanoparticles : [B. CHAUDRET](#) [[Abstract](#)]

Magnetic microscopy

Dresden, Germany [[Abstract](#)]

[2019] Electron holography and tomography: [AXEL LUBK](#), Dresden, Germany [[Abstract](#)]

[2019] Holography, tomography (Electron, X-ray): X-rays: [JAN LÜNING](#), Berlin, Germany [[Abstract](#)]

[2019] Scanning probe microscopy for magnetism: [OLIVIER FRUCHART](#), Grenoble, France [[Abstract](#)]

[2017] Characterization techniques for nano-sized systems: [OLIVIER FRUCHART](#), Grenoble, France [[Abstract](#) | [Slides](#)]

[2015] Magnetic imaging techniques: [LAURA HEYDERMAN](#), Zürich, Switzerland [[Abstract](#) | [Intro](#) | [Kerr](#) | [Scanning probe](#) | [PEEM](#)]

[2013] Magnetic imaging techniques: [LAURA HEYDERMAN](#), Zürich, Switzerland [[Abstract](#) | [Slides](#)]

[2007] Magneto-optical microscopy and its applications: [RUDOLF SCHÄFER](#), IFW, Dresden, Germany [[Abstract](#) | [Slides pt.1-2](#)]

[2007] STM and spectroscopy of nanosized ferromagnetic structures: [GUILLEMIN RODARY](#), MPI-Halle, Germany [[Slides](#)]

[2005] Magneto-optical microscopy (incl. time resolved): [J. McCORD](#) [[Abstract](#) | [Slides](#) (12.6MB)]

[2005] Scanning probe techniques (MFM, SNOM, etc): [L. ABELMANN](#) [[Abstract](#) | [Slides](#) (3.5MB) | [Supplementary information \(AVI\)](#) (2.6MB)]

[2005] STM and spin-polarized-STM: [W. WULFHEKEL](#) [[Abstract](#) | [Slides pt1](#) (5.6MB) | [Slides pt2](#) (2.3MB)]

[2005] Magnetic imaging by LEEM, X-PEEM, X-ray microscopy, and X-ray holography: [W. KUCH](#) [[Abstract](#) | [Slides](#) (5.4MB)]

[2005] Electron microscopies (Lorentz, holography, SEMPA, etc): [B. WAROT-FONROSE](#) [[Abstract](#) | [Slides](#) (11.5MB)]

[2003] Analysis of nanostructures by electron Microscopy (EM) and Scanning Probe Microscopy (SPM) (structural and compositional analysis): [M. HIETSCH](#)

[2003] High spatial-resolution analysis of magnetic properties (special SPM and EM techniques as SHPFM and Lorentz-Microscopy) [M. HIETSCHOLD](#) [[Abstract](#)]

[2003] Magnetic force microscopy (MFM) and spin polarized scanning tunneling microscopy (SPSTM): [A. THIAVILLE](#) [[Abstract](#) | [Slides](#)]

Magnetometry

[2019] General and torque magnetometry: [VITTORIO BASSO](#), Torino, Italy [[Abstract](#)]

[2019] Indirect techniques: calorimetry, dilatometry, transport: [VITTORIO BASSO](#), Torino, Italy [[Abstract](#)]

[2018] Magnetometry: [PAOLO VAVASSORI](#), San Sebastian, Spain [[Abstract](#) | [Slides](#)]

[2018] Tutorial: experimental methods for magneto-optical Kerr effects measurements: [PAOLO VAVASSORI](#), San Sebastian, Spain [[Slides](#)]

[2005] Advanced Magnetometry: [D. SANDER](#) [[Abstract](#) | [Slides](#) (2.3MB)]

[2003] Nanomagnetometry: microSQUID, Hall microprobe: [E. BONET](#) [[Abstract](#) | [Slides](#)]

Optics and X-ray tools (structural and magnetic)

[2019] Magneto-optics: [RUDOLF SCHÄFER](#), Dresden, Germany [[Abstract](#)]

[2019] Holography, tomography (Electron, X-ray): X-rays: [JAN LÜNING](#), Berlin, Germany [[Abstract](#)]

[2019] X-ray techniques: synchrotron, FEL, HHG: [JAN LÜNING](#), Berlin, Germany [[Abstract](#)]

[2019] Time-resolved pump-probe techniques: [THEO RASING](#), Nijmegen, The Netherlands [[Abstract](#)]

[2018] X-ray magnetic dichroism: [EBERHARD GOERING](#), Stuttgart, Germany [[Abstract](#) | [Slides](#) (Pt.1, Pt.2)]

[2018] Synchrotron radiation: [MARCIN SIKORA](#), Kraków, Poland [[Abstract](#) | [Slides](#)]

Neutrons

[2019] Neutron scattering: [VIRGINIE SIMONET](#), Grenoble, France [[Abstract](#)]

[2017] Magnetic diffraction with neutrons, non-resonant and resonant X-ray scattering, [2017] Neutron diffraction for magnetic structure determination: [VIRGINIE SIMONET](#), Gr

[2011] Spin waves: theory and neutron scattering: [SYLVAIN PETIT](#), CEA-Saclay, France

[2011] Neutrons for magnetism: [STEPHEN BLUNDELL](#), Oxford, UK: [[Abstract](#) | [Slides](#)]

[2005] Neutrons and magnetism: [A. WILDES](#) [[Abstract](#) | [Slides-pt1](#) (23.0MB) | [Slid](#)

[2005] Magnetic scattering: X-ray and neutrons: [CH. VETTER](#) [[Abstract](#) | [Slides](#) (1.8

Precessional techniques

[2019] Magnetic resonance: [LAURENT RANNO](#), Grenoble, France [[Abstract](#)]

[2011] Muons for time-dependent studies in magnetism: [ANDREICA, D.](#), UBB - Cluj-Nap

[2011] Local and resonance techniques: FMR, EPR, NMR, Mössbauer: [PHILIPPE MEN](#)

[2005] Using muons for magnetization studies: [D. ANDREICA](#)

Electron spectroscopies

[2005] XPS, including spin-polarized XPS: [M. NEUMANN](#) [[Slides](#) (3.5MB)].

[2005] Surface magnons by EELS: [J. KIRSCHNER](#) [[Abstract](#) | [Slides](#) (1.9MB)]

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Outline

I. Few preliminary details about the sample environment

➡ Magnetic field, Temperature

II. Static macroscopic magnetometry techniques

➡ VSM, SQUID, Torque, MOKE, XMCD

III. AC macroscopic magnetometry techniques

➡ AC susceptometry

IV. Imaging techniques

➡ Scanning probe microscopies, Photon-out

Help from European/French magnetometry networks

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Home > NETWORK > Magnetometry.eu

The European Magnetometry Network

MAGNETOMETRY.EU

The European Magnetometry Network

Magnetometry.eu is a European network on magnetometry created in 2017 [under name **Mag-Net(-o-Metry)**], under the auspices of EIT KIC RawMaterials. It ambitions to help define, create and protect jobs in universities, research institutions, SMEs and industries through instrumentation, novel science, innovating products and processes, as well as new industrially compatible characterization methods.

Objectives

Maintain a federated community around magnetometry, for networking and to help define and create jobs through novel instrumentation (...)

Focus

Promote magnetometry, provide training, facilitate access to plateforms, promote R&D collaborations governmental institutions and companies (...)

R&D service catalogue

NETWORK

- ◆ The SpinTronicFactory
- ◆ Magnetometry.eu
 - > Objectives
 - > Focus
 - > R&D service catalogue
 - > Join
- ◆ The European Physical Society
- ◆ Magnetism societies

Special thanks to F. Mazaleytrat, Ph. Vanderbemden, L. Ranno, C.-S. Chang, B. Hillebrands, O. Fruchart

Outline

I. Few preliminary details about the sample environment

➡ **Magnetic field**, Temperature

II. Static macroscopic magnetometry techniques

➡ VSM, SQUID, Torque, MOKE, XMCD, Photo-emission spectroscopy

III. AC macroscopic magnetometry techniques

➡ AC susceptometry, FMR

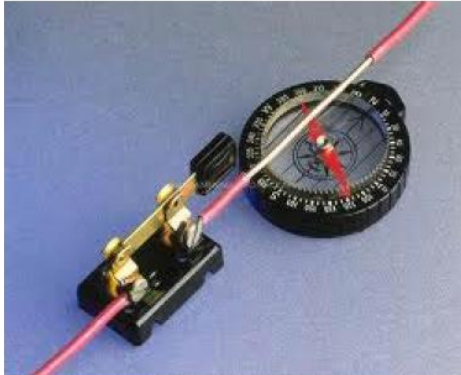
IV. Imaging techniques

➡ Scanning probe microscopies, Photon-out, Electron-out

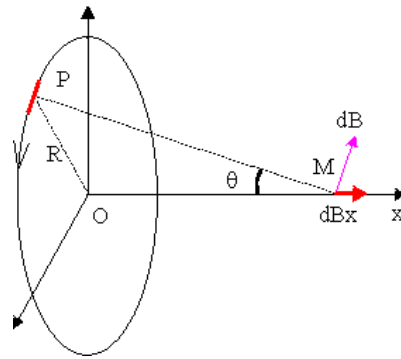
Magnetic field amplitude scale

Human brain	10^{-15} T
Earth's magnetic field	5×10^{-5} T
Refrigerator magnet	0.05 T
Computer	0.1 T
MRI scanner	1 - 7 T
Laboratoire de Champs Magnétiques Intenses	37 T
Pulsed field magnet	100 T
White dwarf star	10 000 T
Pulsar	100 000 000 T

How to generate a magnetic field



1820 - Hans Christian Oersted

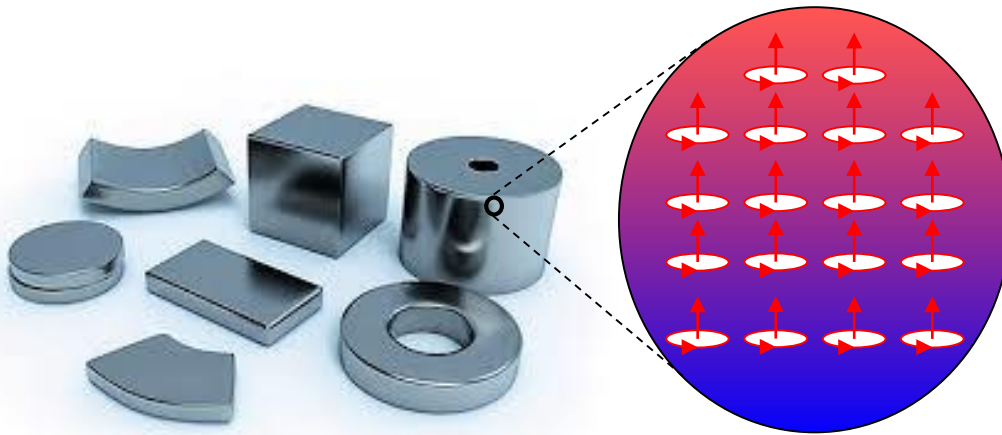


$$d\vec{B}(\vec{r}) = \frac{\mu_0}{4\pi} \frac{I d\vec{l} \wedge (\vec{r} - \vec{r}')}{|\vec{r} - \vec{r}'|^3}$$

Electromagnets :

- Requires electric energy
- **1 coil with R=25mm and 40 kA generates 1 Tesla**
- Non-uniform or uniform fields
- Field can be tuned easily with current
- Can produce **DC, AC or pulsed fields** (μs , ns)

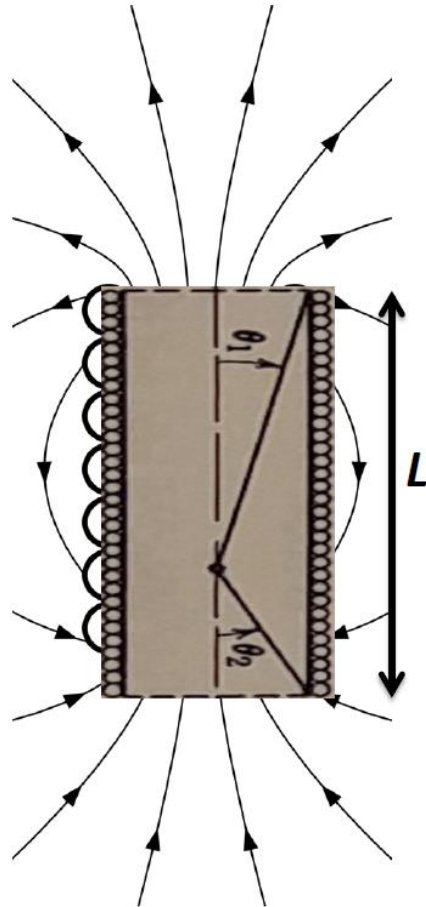
Permanent magnets :



- Assembly of dipoles $\vec{B} = \frac{\mu_0}{4\pi} \left[\frac{3(\vec{\mathcal{M}} \cdot \vec{r}') \cdot \vec{r}'}{r'^5} - \frac{\vec{\mathcal{M}}}{r'^3} \right]$
- **DC Magnetic flux with no energy**
- Non-uniform and uniform fields
- Big advantage for small sample space

Electromagnets : homogeneous field up to 3 Tesla

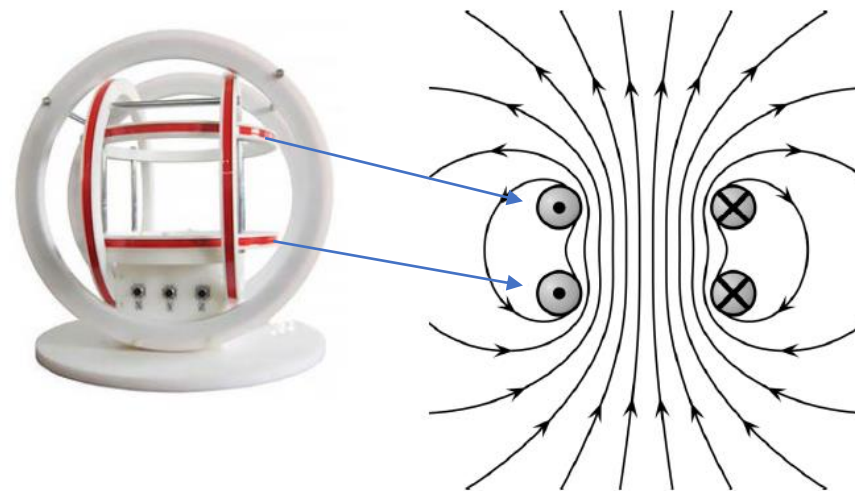
Coilset with N turns



Field along z-axis for N turns, current I and length L

$$B_z(z) = \frac{NI}{L} (\cos \theta_1 + \cos \theta_2)$$

Coilset in Helmholtz geometry

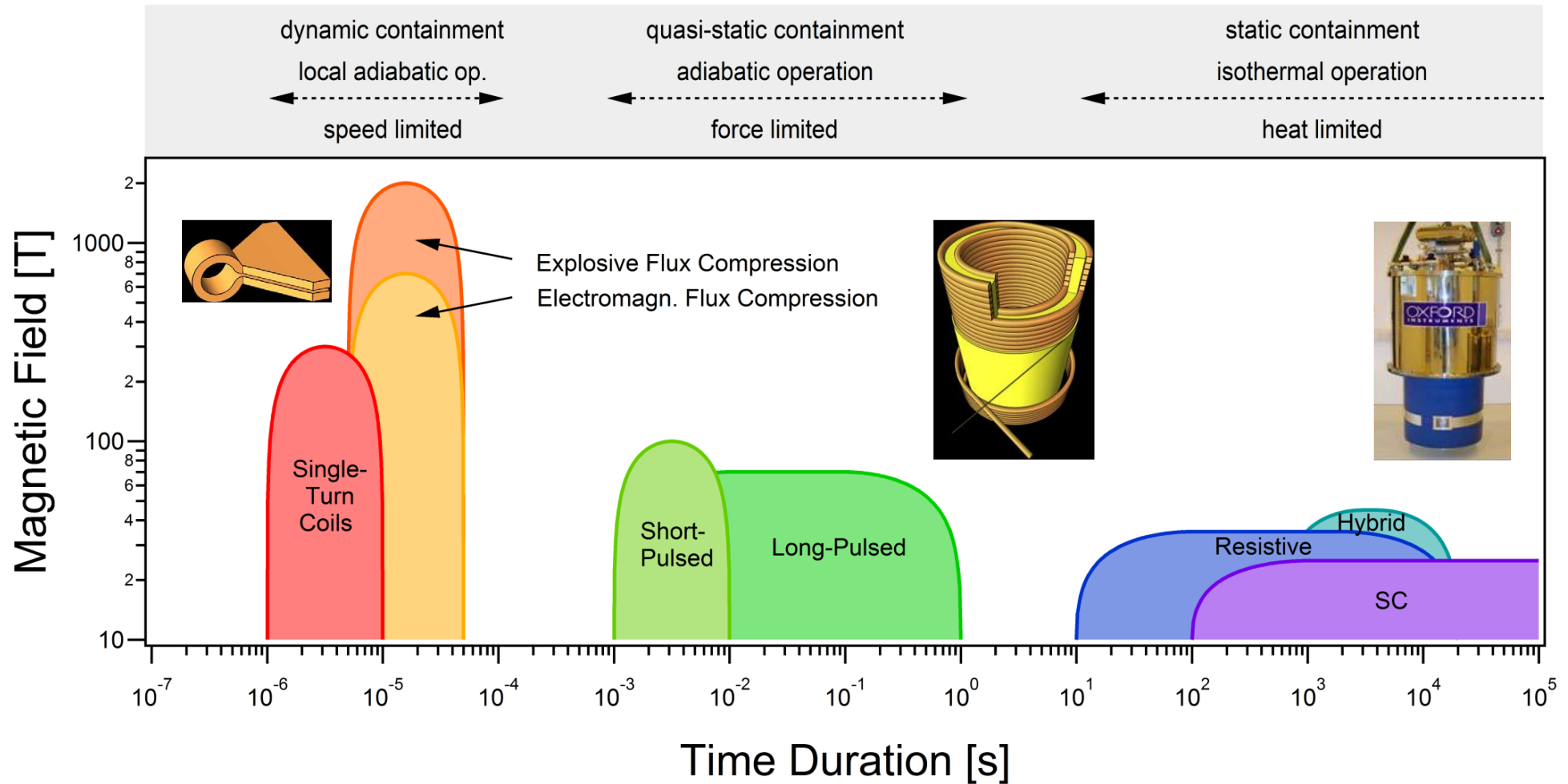


$$B_z(z) = \frac{\mu_0 I R^2}{d^3} \left[1 + \frac{3(b^2 - R^2)}{2d^4} z^2 + \frac{15(b^4 - 6b^2 R^2 + 2R^4)}{16d^8} z^4 + \dots \right]$$

Coil radius R , Coil distance b , **Helmholtz condition**: $b = R \rightarrow$ quadratic term vanishes

$$d = \sqrt{R^2 + \frac{1}{4} b^2}$$

Fields above 3 Tesla

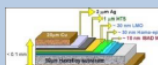


Limitations :

1) Energy dissipation $P = \int \rho(x) \mathbf{J}^2(x) d^3x \propto \mathbf{B}^2$

2) Force de Lorentz $\mathbf{F} = \int \mathbf{J}(x) \times \mathbf{B}(x) d^3x \propto \mathbf{B}^2$

Superconducting electromagnets

NbTi LTS		Nb ₃ Sn LTS		MgB ₂ MTS		Bi-2212/Bi-2223 HTS		YBCO HTS	
T _c = 9.8 K B _{max} (4.2K) 9.5T (2.2K) 11.5T		T _c = 18.1 K B _{max} (4.2K) 20T (2.2K) 23.5T		T _c =39K B _{max} (4k) 5T-10T ?		T _c = 90-110K B _{max} > 40 T @4.2K; 8 T @20K 4 T @65K		T _c = 90-135K B _{max} > 40 T @4.2K 12 T @20K 8 T @65K	

1960 (4 T)
NbZr, NbTi



7T



2000 (14 T)
Nb₃Sn split pair



2010 (23.5 T)
NbTi + Nb₃Sn



NMR

2018 (32 T)
NbTi+Nb₃Sn+HTS



2019 (32 T) 
resistive+HTS



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➡ AC susceptometry

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➡ Scanning probe microscopies, Photon-out

Quick reminder on heat transfers

Radiation : In average the coldest region gets more photons from the hottest region than it loses itself

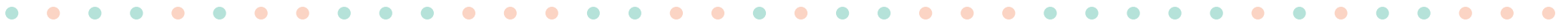
Stefan-Boltzmann's Law defines the relationship between the emission of black bodies with its temperature

$$\text{Surface density of Radiative power} = \sigma \epsilon T^4$$

σ : Stefan constant, ϵ : émissivity, T : temperature

Ways to limit radiative heat transfer :

- reflective materials (metals with low roughness)
- thermal Screening by absorbant materials (N2)



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Conduction : Heat transfer, without moving material, between two media of different temperature (vibrations)

Fourier law's : heat flux density = $-\lambda \overrightarrow{\text{grad}} T$
Thermal conductivity

Ways to limit heat transfer through conduction :
- Materials with low thermal conductivity (thermal insulation)
- Removing materials between two region (vacuum)

Quick reminder on heat transfers

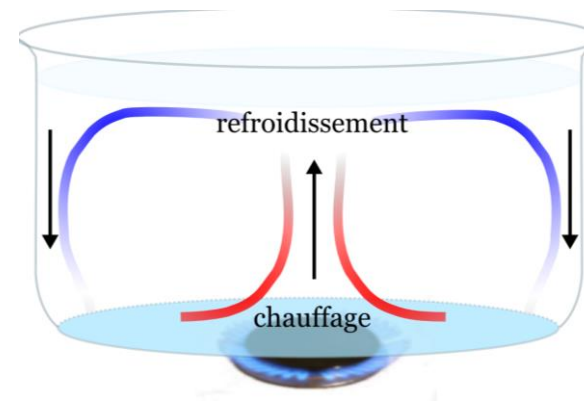
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Conduction : Heat transfer, without moving material, between two media of different temperature (vibrations)

Ways to limit heat transfer through conduction :
- materials with low thermal conductivity (thermal insulation)
- absence of materials between two regions (vacuum)

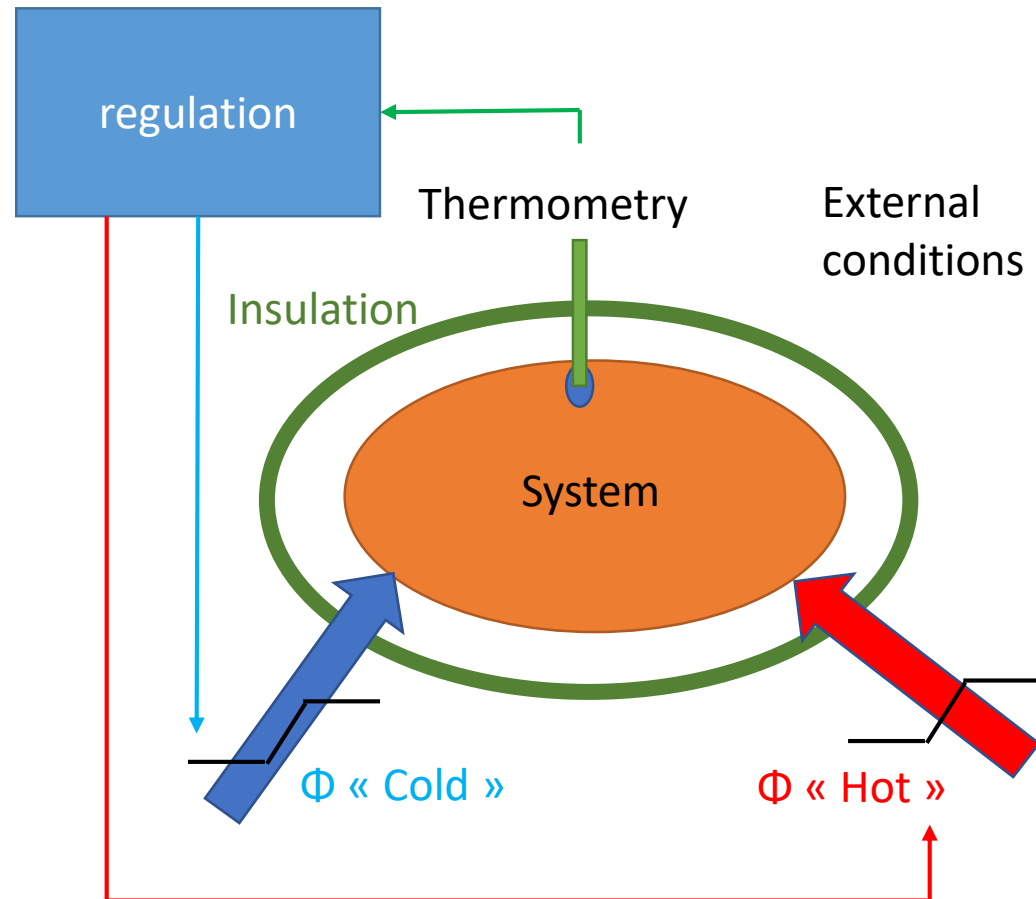
Convection : Heat transfer by moving matter



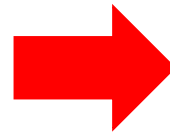
Ways to limit convective heat transfer :
- to limit matter motion
- absence of matter between the two regions (vacuum)

General design of a cryostat

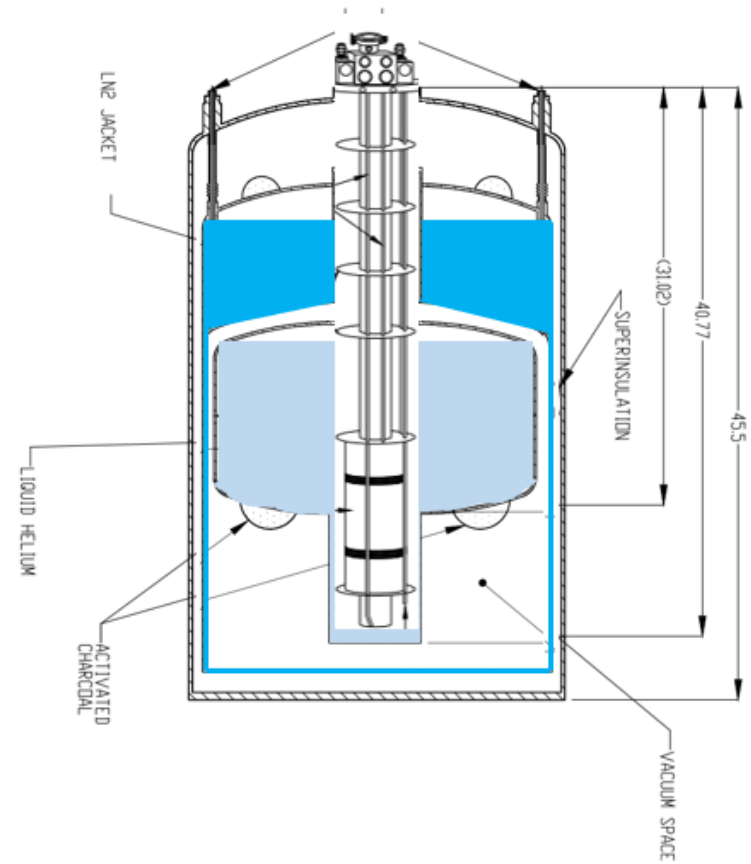
- 1) Low temperature source
 - Cold flux
- 2) High temperature source
 - Hot flux
- 3) Control of the environment
 - Insulated system
- 4) Measure of temperature
 - Well chosen thermometer



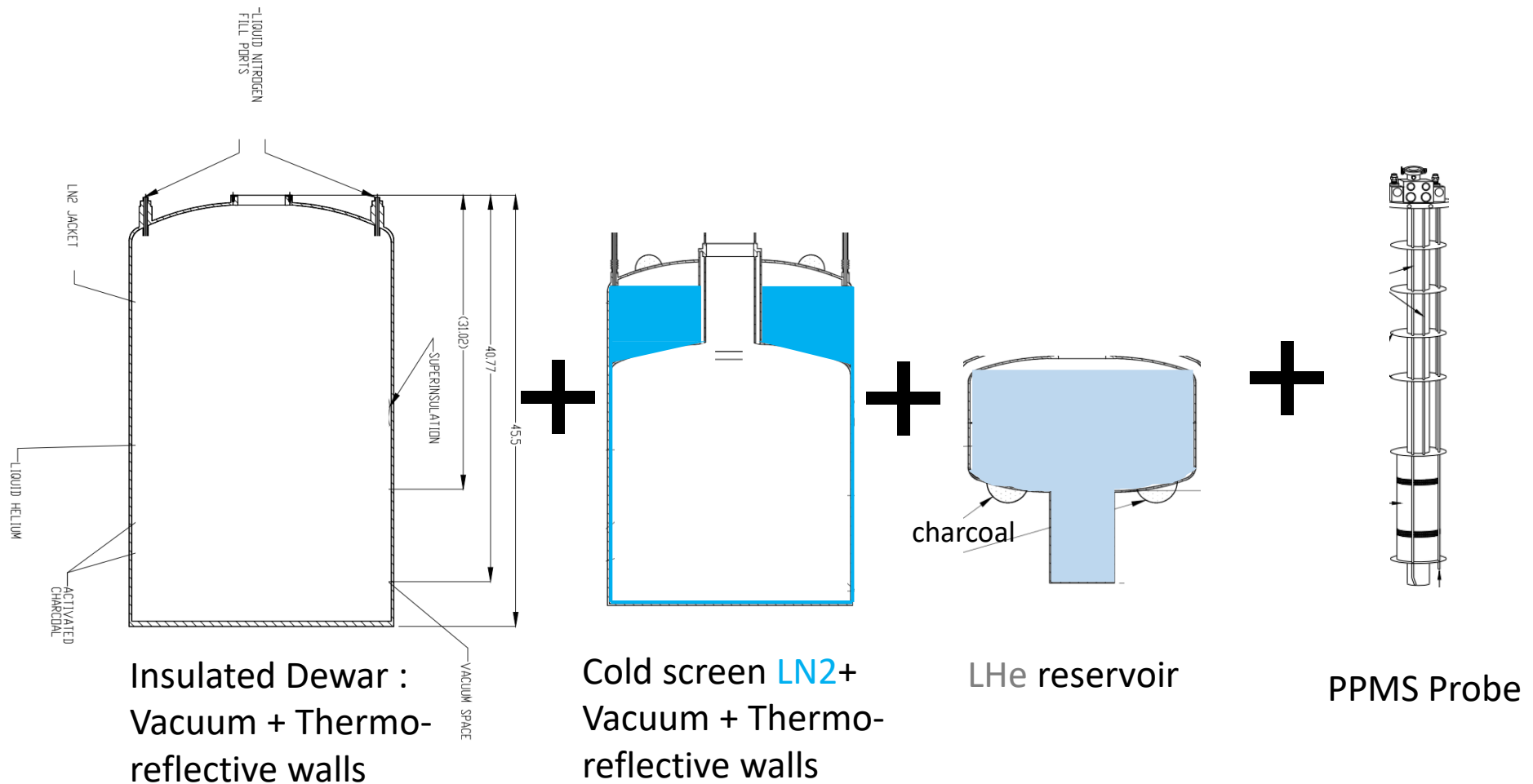
One example : QD PPMS cryostat



What's inside ?

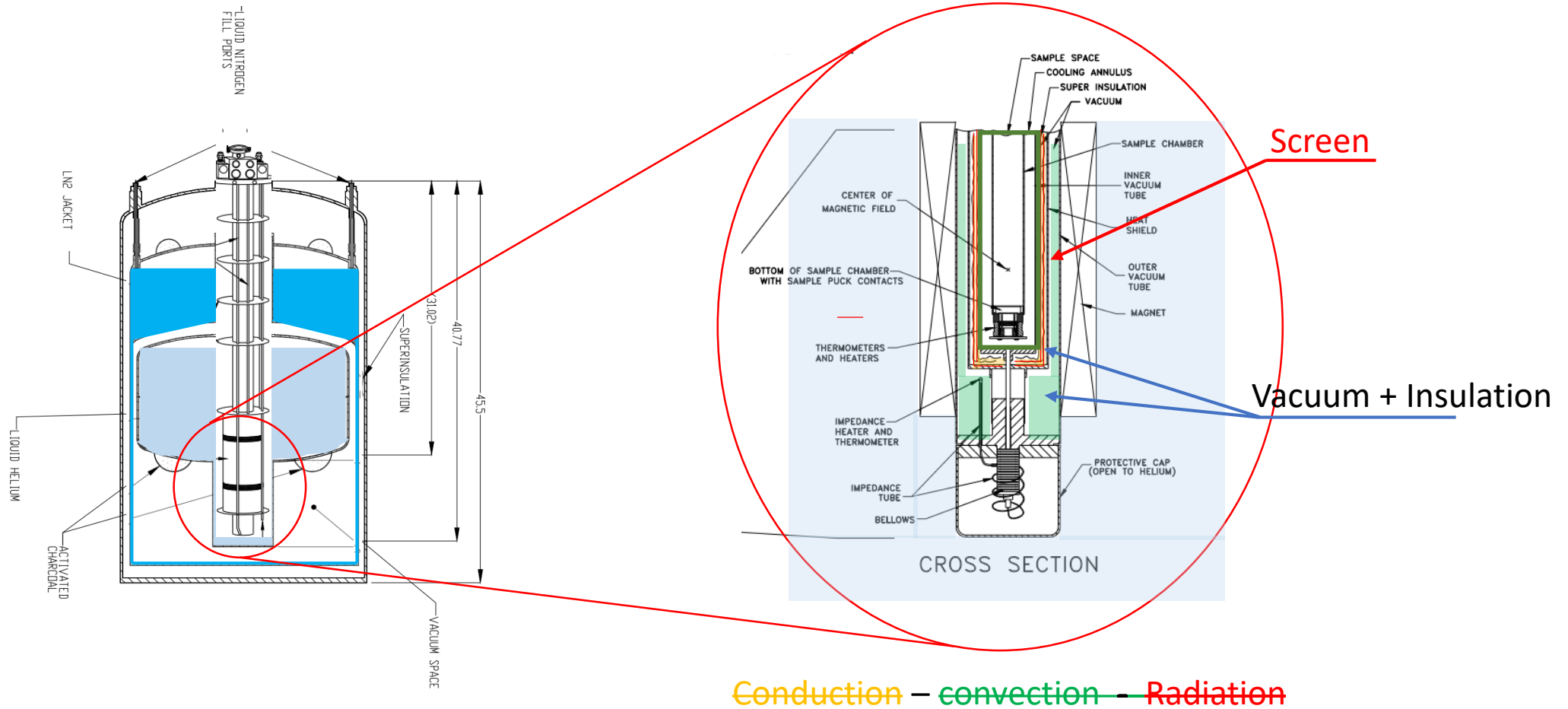


One example : QD PPMS cryostat



Conduction — convection — Radiation

One example : QD PPMS cryostat

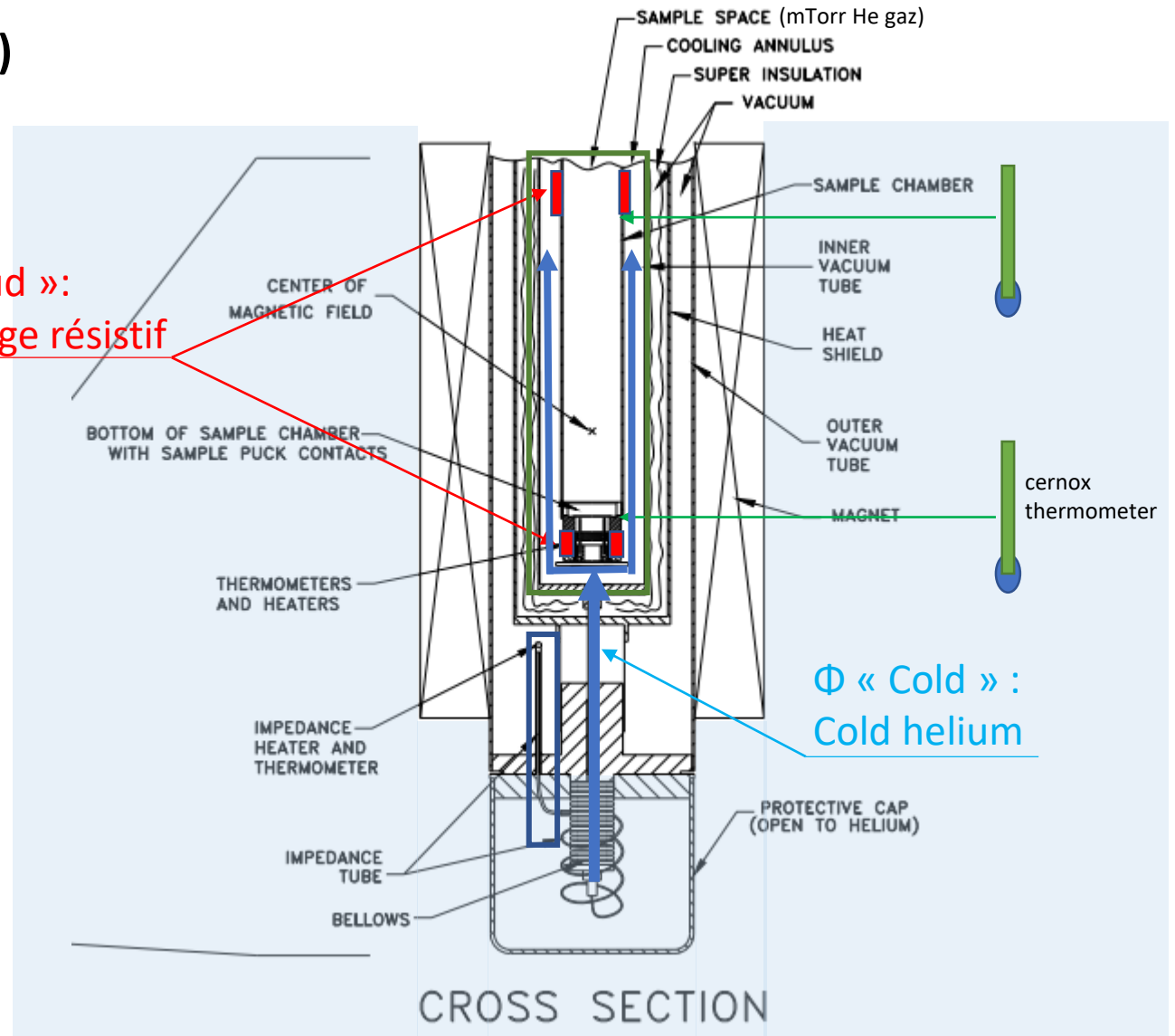
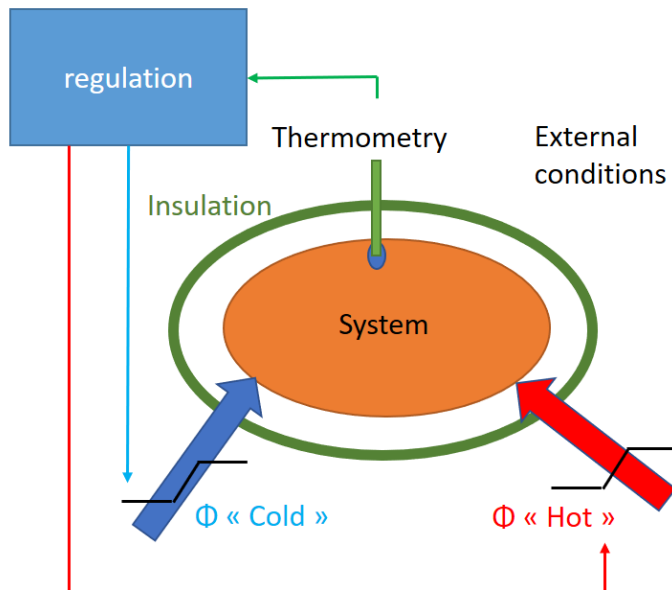


One example : QD PPMS cryostat



Temperature control (5K-400K)

Φ Chaud » :
Chauffage résistif



One example : QD PPMS cryostat



Temperature control (5K-400K)



Thermometers choice

Cernox : 100mK -> 325 K

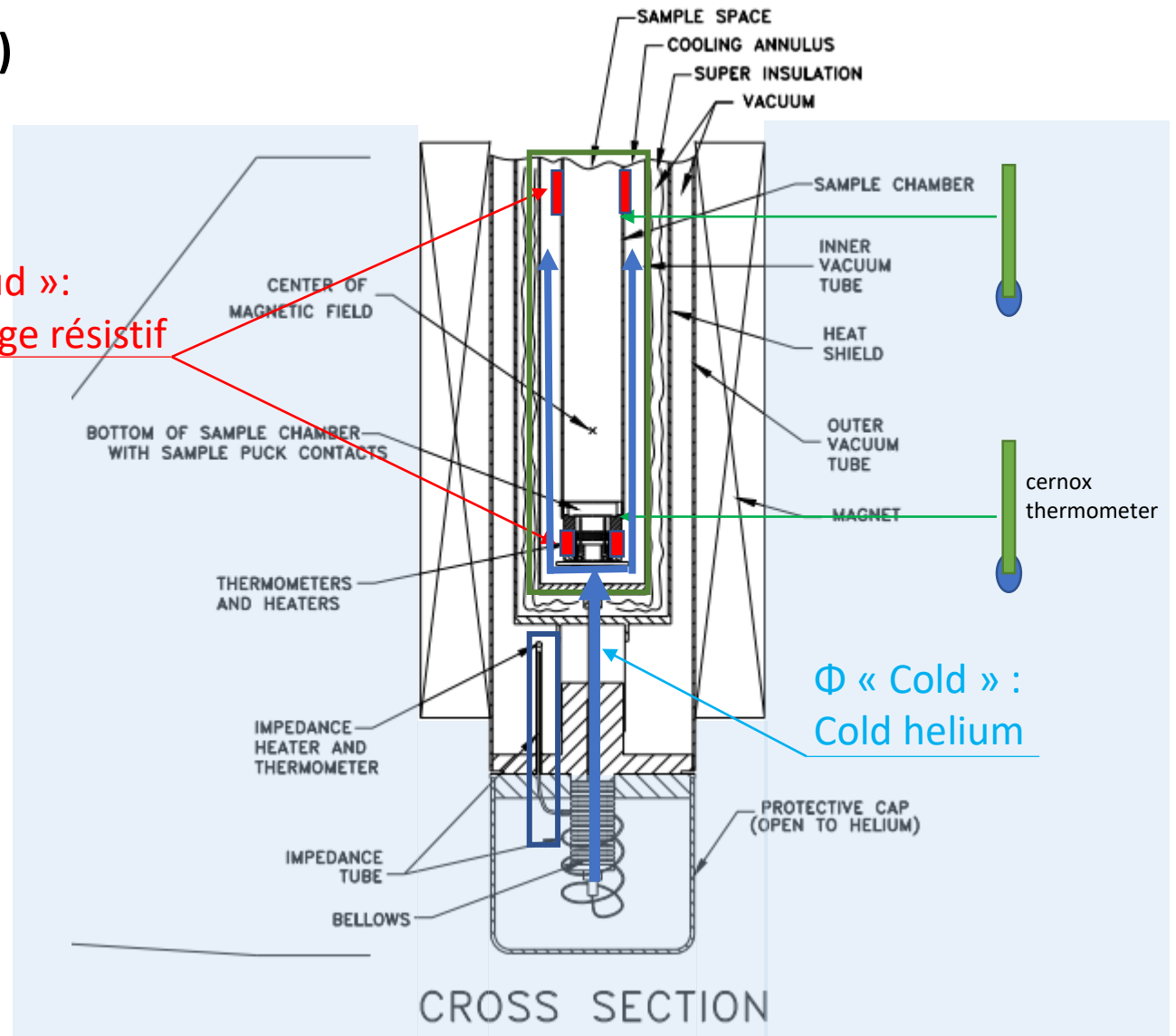
Platine resistance: 30K -> 800K

Typical magnetic field-dependent temperature errors⁴ $\Delta T/T$ (%) at B (magnetic induction)

Package base parallel to field B					
T (K)	2.5 T	5 T	8 T	14 T	19 T
20	20	—	100	250	—
40	0.5	1.5	3	6	8.8
87	0.04	0.14	0.4	1	1.7
300	-0.01	0.001	0.02	0.07	0.13

⁴ Recommended for use when $T = 30$ K

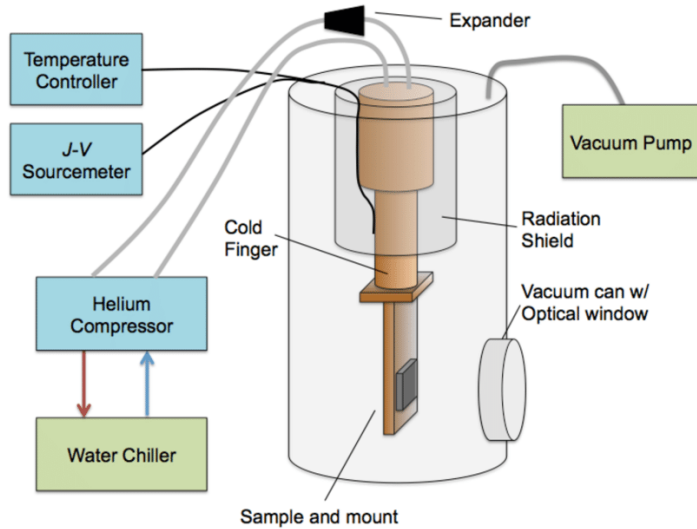
Φ Chaud »:
Chauffage résistif



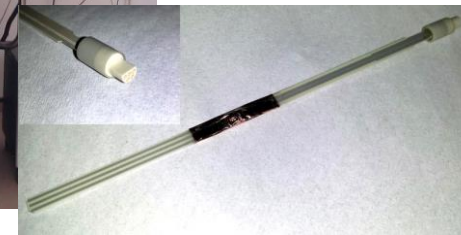
Φ « Cold » :
Cold helium

Other typical temperature control set ups

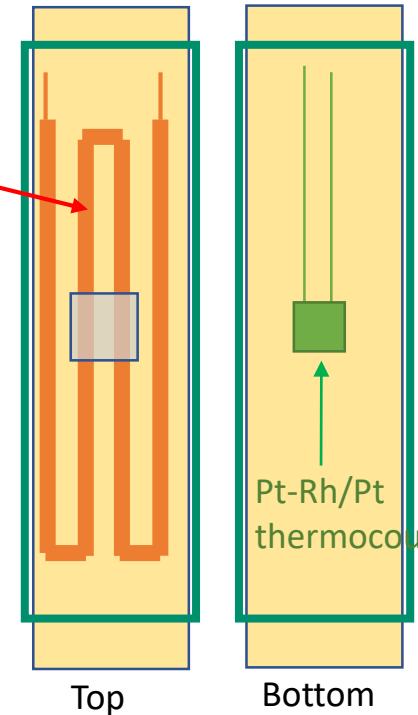
Cold finger cryostat



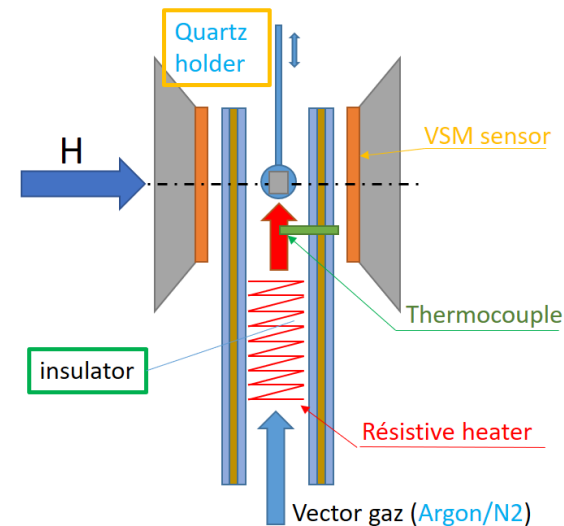
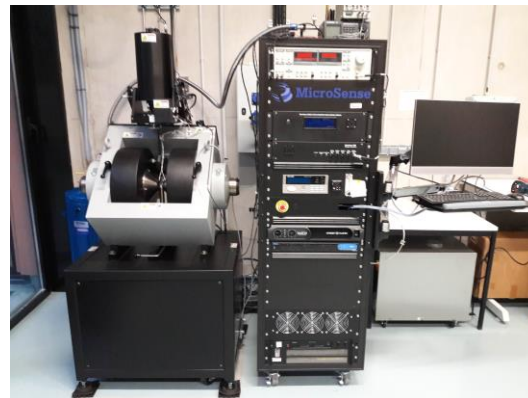
Resistive heater



Resistive leads



Temperature control through gas flow (conduction)



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➡ **VSM, SQUID**, Torque, MOKE, XMCD, Photo-emission spectroscopy

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➡ AC susceptometry, FMR

IV. Imaging techniques

➡ Scanning probe microscopies, Photon-out, Electron-out

Macroscopic moment measurement

do not confuse the two m's : « M » and « m »



$$M = \frac{m}{V}$$

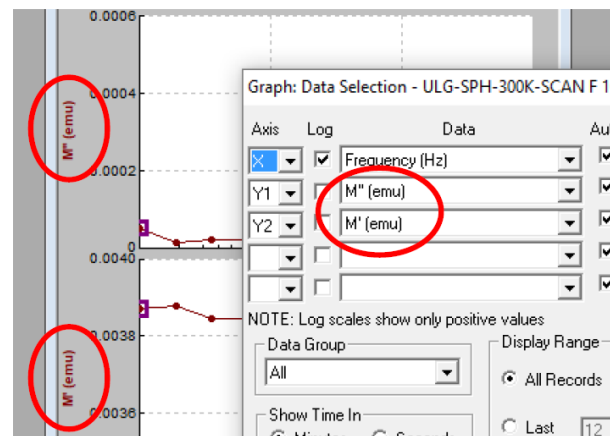
Magnetic moment [Am^2]
or [emu] = [10^{-3}Am^2]

Parameter that is measured
with VSM or SQUID

Magnetisation [A/m]

Volume [m^3]

But in some tools you can find :



(argh!)

Induction to detect guitar string motion (1950's)



Figure 1 — The Frying Pan, guitare hawaïenne solid-body, Rickenbaker 1951.

[Pierrick Lotton, musique & technique, 2009]



Gibson Les Paul 1952

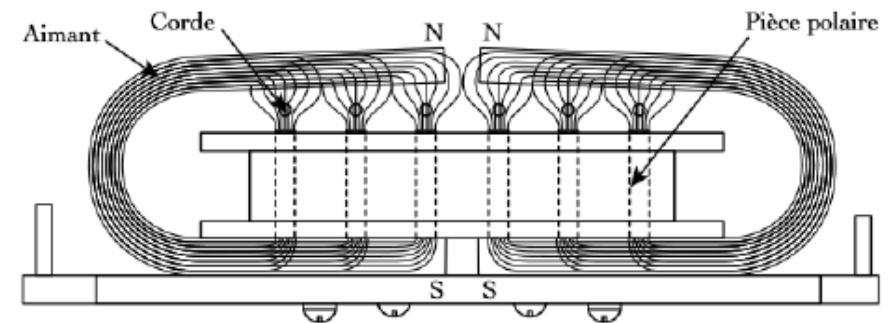
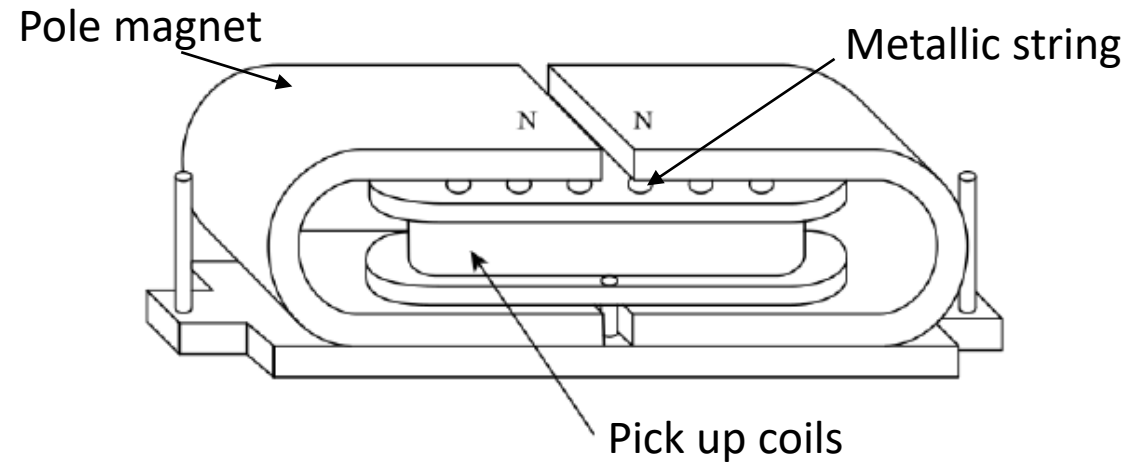


Figure 2 — Pickup développé par G. Beauchamp pour Rickenbaker.

String vibrations ➡ AC magnetic field inside the pick up coils ➡ AC electrical current

First vibrating sample magnetometer (1959)

Rev. of Scientific Instr. 1959
Brevet déposé en 1960



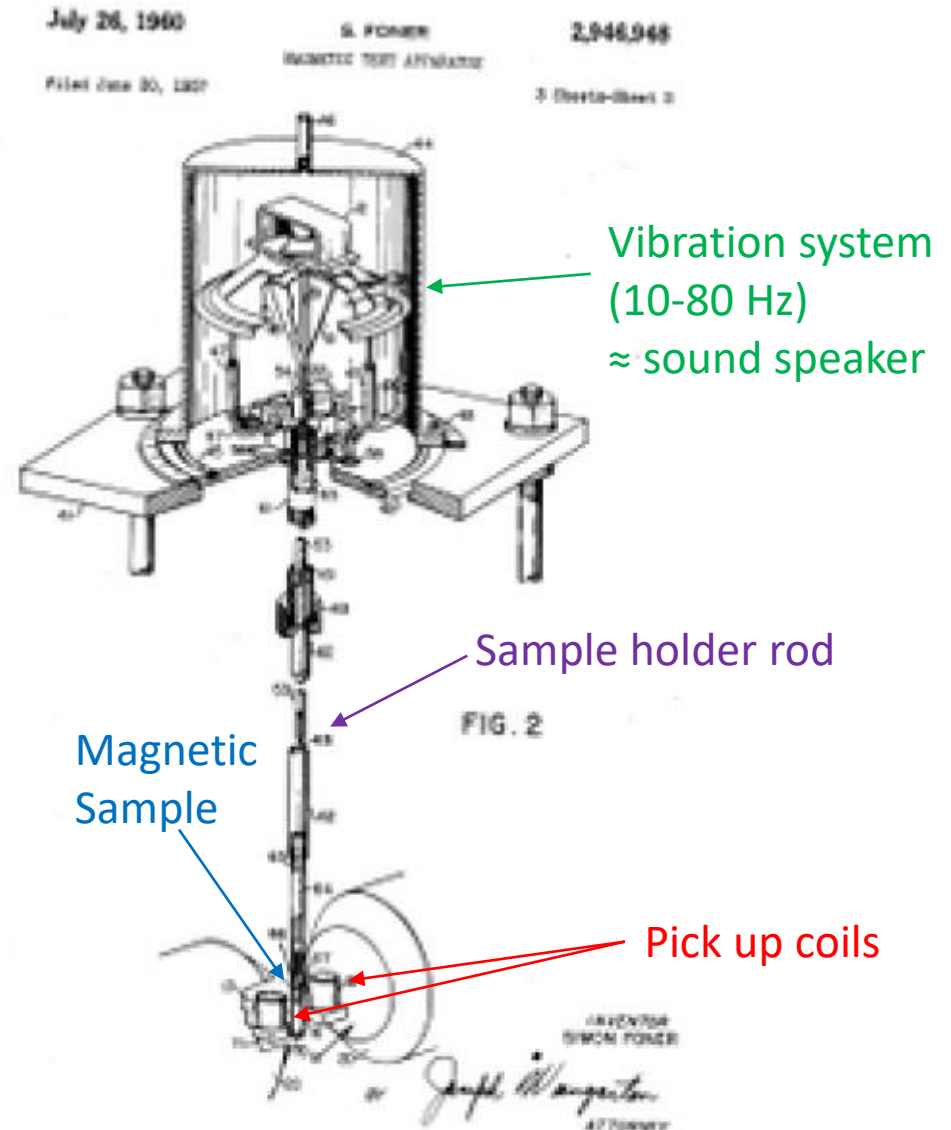
Simon FONER 1925 † 2007

J. Appl. Phys. 79 (8), 15 April 1996

The vibrating sample magnetometer: Experiences of a volunteer

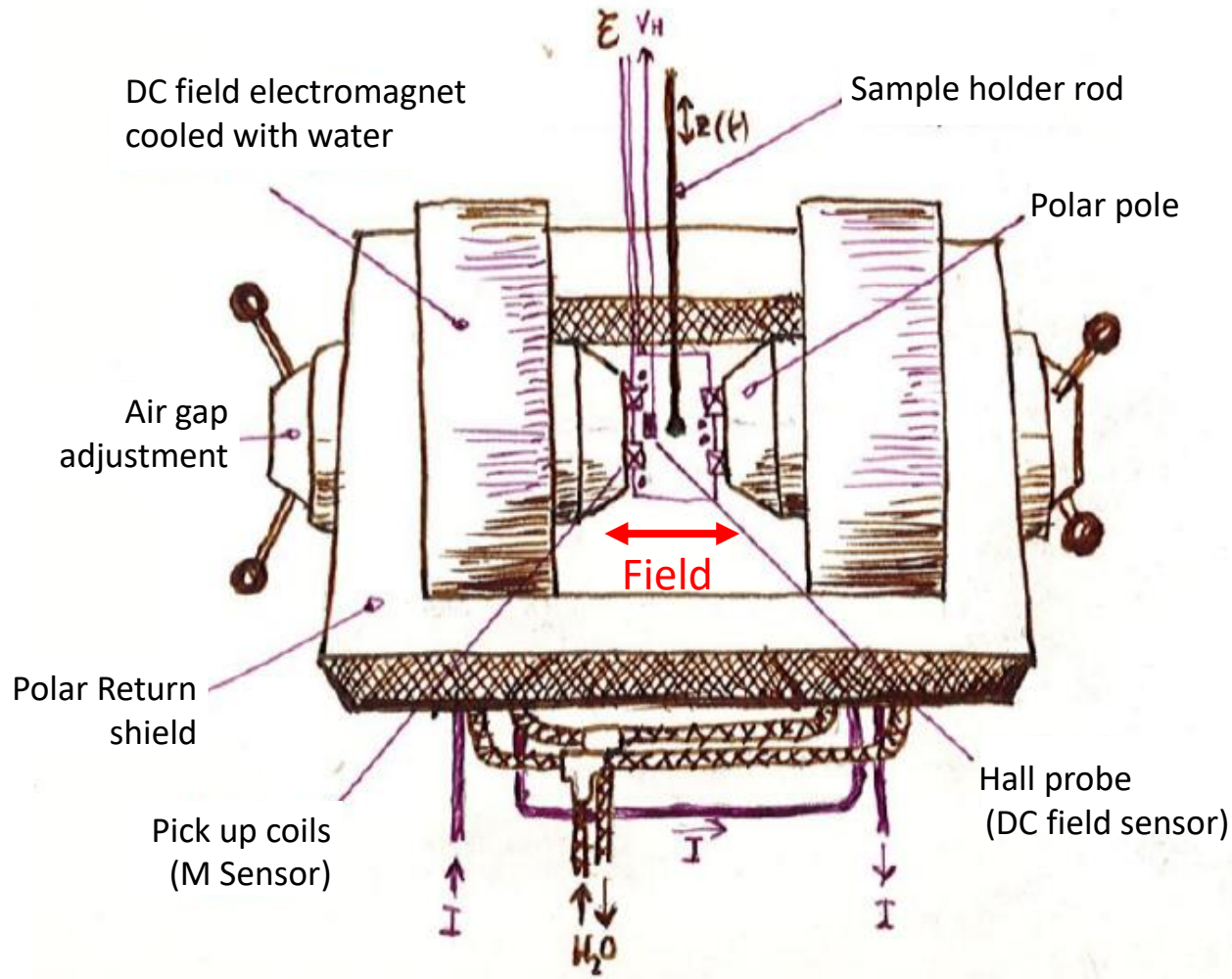
S. Foner
Francis Bitter National Magnet Laboratory and Department of Physics, MIT, Cambridge, Massachusetts 02139

That summer we were living in a small farm-hand's house about 1 km from the laboratory and just off the runway at Hanscom Field, a Strategic Air Command (SAC) base at that time. While shaving one evening I decided to try ac induction for magnetic measurements. With some Duco cement, a small \$2.00 (in 1955) replacement loudspeaker, a conical paper cup, and a paper straw (the latter components were light and conveniently available at night from the lunch room), the first working model VSM was assembled. Initial

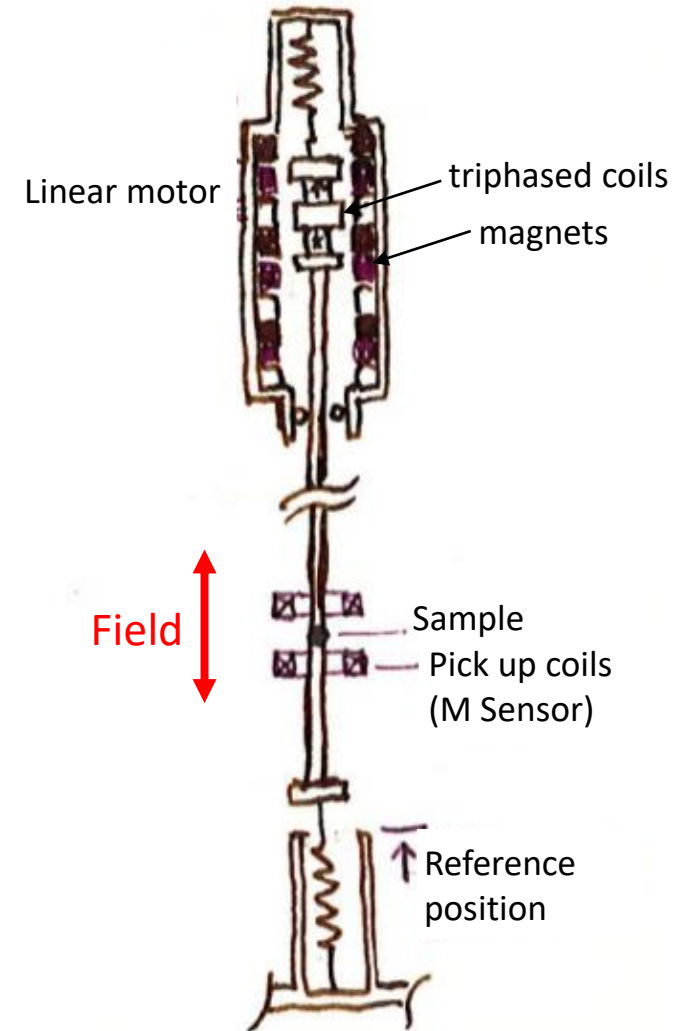


Two VSM geometries

Radial VSM

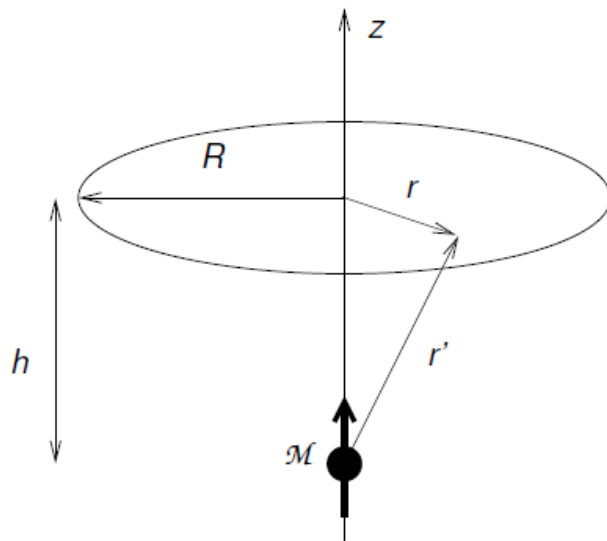


Axial VSM



Axial VSM equations

If the sample is considered as a single magnetic dipole :



$$\vec{B} = \frac{\mu_0}{4\pi} \left[\frac{3(\vec{M} \cdot \vec{r}') \cdot \vec{r}'}{r'^5} - \frac{\vec{M}}{r'^3} \right]$$

$$B_z = \frac{\mu_0}{4\pi} \left[\frac{3\mathcal{M}h^2}{(h^2+r^2)^{5/2}} - \frac{\mathcal{M}}{(h^2+r^2)^{3/2}} \right]$$

$$\begin{aligned} \phi &= \int B_z dS = \int_0^R \frac{\mu_0}{4\pi} \left[\frac{3\mathcal{M}h^2}{(h^2+r^2)^{5/2}} - \frac{\mathcal{M}}{(h^2+r^2)^{3/2}} \right] 2\pi r dr \\ &= \frac{\mu_0 \mathcal{M}}{2} \left[-\frac{3h^2}{(h^2+R^2)^{3/2}} + \frac{1}{(h^2+R^2)^{1/2}} \right] \end{aligned}$$

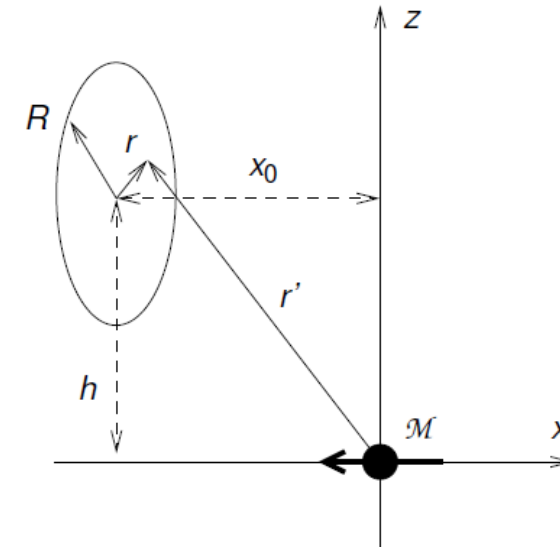
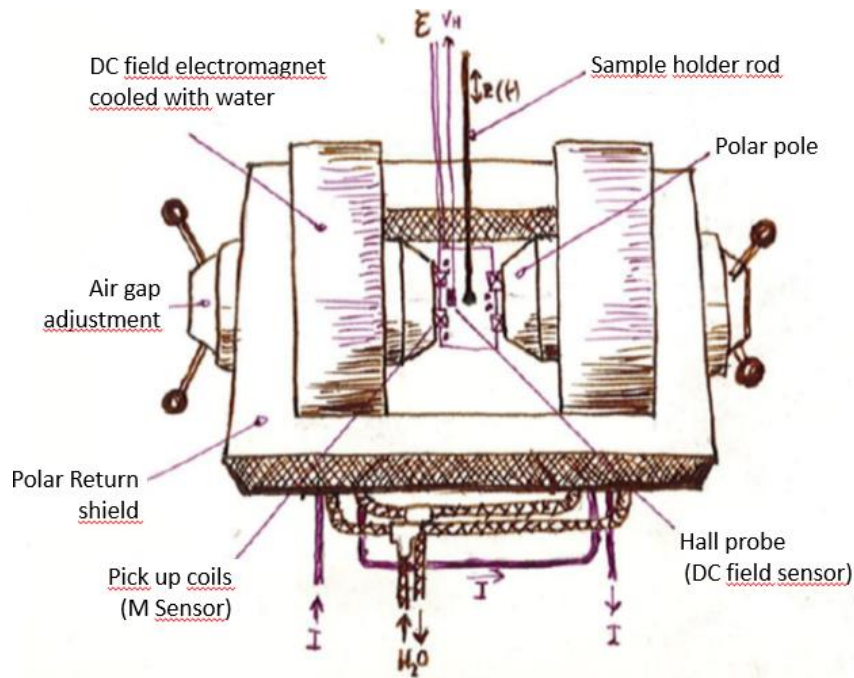
Taylor : $\phi = \frac{\mu_0 \mathcal{M}}{2R} \left[-3 + \frac{9h^4}{2R^4} + 1 - \frac{h^2}{2R^2} + \frac{3h^4}{8R^4} + o\left(\frac{h^6}{R^6}\right) \right]$
 $H \ll R$

If the sample vibrates along z : $h(t) = h + a \sin(\omega t)$, $a \ll h$

$$\frac{d\phi}{dt} = \frac{-\mu_0 \mathcal{M}}{4R^3} \frac{d}{dt} (h^2 + 2ah \sin(\omega t) + a^2 \sin^2(\omega t))$$

Induced fem for n spires : $\mathcal{E} = -n \frac{d\phi}{dt} = \frac{n\mu_0 \mathcal{M} h a \omega}{2R^3}$

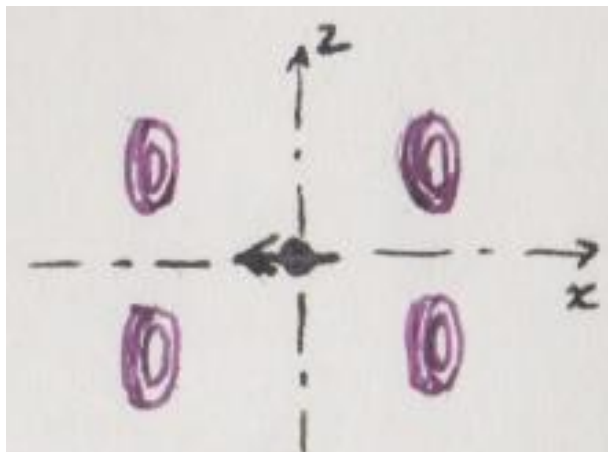
Radial VSM equations



$$\mathcal{E} = \frac{3}{2} n \mu_0 \mathcal{M} a \iint \frac{r(r \sin \theta + h)}{r'^5} \left(5 \frac{x_0^2}{r'^2} - 1 \right) dr d\theta$$

$$r'^2 = x_0^2 + r^2 \cos^2 \theta + (r \sin \theta + h)^2$$

$$h(t) = h + a \sin(\omega t)$$



Both VSMs carry good sensitivity (down to 10^{-9} A.m²) because of the synchronous detection (Lock-In)

Two VSM geometries : usual tools

Radial VSM



MicroSense (USA),

**Up to 2.7 Tesla
300K up to 1200K
Easy sample rotation**



LakeShore (USA)

Axial VSM



Quantum Design (USA)

**Up to 9-14 Tesla
2K up to 400K**



Cryogenic (UK)

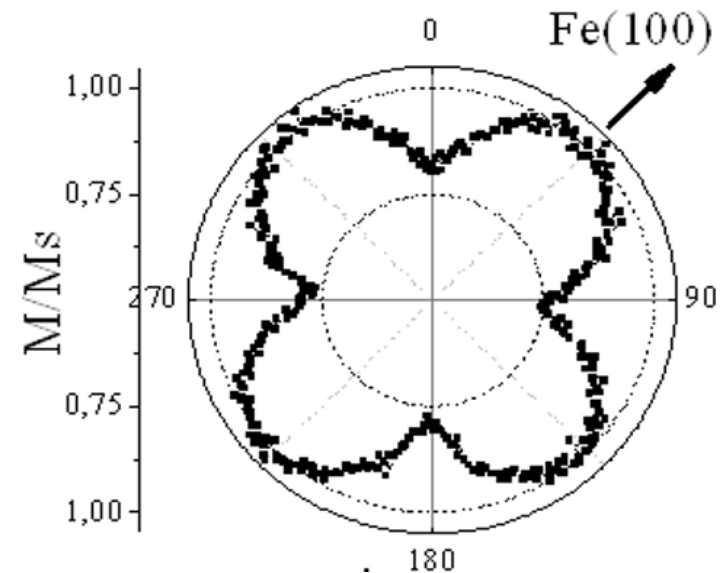
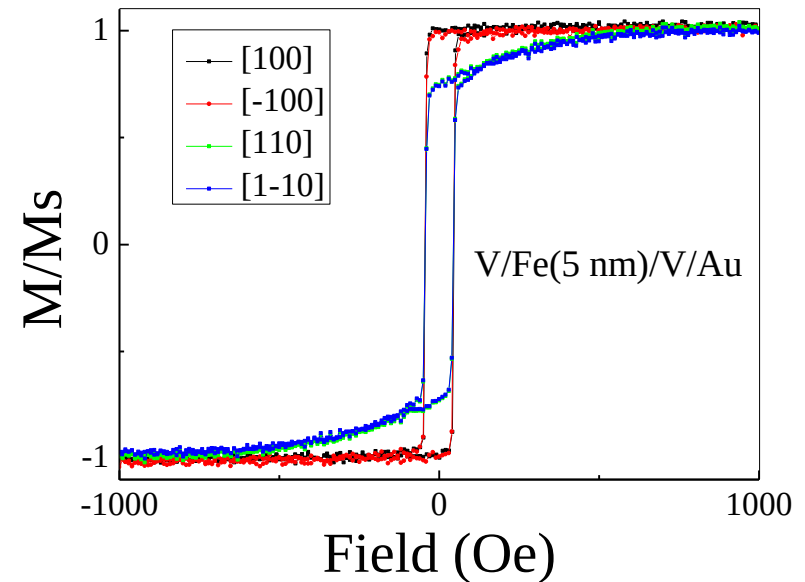
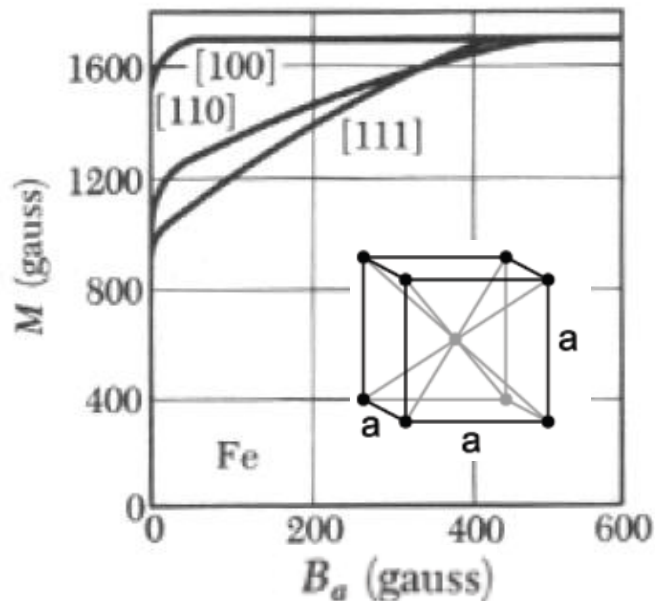
Example 1 : anisotropies in crystals

Fe bcc atomic lattice anisotropy leads to preferred directions for the atomic magnetic moments. This translates into an anisotropy of potential energy :

$$E_{mc} = K_1 (\alpha_1^2 \alpha_2^2 + \alpha_2^2 \alpha_3^2 + \alpha_3^2 \alpha_1^2) + K_2 (\alpha_1^2 \alpha_2^2 \alpha_3^2);$$

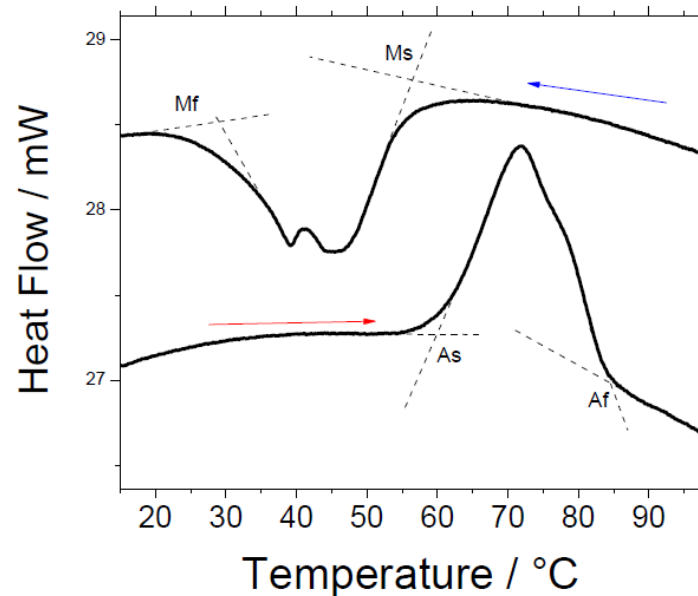
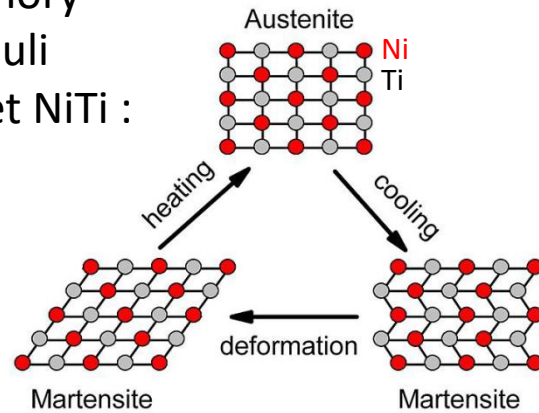
where $\alpha_i = \cos \theta_i$; θ_i -angle between axis and M

From the literature :

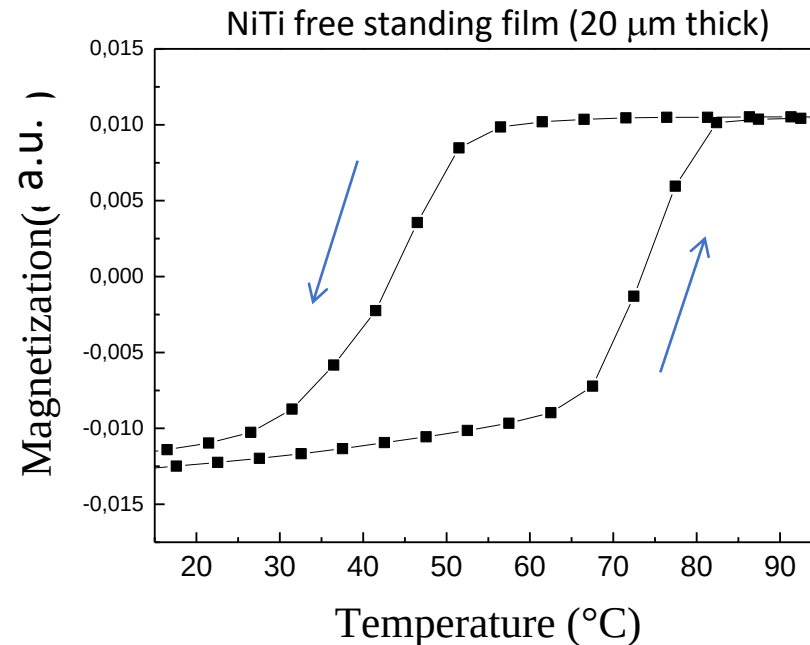
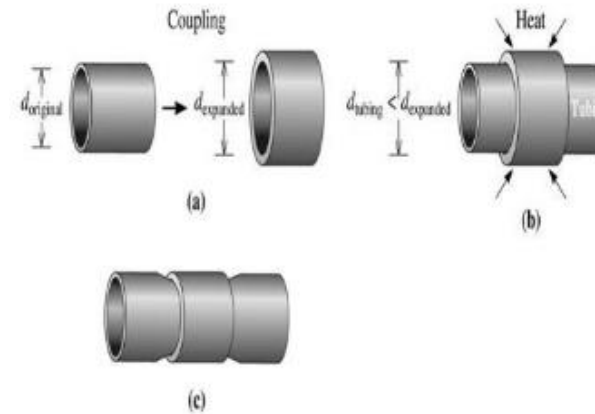


Example 2 : study of structural transitions

Shape memory effect in Pauli paramagnet NiTi :



One example of industrial application :



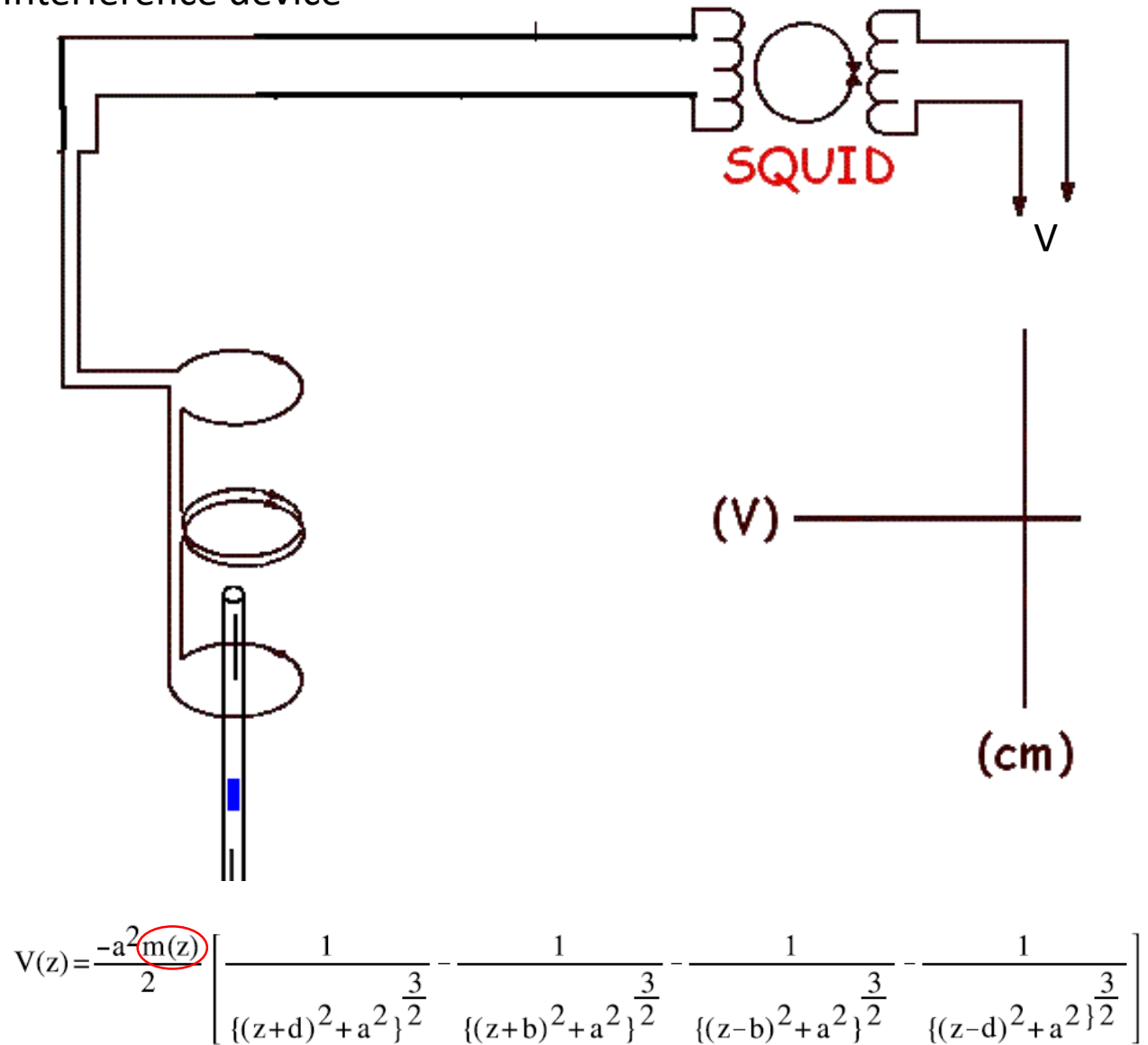
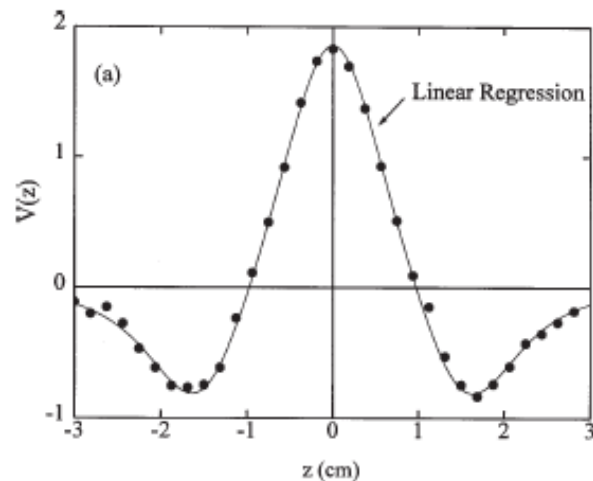
SQUID magnetometer

<http://squad-cmmp.blogspot.com/2011/07/blog-post.html>

SQUID = Superconducting Quantum Interference device



Measure good data for
signal as low as 10^{-11} A.m²



Magnetic flux through a superconducting coil



Perfect Superconducting coil

Vector potential $\vec{A} = \text{rot}(\vec{A})$

Electrons are coupled in Cooper pairs

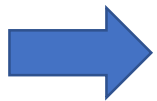
$$\text{Superconducting current : } \vec{j} = \frac{ne}{m} (\hbar \vec{\nabla} \varphi - \frac{2e}{c} \vec{A})$$

$$\text{If there is no current : } \oint \vec{j} d\vec{l} = 0 = \hbar \cdot 2\pi \cdot N + 2e \iint \vec{B} \vec{S}$$



$$\iint \vec{B} \vec{S} = N \cdot \frac{h}{2e} = N \Phi_0$$

$$1 \text{ quantum } \Phi_0 = \frac{h}{2e} = 2.10^{-15} \text{ Tm}^2 (= \text{Wb Weber})$$



- Magnetic flux in the coil is quantified
- when superconducting, magnetic field cannot vary inside the coil

Magnetic flux through a superconducting coil



Perfect Superconducting coil

Electrons are coupled in Cooper pairs

$$\text{Superconducting current : } \vec{j} = \frac{ne}{m} (\hbar \vec{\nabla} \varphi - \frac{2e}{c} \vec{A})$$

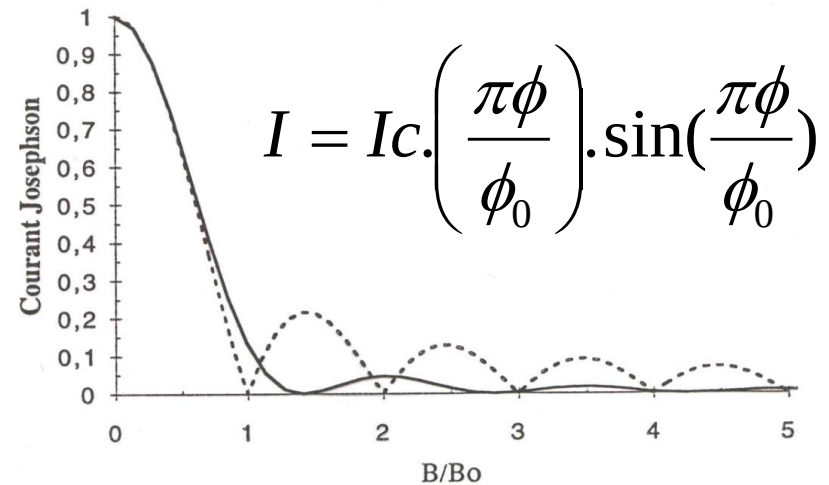
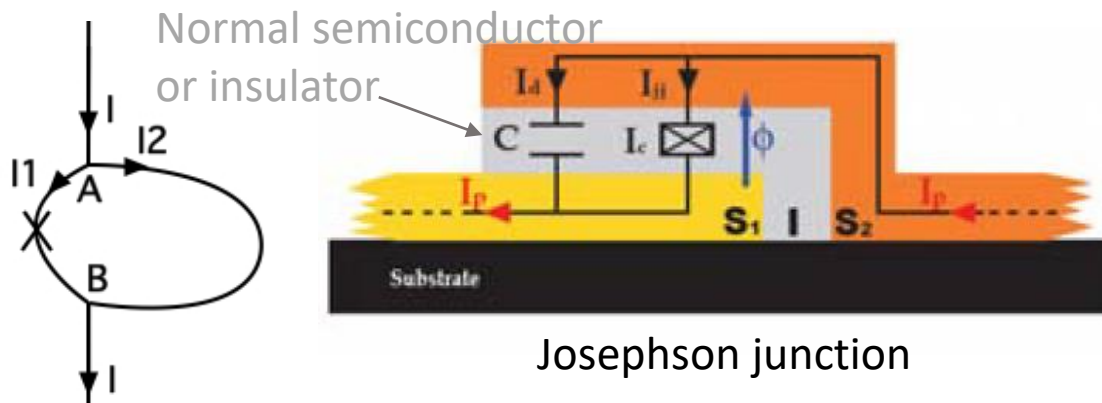
$$\text{If there is no current : } \oint \vec{j} d\vec{l} = 0 = \hbar \cdot 2\pi \cdot N + 2e \iint \vec{B} \vec{S}$$



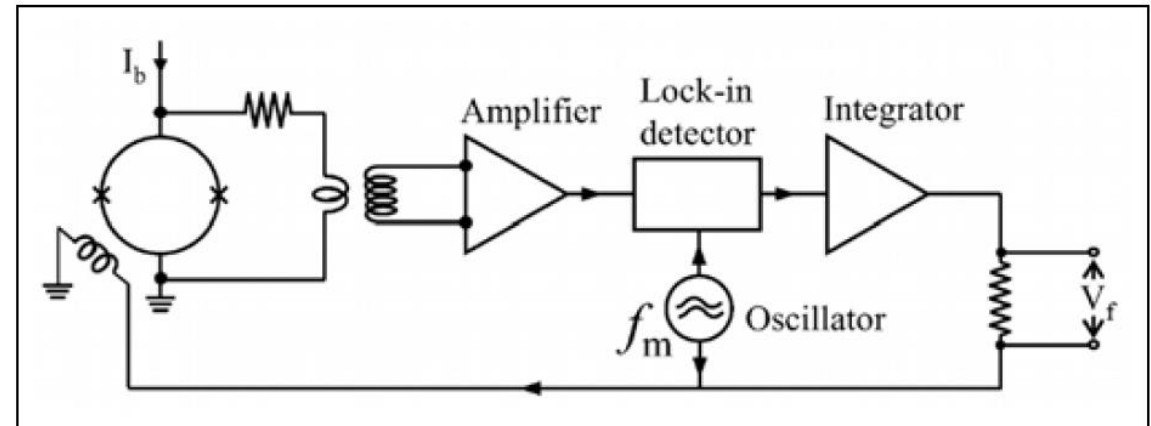
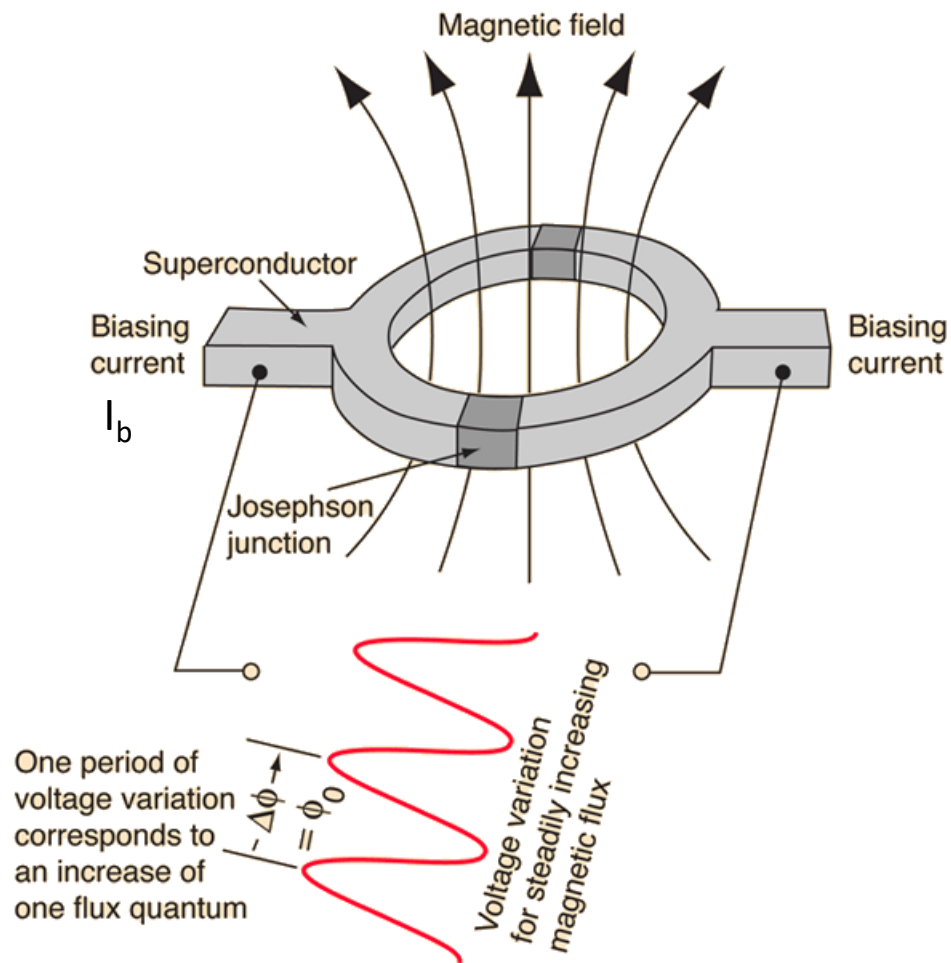
$$\iint \vec{B} \vec{S} = N \cdot \frac{h}{2e} = N \Phi_0$$

$$1 \text{ quantum } \Phi_0 = \frac{h}{2e} = 2.10^{-15} \text{ Tm}^2 (= \text{Wb Weber})$$

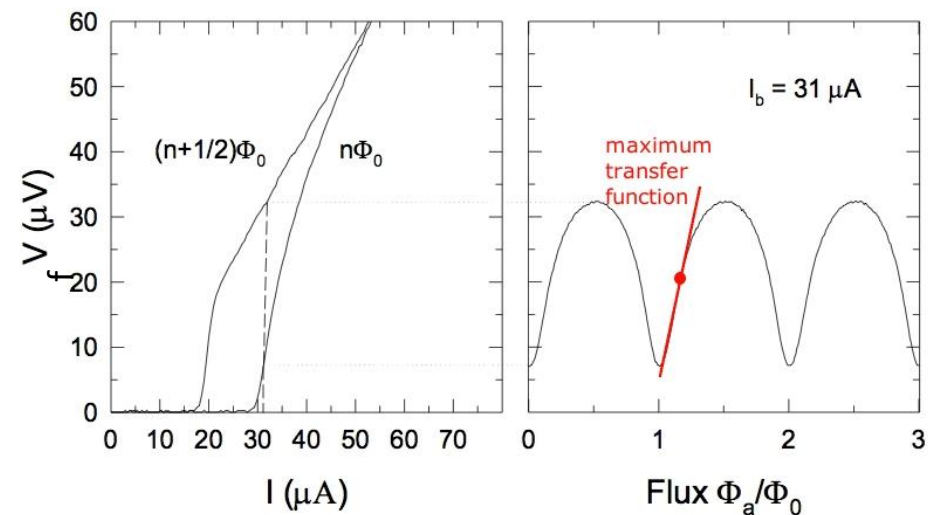
But magnetic field can penetrate through defect :



DC SQUID : 2 interfering Josephson junction



DC CHARACTERISTICS AND NOISE PERFORMANCE



Measured Voltage-Current (V - I) and Voltage-Flux (V - Φ) characteristics of a typical M800 dc SQUID magnetometer operated 4.2 K.

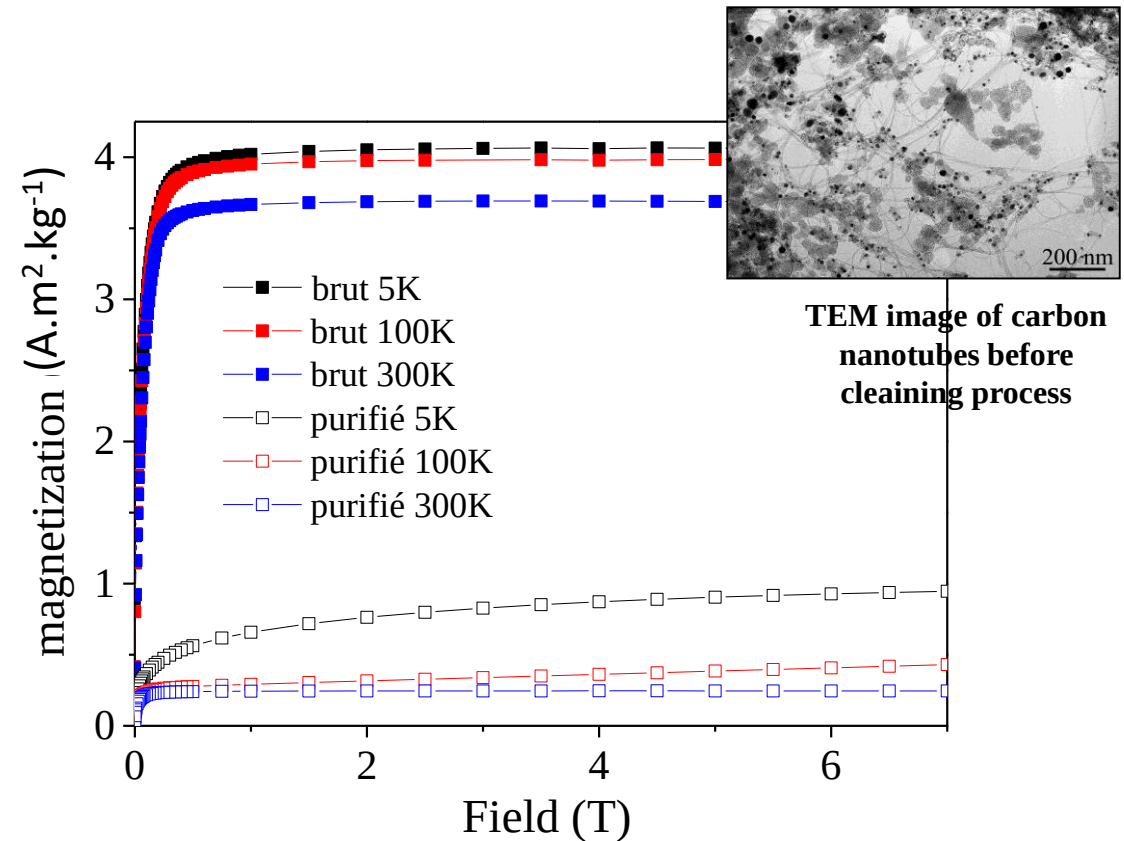
Résolution on magnetic flux of $10^{-6} \Phi_0$

If SQUID radius= 1mm $\Rightarrow \Delta B \approx 10^{-15} \text{ T}$

Example : detecting Ni nanoparticles



SQUID-VSM : Small signal measurement



Method for detection of Ni nanoparticles after they are used to grow carbon nanotubes

B.Vigolo et al. IJL Nancy
European Patent PCT/FR2011/052519 (2011)

VSM and SQUIDs limiting factors



Final Lock-in voltage =

Gain x Moment x Sample geometry factor x Coil geometry factor x Amplitude x Frequency

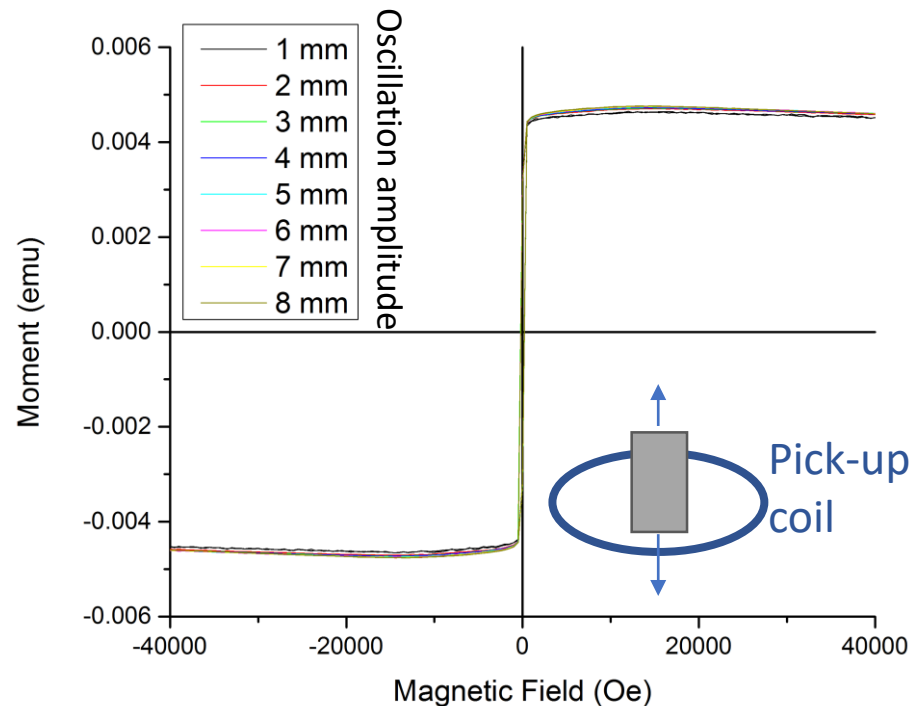
- The parameters in green are accounted for through calibration with a standard of known moment for a particular VSM coil set.
- This leaves sample moment coupled together with its geometry factor. This is very important to consider when interpreting the measured moment.

Experimental limiting factors : sample geometry

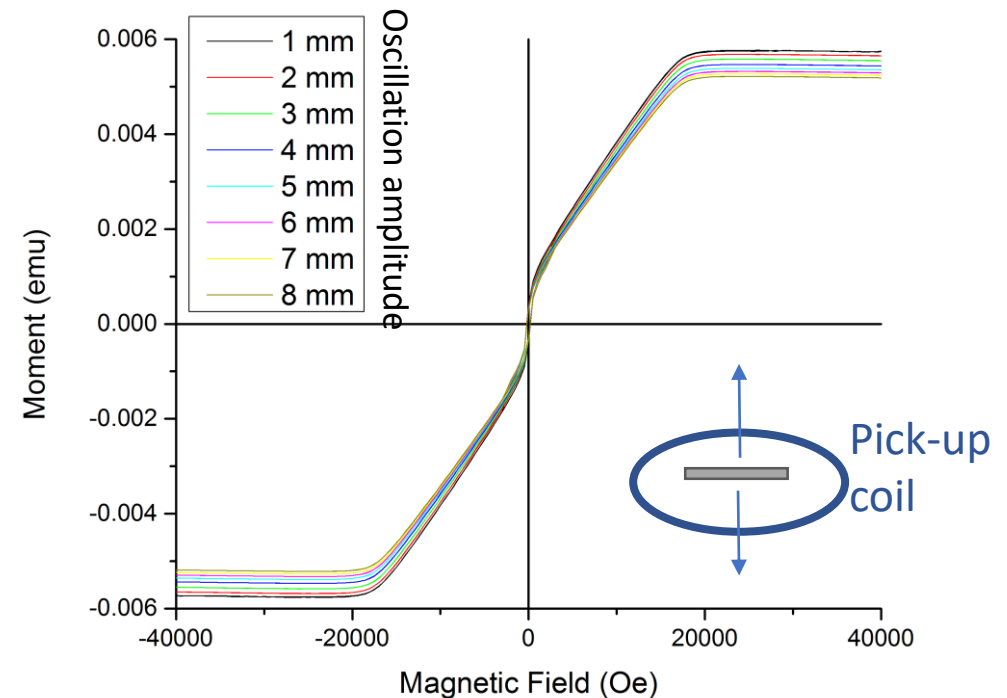
Final Lock-in voltage =

Gain x Moment x Sample geometry factor x Coil geometry factor x Amplitude x Frequency

Film in-plane



Film out-of-plane



Example of a **thin film sample geometry** effect for SQUID VSM
(4 mm x 4 mm x 200 nm Ni film on silicon)

Experimental limiting factors : sample geometry

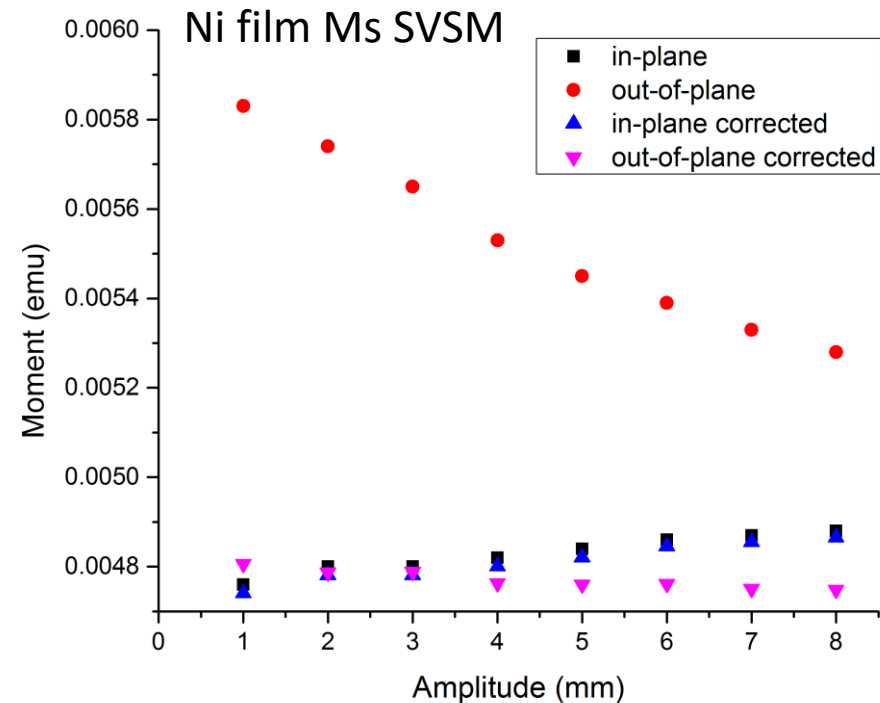
Final Lock-in voltage =

Gain x Moment x Sample geometry factor x Coil geometry factor x Amplitude x Frequency

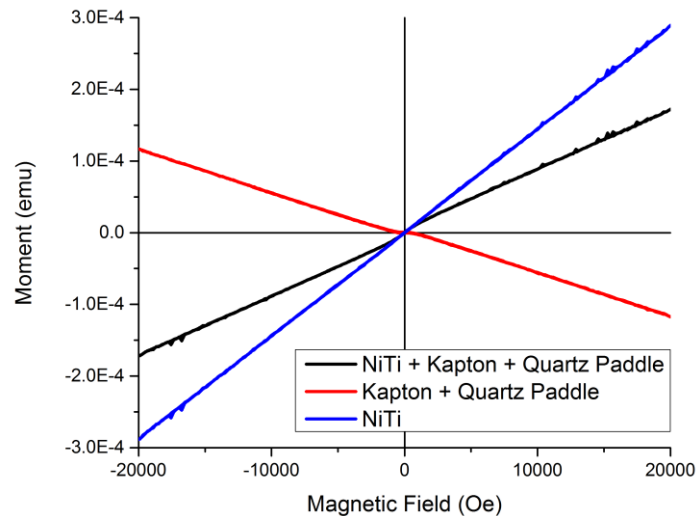
➡ QD Software : Corrected Moment = Measured Moment / Correction Factor

The screenshot shows the 'MPMS 3 Sample Geometry Simulator' window. It is divided into four main sections: Reference Geometry (Pd Cylinder), Sample Geometry, Measurement Parameters, and Estimated Correction Factors. The Reference Geometry section has input fields for Height (mm) at 3.80, Diameter (mm) at 2.80, and DC Scan Length (mm) at 30. The Sample Geometry section has a dropdown menu set to 'Thin Film (Field ⊥ ab)', input fields for 'a (mm)' and 'b (mm)' both at 4, and a 'Radial Offset (mm)' field at 0. The Measurement Parameters section has 'VSM Amplitude (mm)' at 8 and 'DC Scan Length (mm)' at 30. The Estimated Correction Factors section shows 'VSM Measurement' at 1.112 and 'DC Scan' at 1.077. A 'Calculate' button is located at the bottom right.

Section	Parameter	Value
Reference Geometry (Pd Cylinder)	Height (mm)	3.80
	Diameter (mm)	2.80
	DC Scan Length (mm)	30
Sample Geometry	Sample Geometry	Thin Film (Field ⊥ ab)
	a (mm)	4
	b (mm)	4
	Radial Offset (mm)	0
Measurement Parameters	VSM Amplitude (mm)	8
	DC Scan Length (mm)	30
Estimated Correction Factors	VSM Measurement	1.112
	DC Scan	1.077



Experimental limiting factors : background



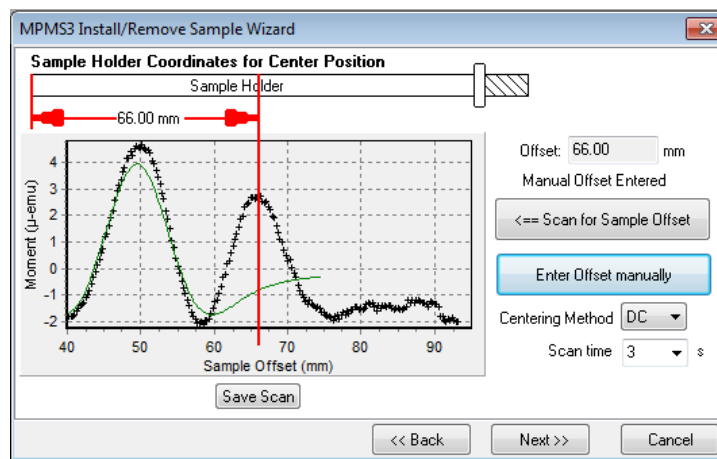
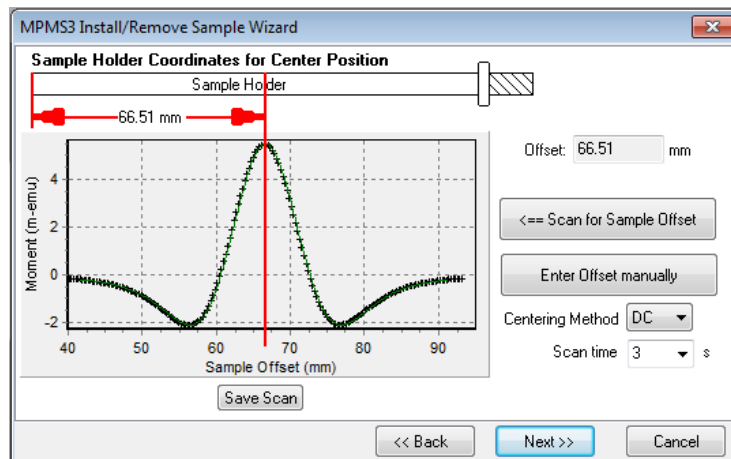
Final Lock-in voltage =

Gain x Moment x Sample geometry factor x Coil geometry factor x Amplitude x Frequency

contains any magnetic signal from the environment (background)

Here, same piece of Kapton tape and sample holder measured without the sample to obtain background signal.

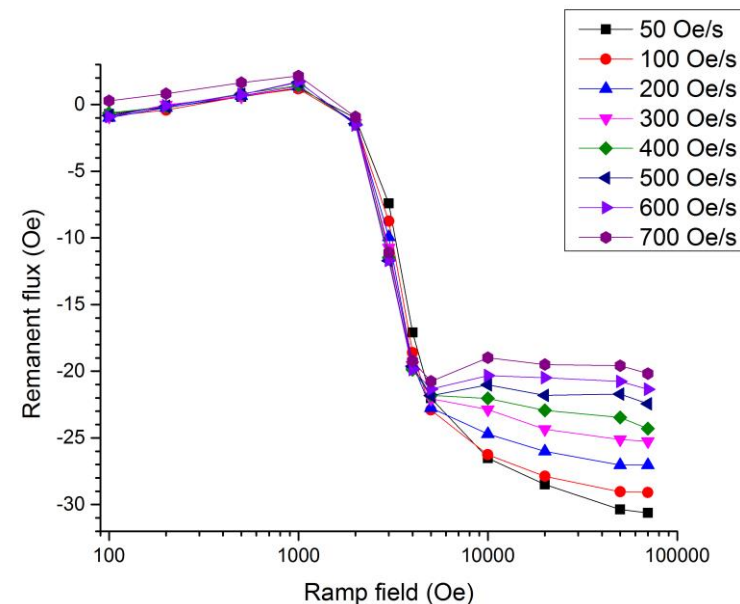
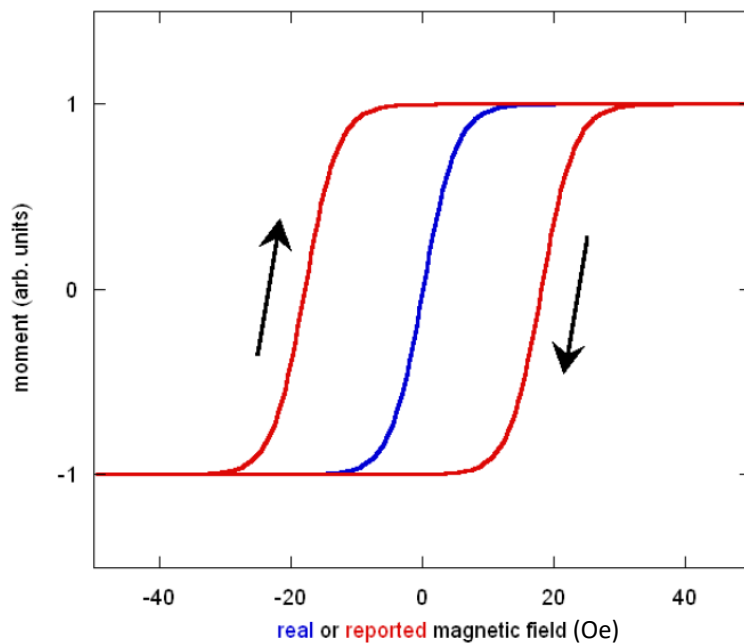
But it can be worst... and if you don't check, you don't find out



In the case of a non-uniform background signal, the software is still trying to fit the curve whatever the curve is.

Experimental limiting factors : trapped field

The superconductive magnet can have trapped flux especially when the magnet has been loaded at fields larger $\sim 0,5$ T



The System does not measure the actual field. The reported field is calculated based on the current placed in the magnet.

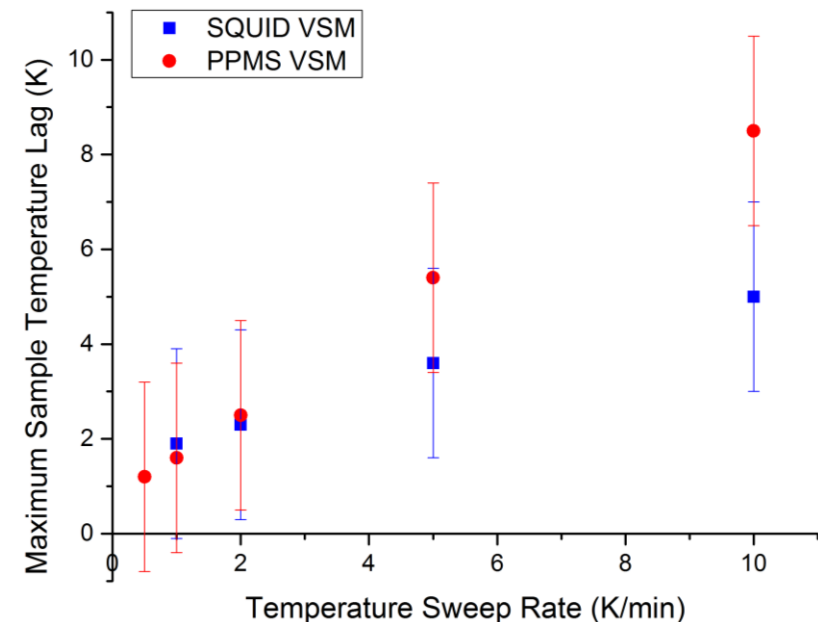
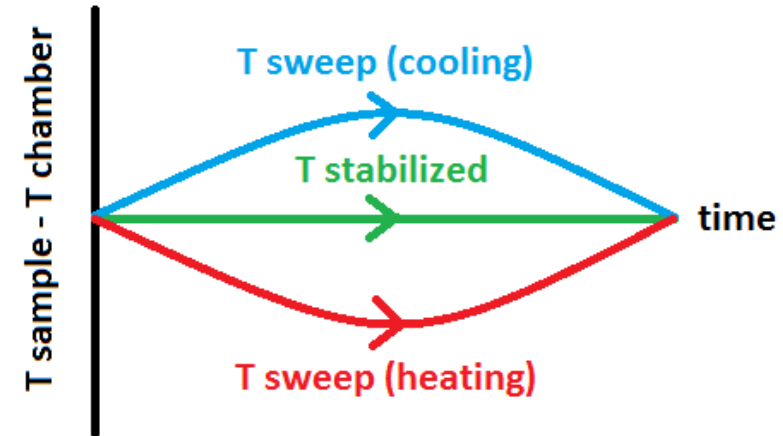
Experimental limiting factors : temperature



When measuring while temperature is sweeping, there will be thermal lag between the measured and the actual sample temperature.



**Don't sweep faster than 3K/min
even if your tool can go 20K/min**



Outline

I. Few preliminary details about the sample environment

➡ Magnetic field, Temperature

II. Static macroscopic magnetometry techniques

➡ VSM, SQUID, **Torque, MOKE, XMCD**

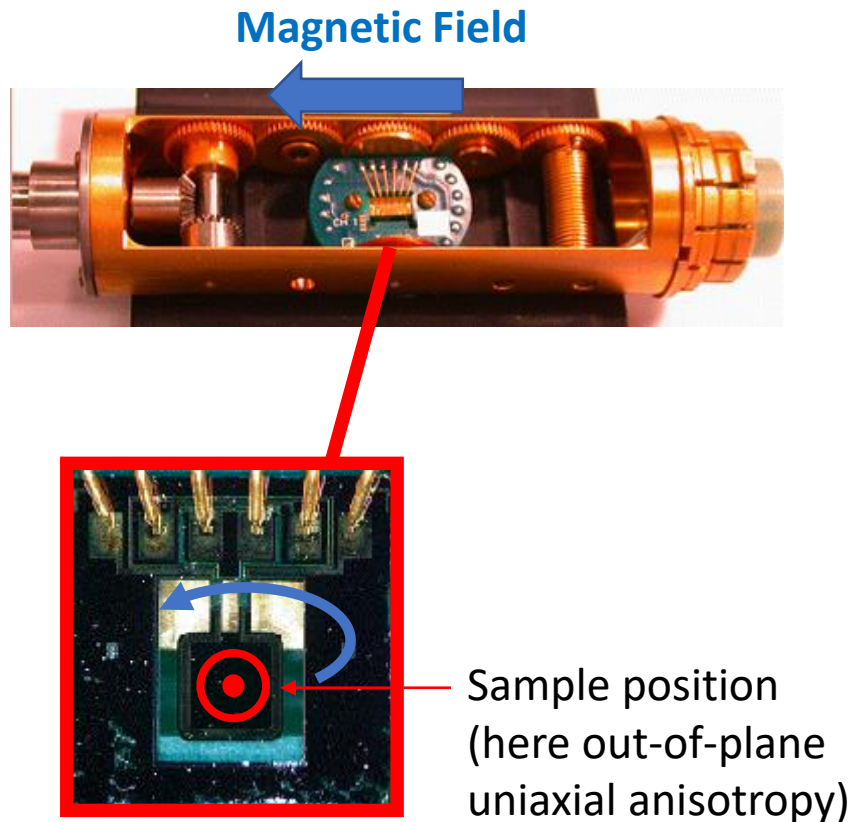
III. AC macroscopic magnetometry techniques

➡ AC susceptometry

IV. Imaging techniques

➡ Scanning probe microscopies, Photon-out

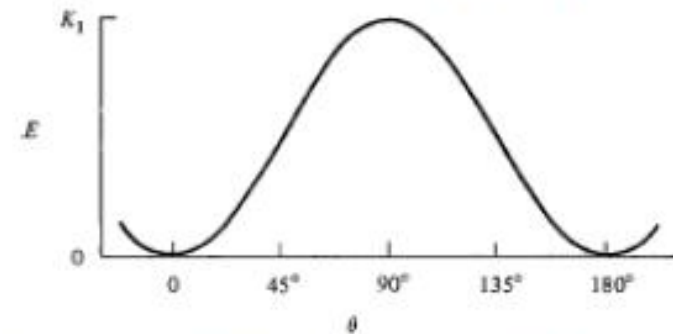
Torque magnetometry



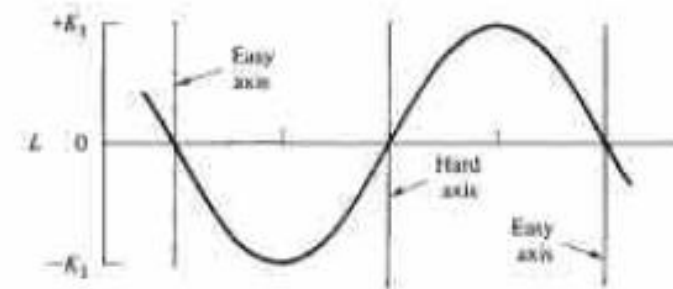
Torque measured via piezoelectricity

$$\text{Torque: } \tau = \vec{M} \times \vec{B} = -\frac{dE}{d\theta}$$

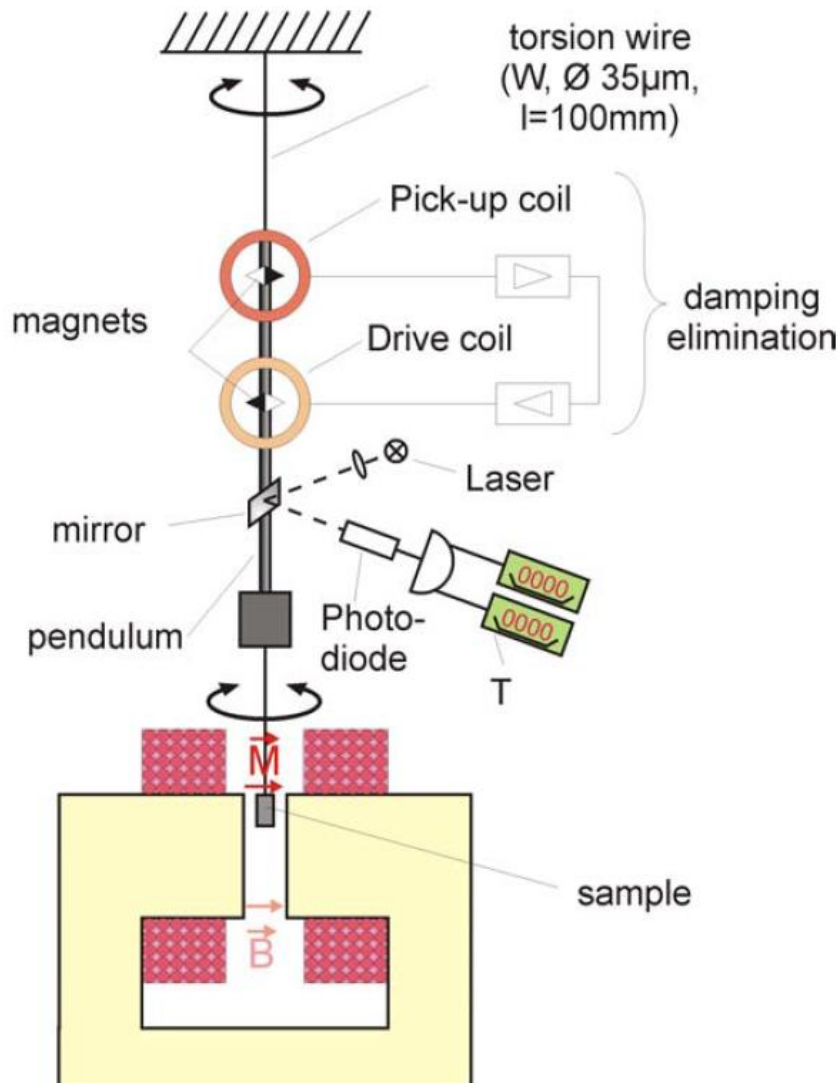
Uniaxial anisotropy $E_a = K_1 \sin^2\theta$



$$\text{Torque } -dE_{\text{tot}}/d\theta = -dE_a/d\theta = -K_1 \sin 2\theta$$

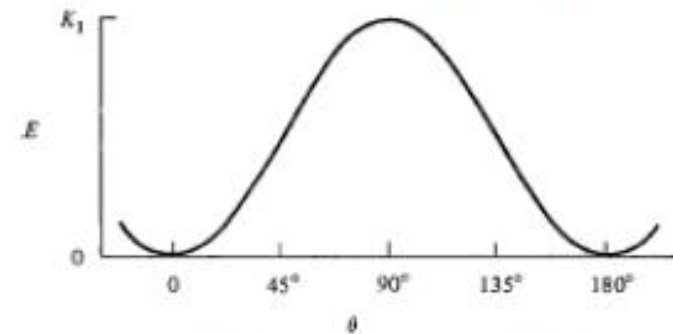


Torque magnetometry

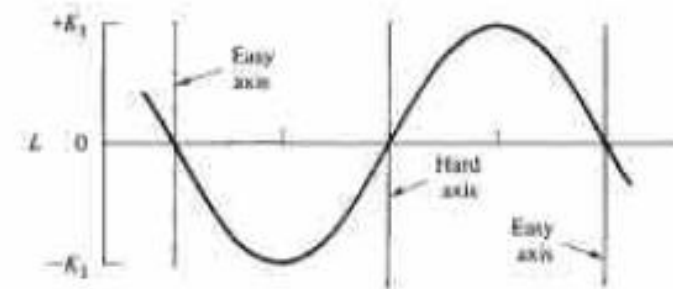


$$\text{Torque: } \tau = \vec{M} \times \vec{B} = -\frac{dE}{d\theta}$$

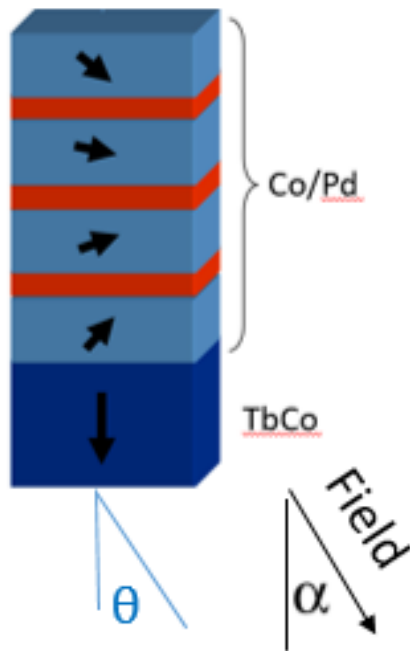
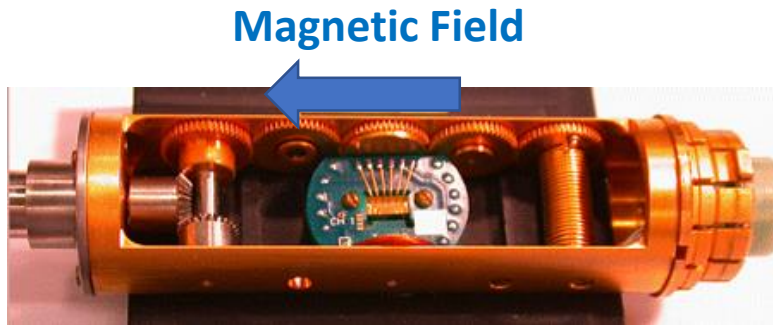
$$\text{Uniaxial anisotropy } E_a = K_1 \sin^2\theta$$



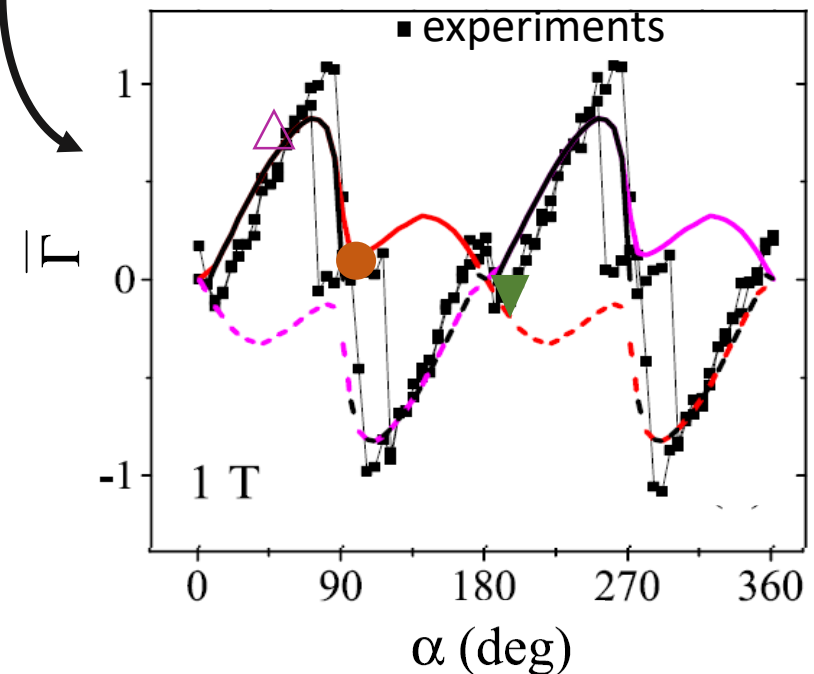
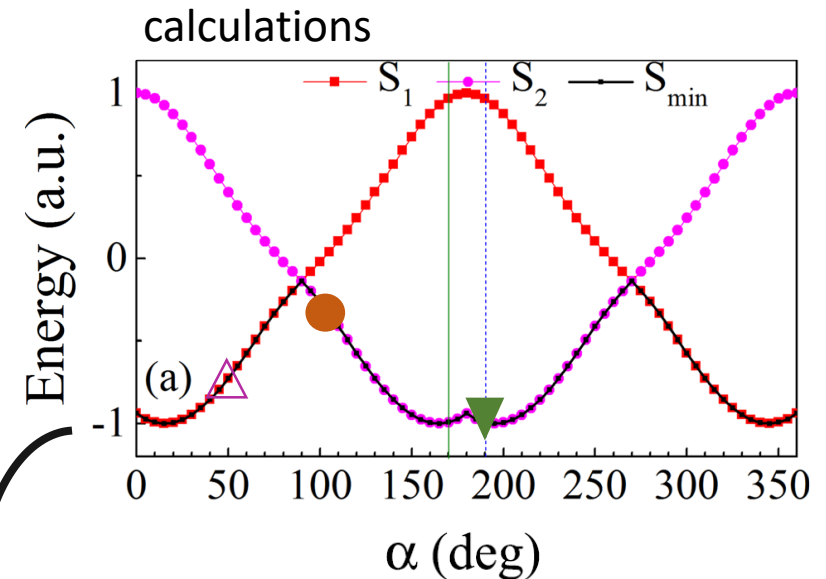
$$\text{Torque } -dE_{\text{tot}}/d\theta = -dE_a/d\theta = -K_1 \sin 2\theta$$



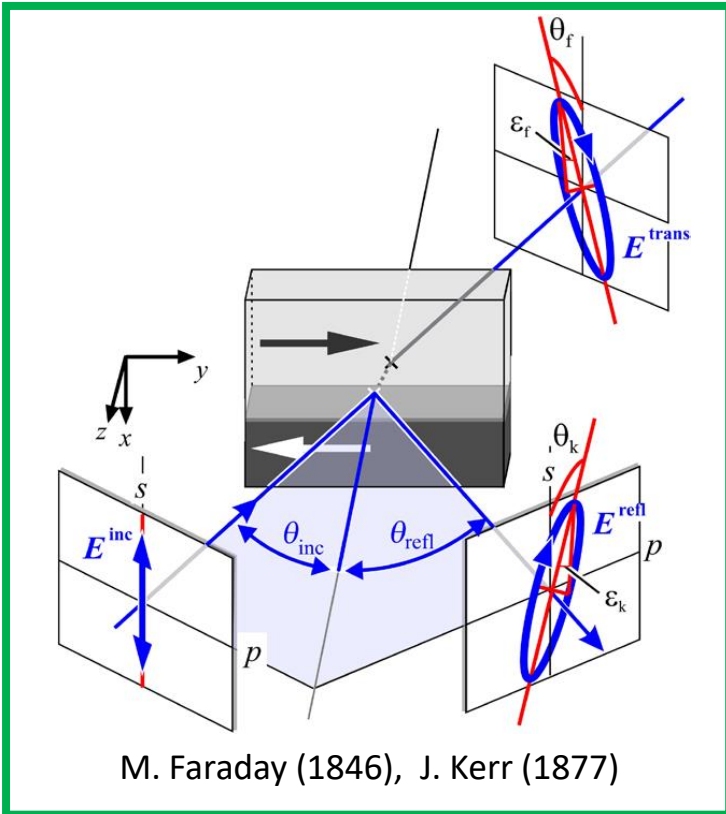
Torque magnetometry : non-uniform configuration



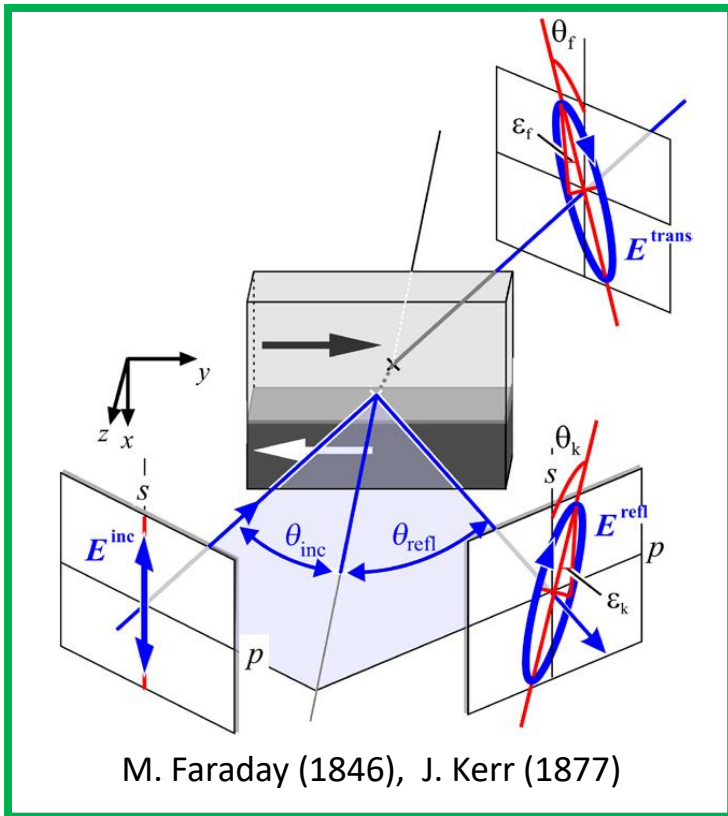
$$\text{Torque } \tau = \frac{dE}{d\alpha}$$



Magneto-optical Kerr effect magnetometry



Magneto-optical Kerr effect magnetometry



Classical description

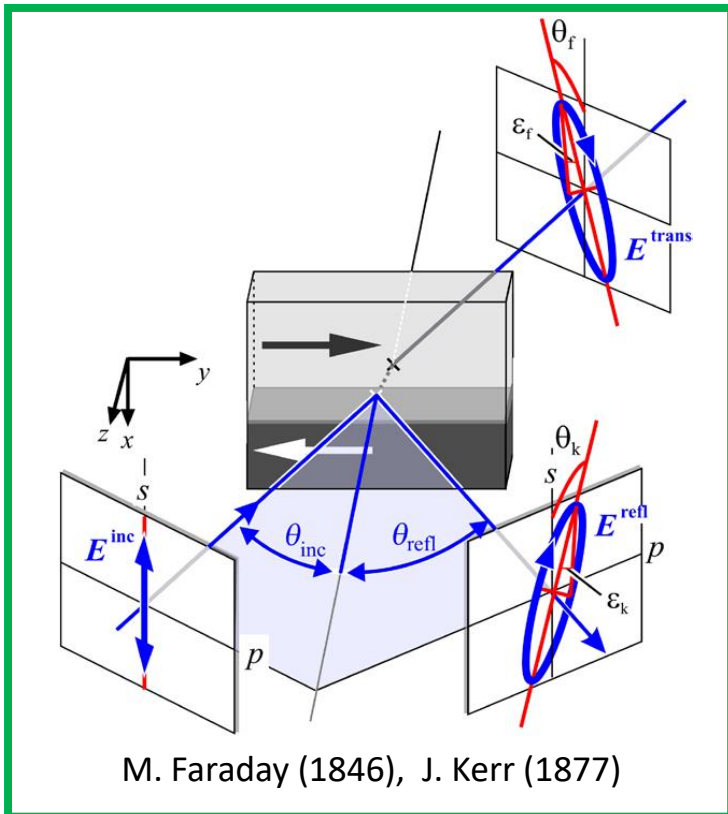
dielectric conductivity tensor $\vec{\sigma} = \begin{bmatrix} \sigma_0 & -\sigma_1 m_z & 0 \\ \sigma_1 m_z & \sigma_0 & 0 \\ 0 & 0 & \sigma_0 \end{bmatrix}$

diagonalization $\rightarrow$

$$\begin{aligned} \sigma_+ &= \sigma_0 - i\sigma_1 \\ \sigma_- &= \sigma_0 + i\sigma_1 \\ \sigma_z &= \sigma_0 \end{aligned}$$

$n_{\pm}(\omega) = \sqrt{1 + \frac{4\pi i}{\omega} \sigma_{\pm}(\omega)}$

Magneto-optical Kerr effect magnetometry



Classical description :

dielectric conductivity tensor $\vec{\sigma} = \begin{bmatrix} \sigma_0 & -\sigma_1 m_z & 0 \\ \sigma_1 m_z & \sigma_0 & 0 \\ 0 & 0 & \sigma_0 \end{bmatrix}$

diagonalization $\rightarrow$

$$\begin{aligned} \sigma_+ &= \sigma_0 - i\sigma_1 \\ \sigma_- &= \sigma_0 + i\sigma_1 \\ \sigma_z &= \sigma_0 \end{aligned}$$

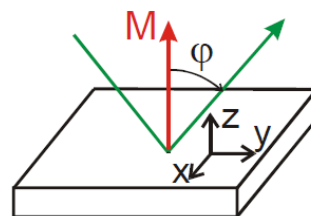
$n_{\pm}(\omega) = \sqrt{1 + \frac{4\pi i}{\omega} \sigma_{\pm}(\omega)}$

More generally : 3 useful configurations

$$\vec{\sigma}(\vec{M}) = \begin{bmatrix} \sigma_0 & -\sigma_1 m_z & \sigma_1 m_y \\ \sigma_1 m_z & \sigma_0 & -\sigma_1 m_x \\ -\sigma_1 m_y & \sigma_1 m_x & \sigma_0 \end{bmatrix}$$

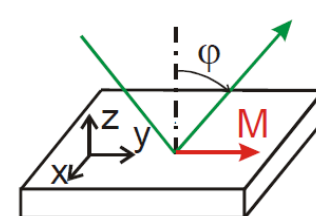
Polar Kerr effect (PMOKE)

$M \perp$ sample surface



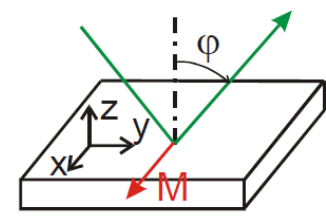
Longitudinal Kerr effect (LMOKE)

$M \parallel$ plane of incidence



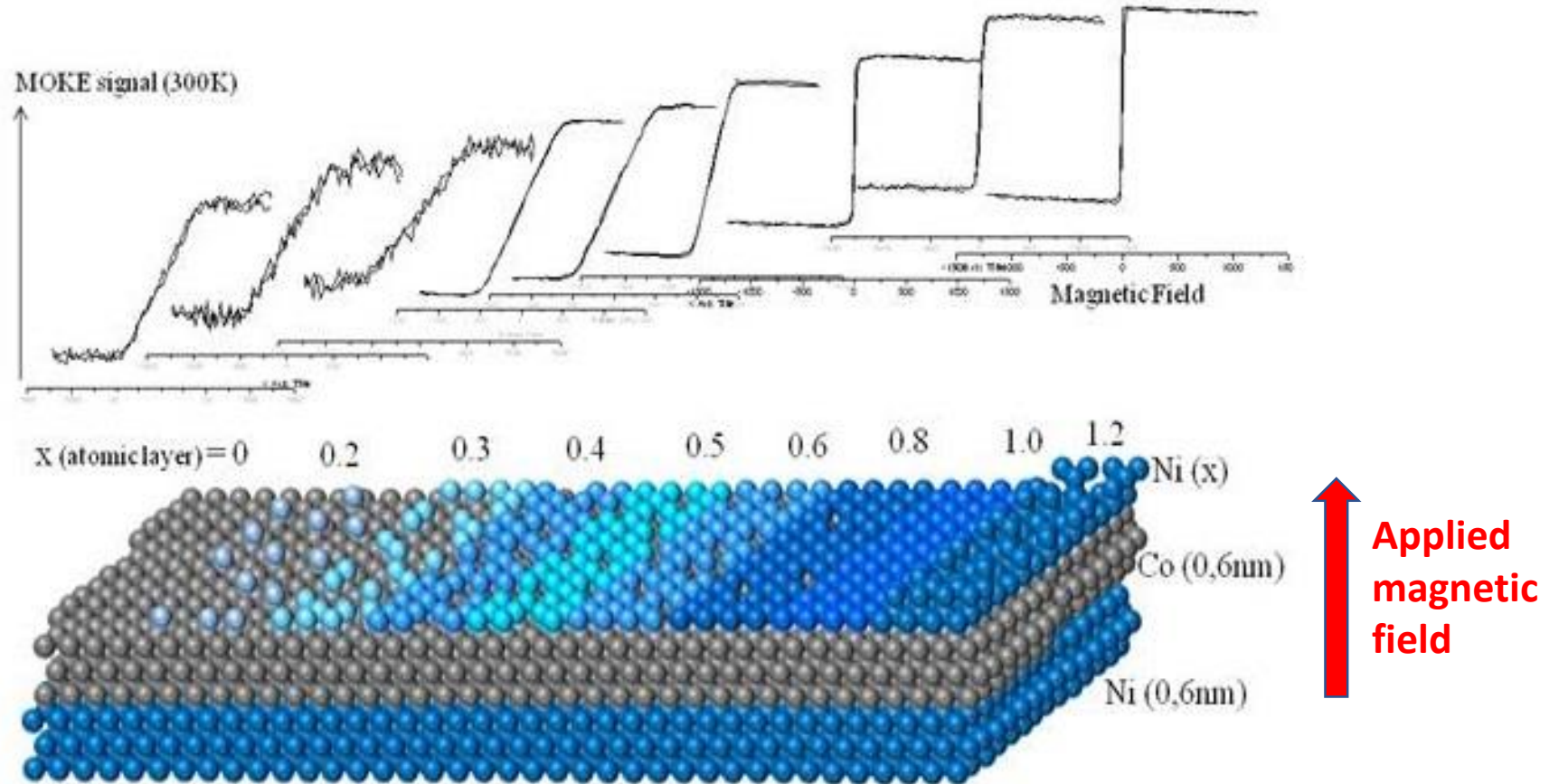
Transversal Kerr effect (TMOKE)

$M \perp$ plane of incidence



MOKE example : sensitive to surfaces

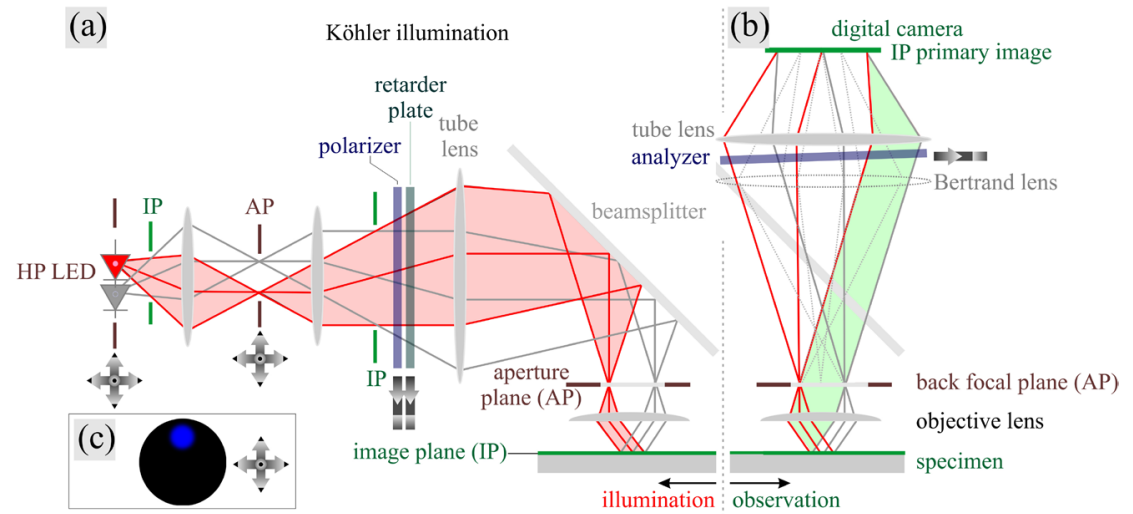
Example : study of magnetic anisotropy in multilayer thin film Ni(0.6nm)/Co(0.6nm)/Ni(x)



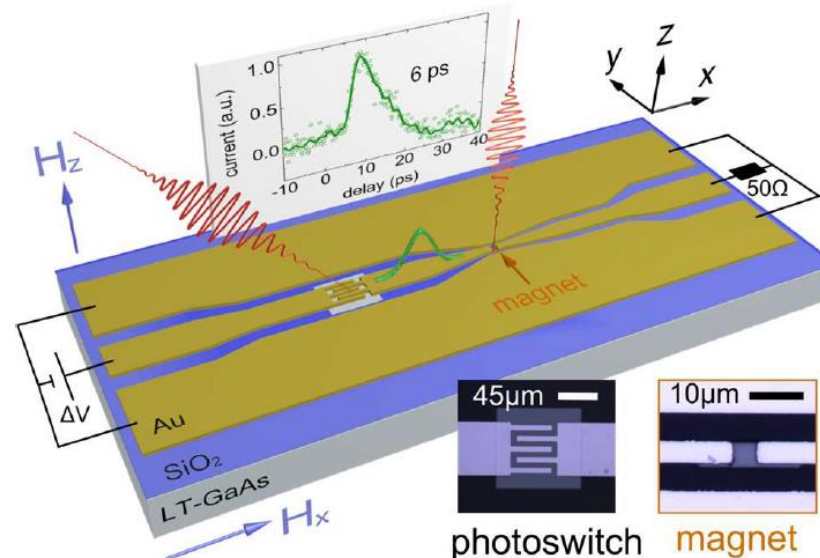
MOKE is only sensitive to about 20-50 nm thickness at the materials surface

MOKE magnetometry : imaging and dynamics

MOKE can be focused and so it can be used to perform magnetic microscopy

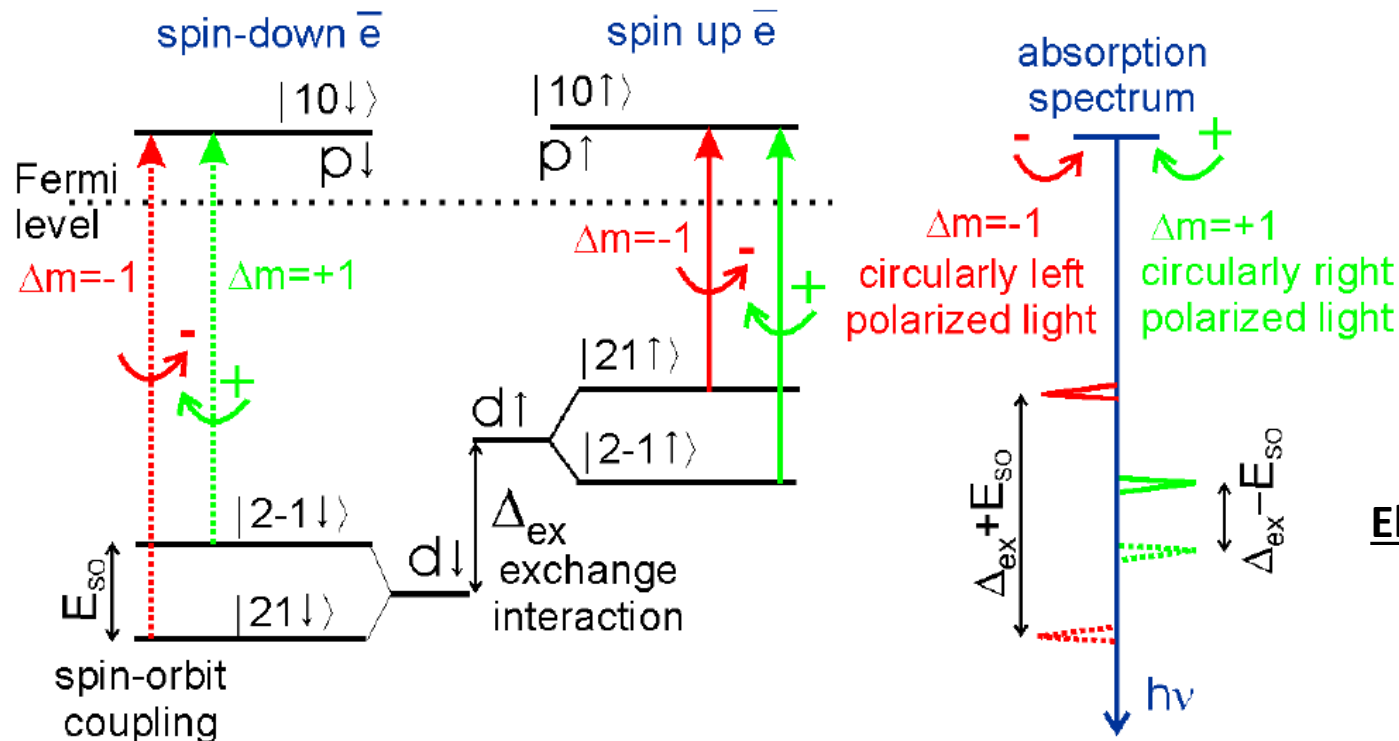


Laser can be pulsed so that MOKE can be used to probe magnetic changes at different timescales down to femtosecond



Picosecond SOT switching observed by MOKE
J. Gorchon arXiv:1912.01377

MOKE magnetometry : microscopic model



Transition energy $\approx eV$

Electron (l, m, s) transition rules :

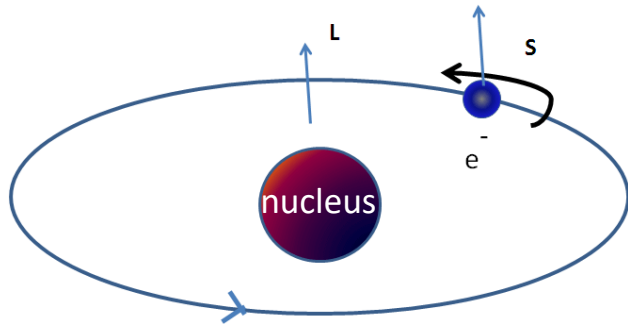
- Energy : $E_f - E_i = \hbar\omega$
(absorbed photon energy = difference between final and initial state)
- Electron spin : $\Delta s = 0$
(spin of electron is preserved for electric dipole transitions)
- Orbital momentum : $\Delta l = \pm 1$
(photon has angular momentum $1\hbar$).
Therefore only $s \leftrightarrow p$, $p \leftrightarrow d$ etc. are allowed
- Orbital momentum along z-axis : $\Delta m = \pm 1$
(determines if photon is right/left polarized)

Hulme, Proc. R. Soc. London **A135**, 237 (1932)

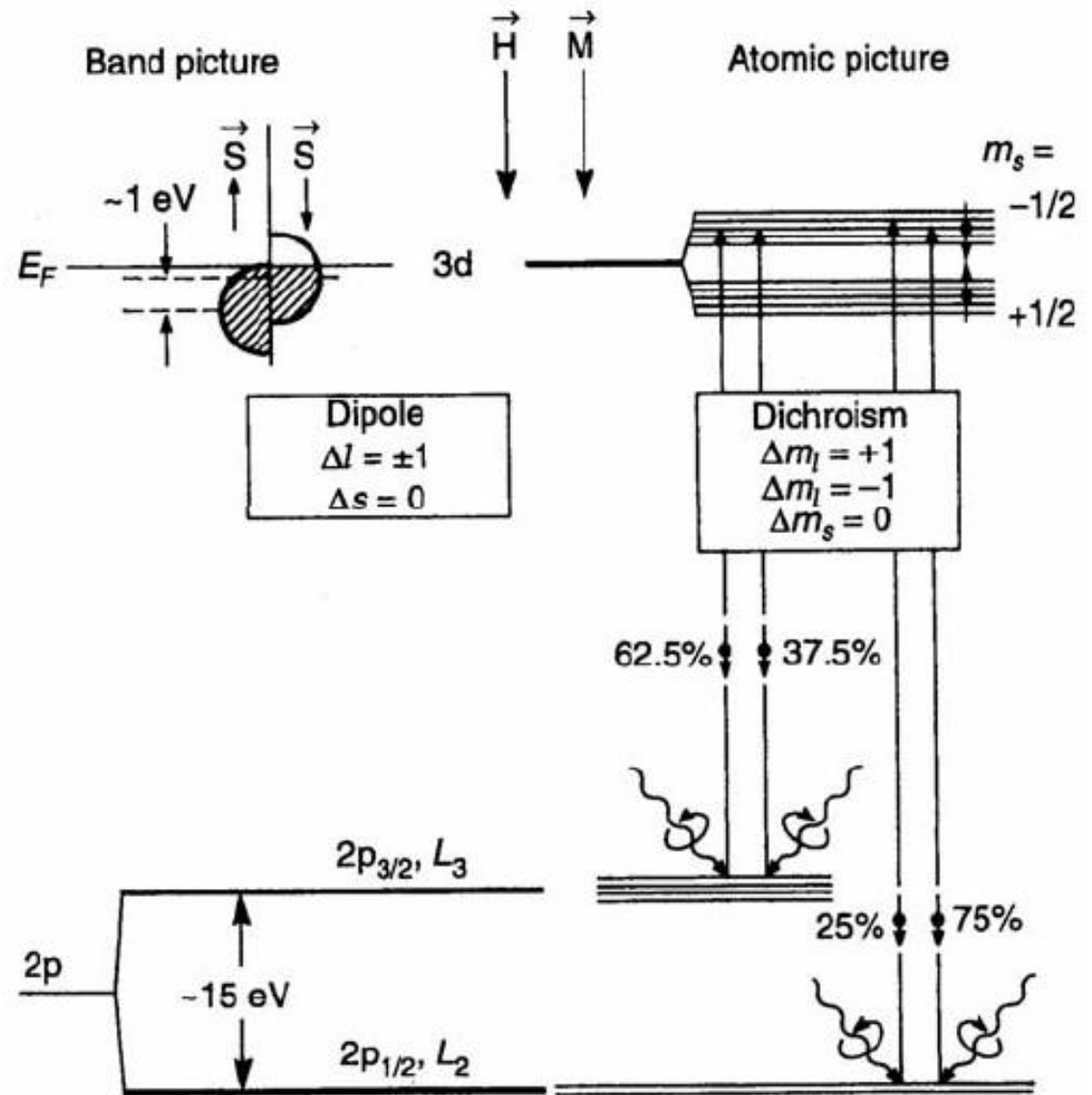
Bruno, PRB **53**, 9214 (1995)

$\Rightarrow$ Both spin orbit coupling and exchange are necessary for MO activity

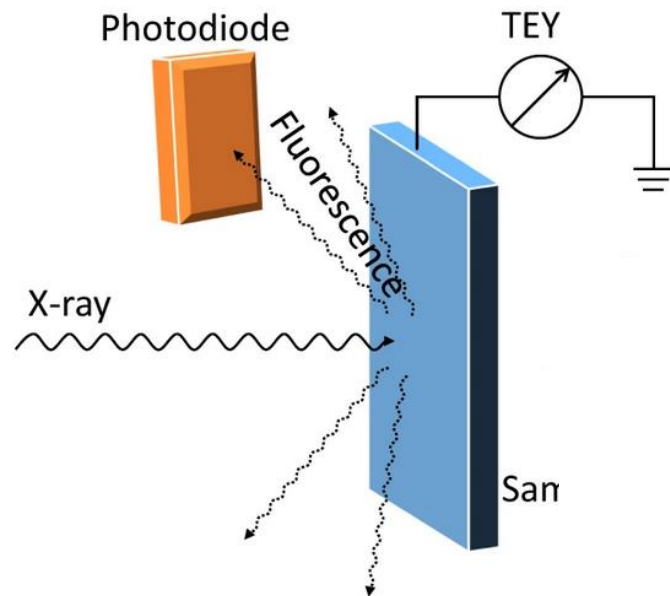
X-ray magnetic circular dichroism (XMCD)



- XMCD disentangles spin and orbital magnetic moment
- XMCD disentangle the moment from specific atoms in an alloy or a multilayer
- XMCD requires to work in synchrotron to get enough X-ray flux (700 - 900 eV for Fe,Co,Ni)



X-ray magnetic circular dichroism (XMCD)

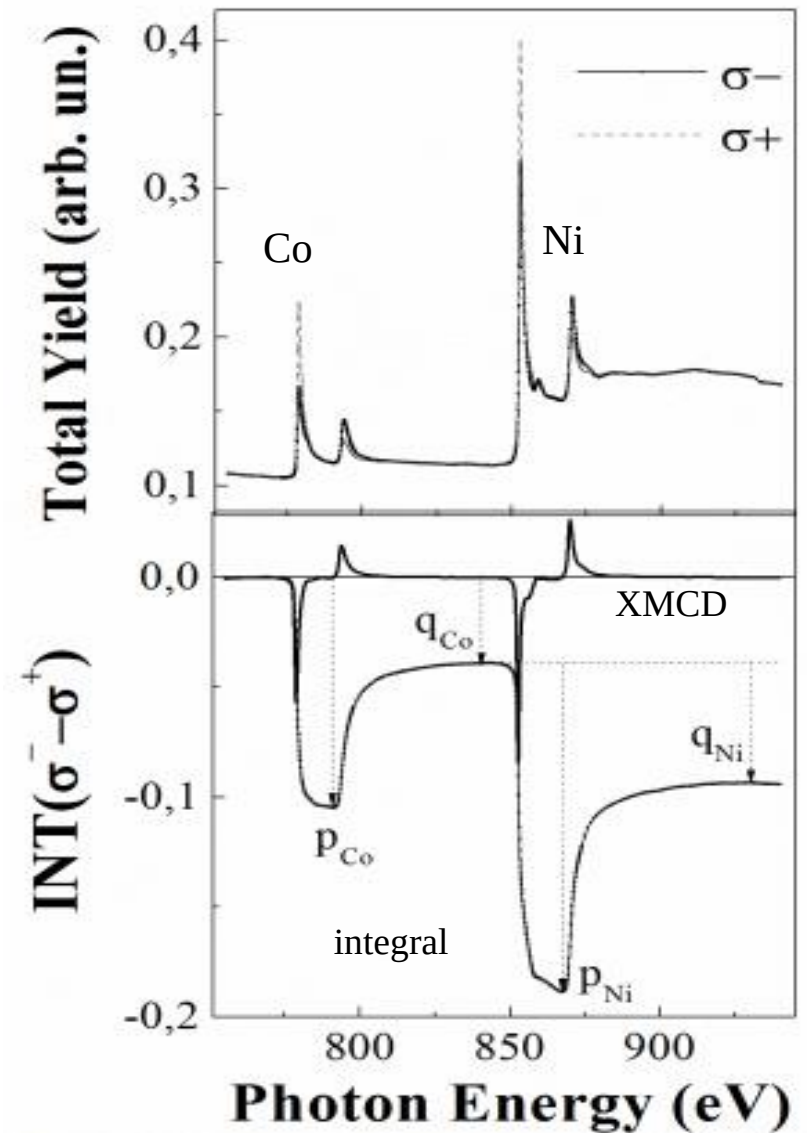


$$m_{\text{spin}}^{\text{eff}} = 2 \langle S_z^{\text{eff}} \rangle \frac{\mu_B}{\hbar} = n_h \cdot \left(\frac{3p - 2q}{r} \right) \mu_B$$

$$m_{\text{orb}} = \langle L_z \rangle \frac{\mu_B}{\hbar} = n_h \cdot \left(\frac{2q}{3r} \right) \mu_B$$

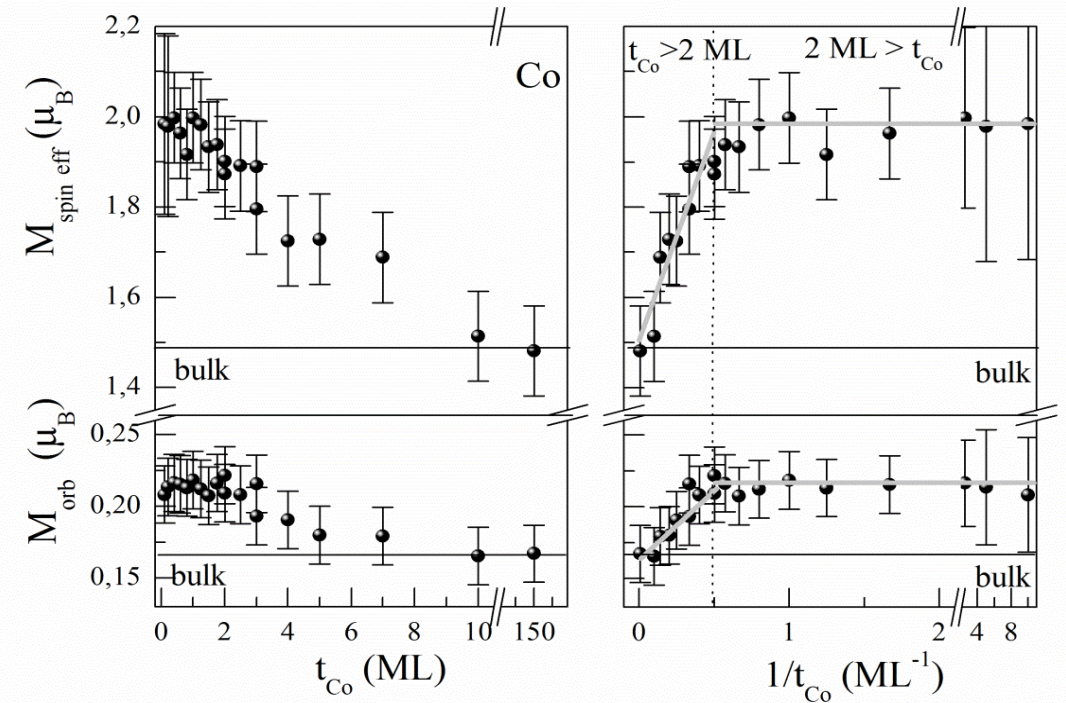
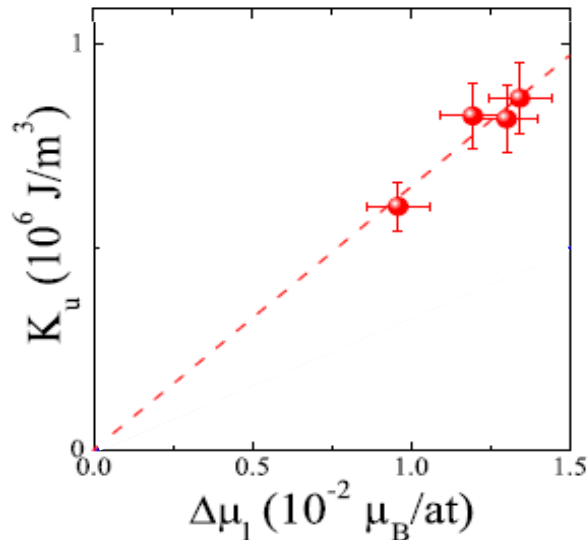
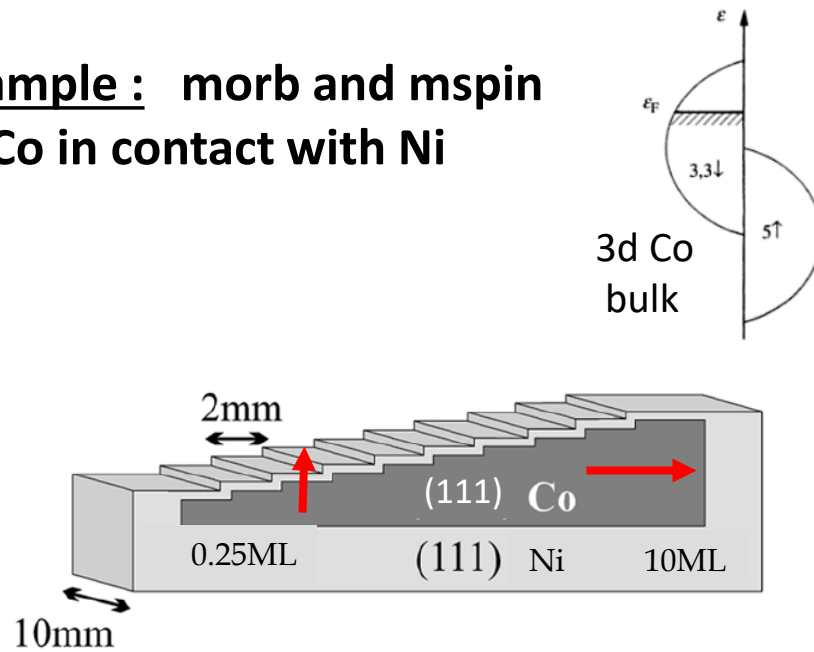


« Surface » sensitive technic (< 50 nm)



Example of XMCD data

Example : morb and mspin of Co in contact with Ni



- 1) Co Spin and orbital moments are affected by the Co/Ni interface electronic hybridizations
- 2) The macroscopic anisotropy constant is proportional to the anisotropy of orbital moment

$$K_u = A \frac{\xi N}{4V} \frac{\Delta\mu_l}{\mu_B}$$

Outline

I. Few preliminary details about the sample environment

➡ Magnetic field, Temperature

II. Static macroscopic magnetometry techniques

➡ VSM, SQUID, Torque, MOKE, XMCD

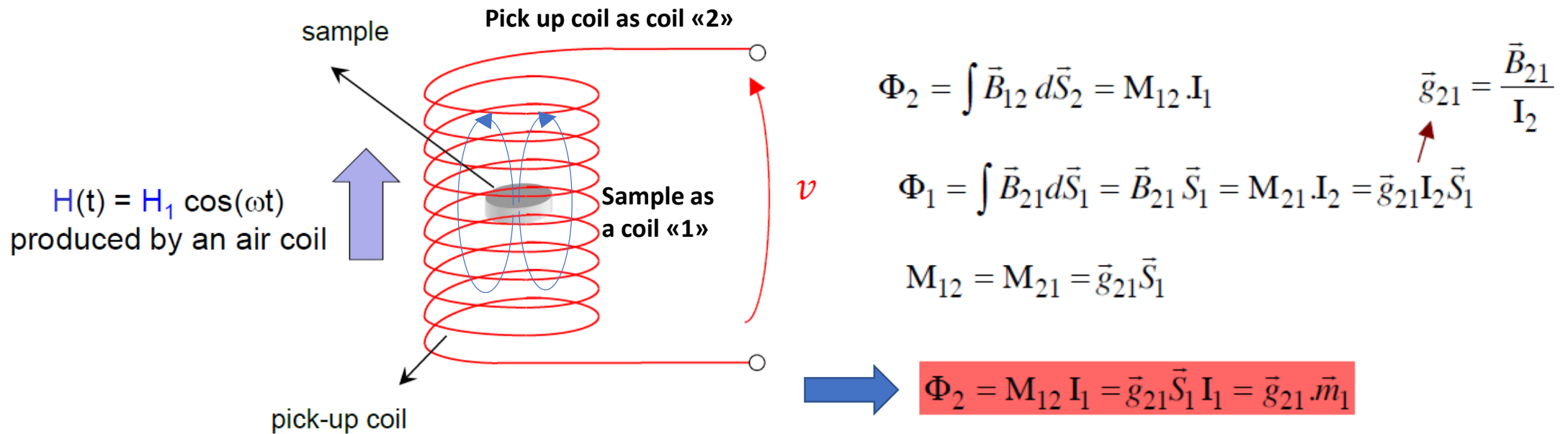
III. AC macroscopic magnetometry techniques

➡ **AC susceptometry**

IV. Imaging techniques

➡ Scanning probe microscopies, Photon-out

AC susceptometry : measure of susceptibility χ



Faraday's law

$$v = -\frac{\partial \Phi_2}{\partial t} = -g_{21} \frac{\partial m_1}{\partial t} \quad \text{avec} \quad \begin{cases} \vec{H}_1 = H_1 [e^{j\omega t}] \\ \vec{M}_1 = M_1 [e^{j\omega t}] \end{cases}$$

Here the sample does not move

$$v = \left(\frac{1}{\alpha} \right) V f H_1 \chi$$

Excitation frequency

Sample susceptibility

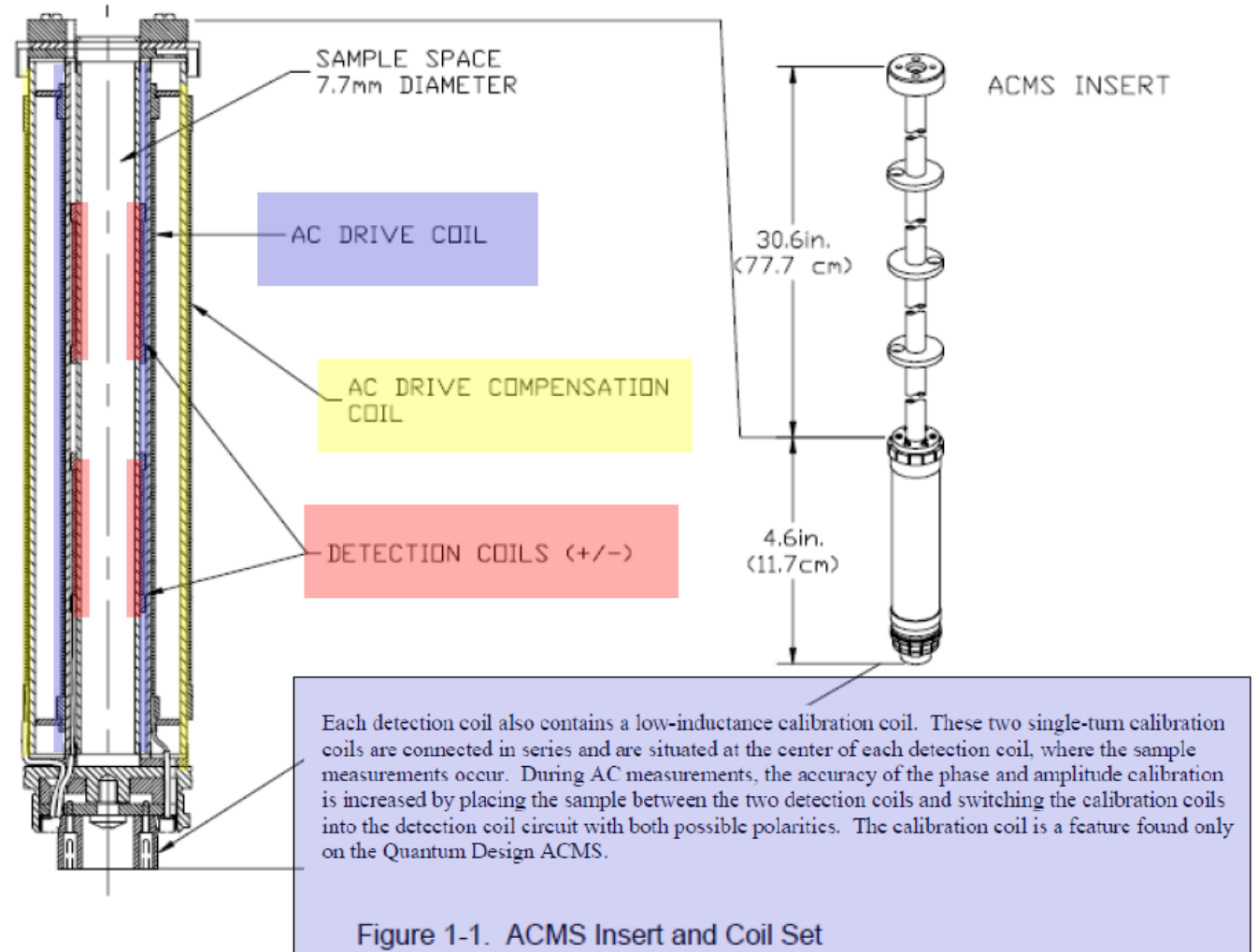
Sample volume

Proportionality factor

Coil sets in a PPMS



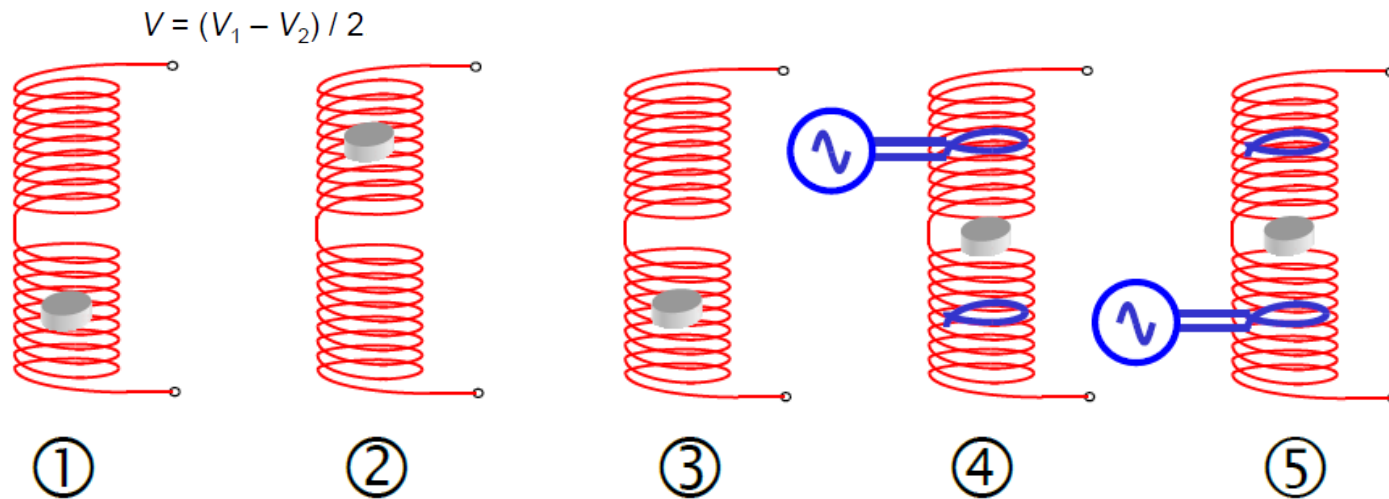
Frequency range 0.1Hz-1kHz
AC amplitude 0.01 à 1 mT



Physical Property Measurement System AC Measurement System Option User's Manual

Measurement method in a PPMS

2 coils in opposite current direction to cancel applied $H(t)$ and to be sensitive to the sample



By default, the sample undergoes a five-point measurement process that utilizes the calibration coil to increase measurement accuracy. The first reading is made with the sample positioned in the center of the bottom detection coil. Then the sample is positioned in the center of the top detection coil, and then in the center of the bottom coil again. During all three readings, the signals from the detection coil array are amplified, low-pass filtered, and digitized by an analog-to-digital converter (A/D). These signals are stored as waveform blocks in the data buffer. All 128 buffer points are used to record each response waveform. The points are fitted and compared to the driving signal to determine the real and imaginary components of the response when the sample is in the center of each detection coil. (Imaginary components are in phase with the driving signal and real components are 90° out of phase with the driving signal.) Subtracting one reading from the other gives a sample vector in the complex plane.

When the bottom-top-bottom coil readings are complete, the sample is placed at the center of the detection coil array so that it is between the two detection coils. Two more readings are taken with the calibration coil switched into the detection circuit with opposing polarities. The real and imaginary components of each response waveform are obtained by again fitting the data and comparing it to the driving signal. The two calibration readings are subtracted to yield a calibration vector in the complex plane. Subtracting the two calibration readings subtracts out the sample signal, leaving only environmental and instrumental factors that affect the reading.

①

②

③

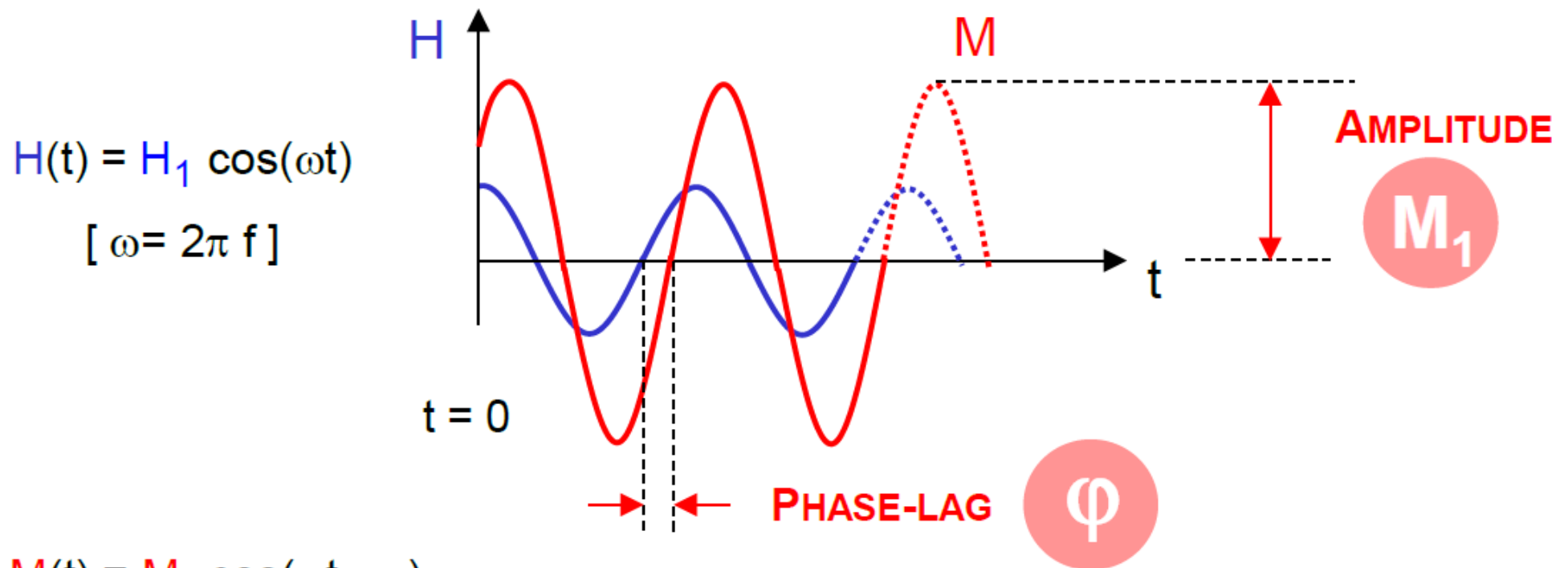
④

⑤

Measurement

Calibration

AC susceptometry equations



$$\begin{aligned}
 M(t) &= M_1 \cos(\omega t - \phi) \\
 &= \underbrace{M_1 \cos(\phi)}_{M'} \cos(\omega t) + \underbrace{M_1 \sin(\phi)}_{M''} \sin(\omega t)
 \end{aligned}$$

M'

M''

! Important remarks !

- $M(t)$ is assumed to follow a sinewave
- Physics dictates that M'' should be ≥ 0

$\bar{M}_1 = M_1 [e^{j\omega t}]$ with $\bar{\chi}_1 = \bar{M}_1 / H_1 = \chi' - j\chi''$

AC susceptometry equations

When $M(t)$ is assumed to follow a pure sinewave (i.e. only one « fundamental » signal at one frequency ω) the complex AC susceptibility reads:

$$\chi_1 = \chi = \chi' - j \chi''$$

In-phase
component

Out-of-phase
component

χ' is related to magnetic energy
stored in the material

$\chi' < 0$ for diamagnetic mat.

$\chi' > 0$ for paramagnetic mat.
ferromagnets
anti-ferromagnets
ferrimagnets
etc.

χ'' is related to magnetic energy
converted into heat

If there are no losses:

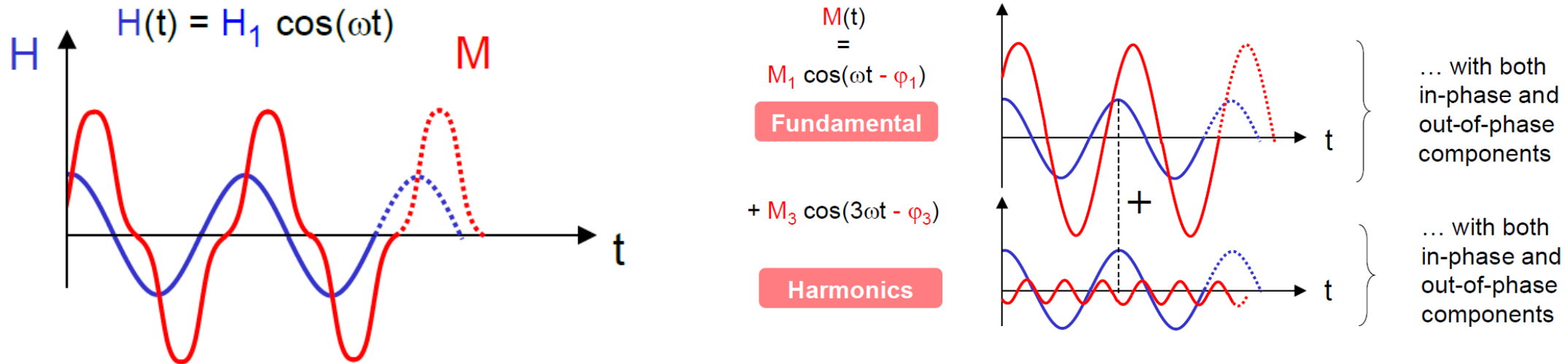
$$\chi'' = 0$$

If there are magnetic losses

$$\chi'' > 0$$

AC susceptometry equations

Most of the time M does not linearly vary with H :



BUT $M(t)$ is still a periodic signal of the same period as the AC field.
Therefore, thanks to the Fourier theorem, $M(t)$ reads

$$M(t) = H_1 \sum_{n=1}^{\infty} (\chi'_n \cos(n\omega t) + \chi''_n \sin(n\omega t))$$

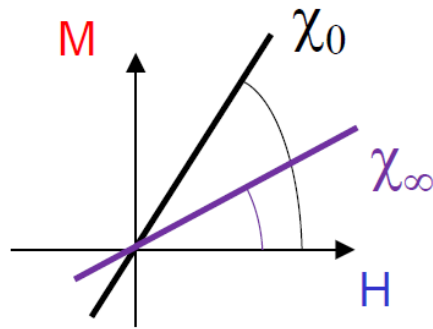
If $M(t)$ is a pure sinewave : χ'_1 and χ''_1 only $\rightarrow \chi' (= \chi'_1)$ and $\chi'' (= \chi''_1)$

If $M(t)$ is distorted : $\rightarrow$ the harmonic susceptibilities might be $\neq 0$

➤ Harmonics originate from the **non-linearity** of the M-H process

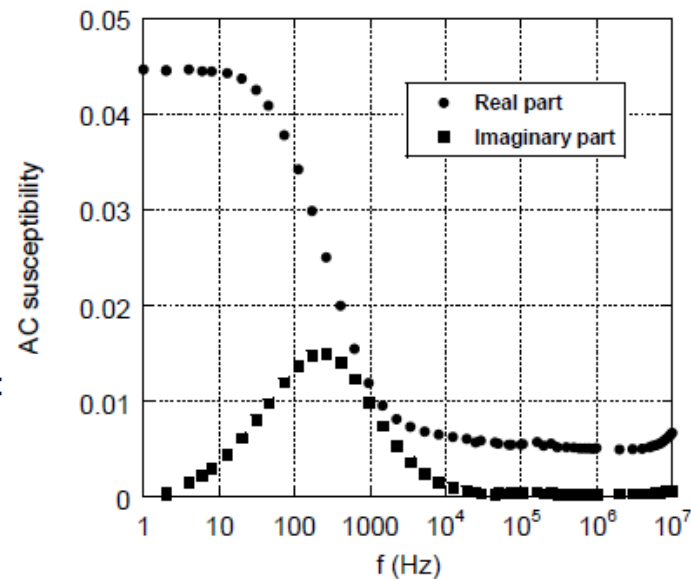
Examples of AC susceptometry data

To characterize
Brownian relaxation
of nanoparticles



We assume a Debye-type relaxation:

$$\chi = \chi_{\infty} + \frac{\chi_0 - \chi_{\infty}}{1 + j\omega\tau}$$



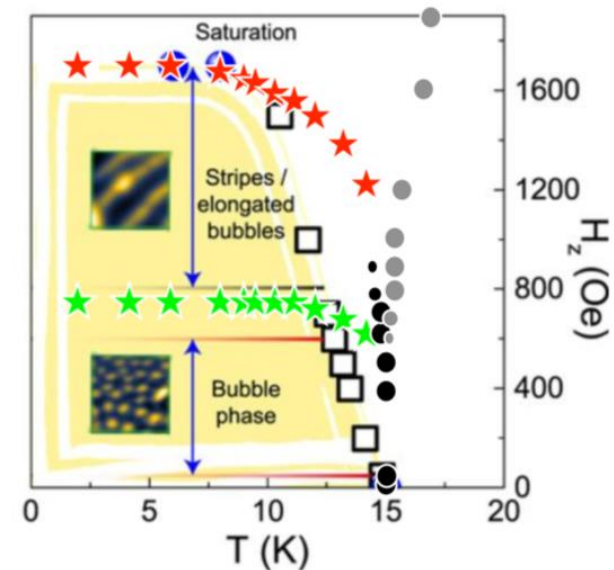
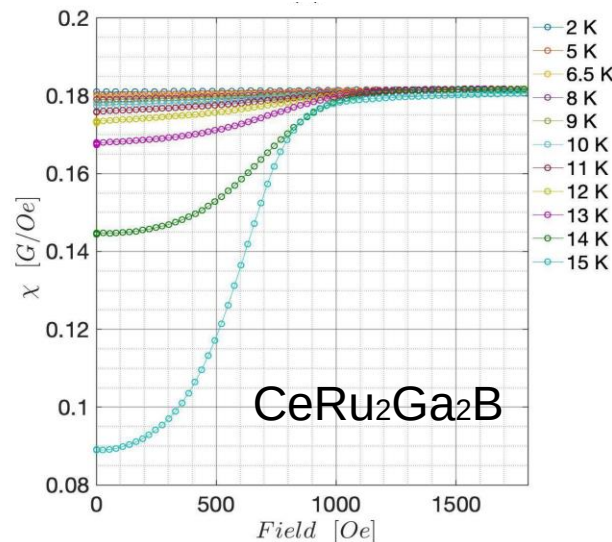
$$\chi' = \chi_{\infty} + \frac{\chi_0 - \chi_{\infty}}{1 + \omega^2\tau^2}$$

$$\chi'' = \frac{\omega\tau(\chi_0 - \chi_{\infty})}{1 + \omega^2\tau^2}$$

$$\chi'_n = 0 \quad \text{and} \quad \chi''_n = 0$$

➔ No harmonics

To find transition
between 2 magnetic
configurations



Outline

I. Few preliminary details about the sample environment

➡ Magnetic field, Temperature

II. Static macroscopic magnetometry techniques

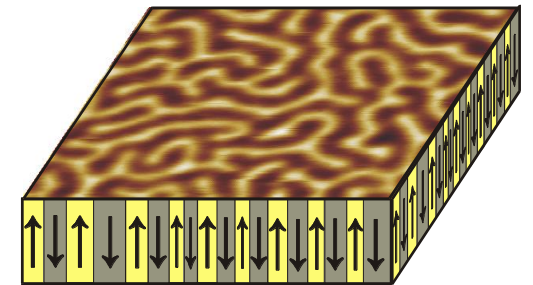
➡ VSM, SQUID, Torque, MOKE, XMCD, Photo-emission spectroscopy

III. AC macroscopic magnetometry techniques

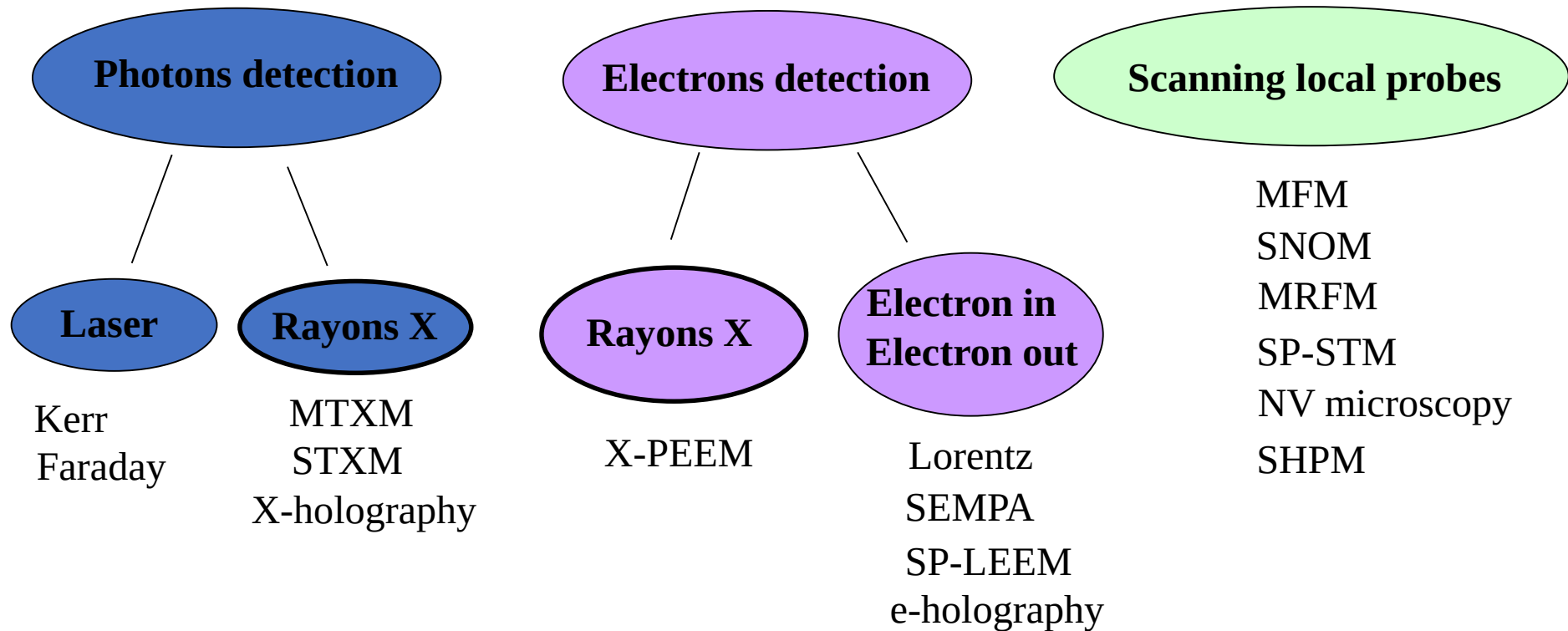
➡ AC susceptometry, FMR

IV. Imaging techniques

➡ **Scanning probe microscopies, Photon-out, Electron-out**



microscopy techniques : a rough map



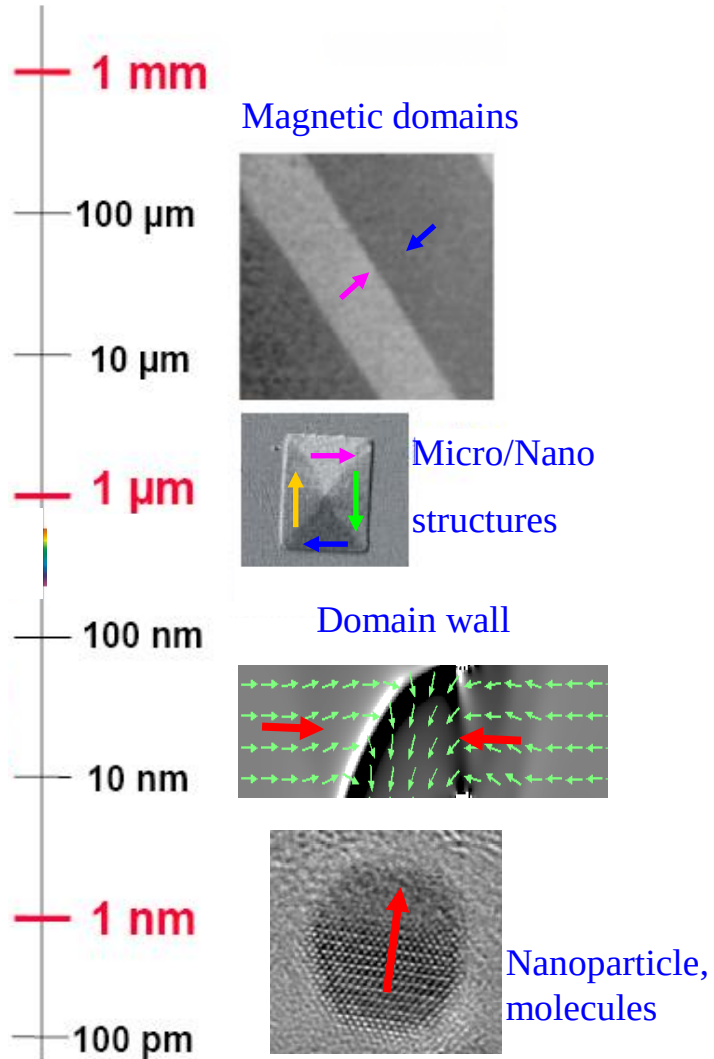
NV = NV center of diamond probe
MFM = magnetic force microscopy
MRFM = magnetoc resonance force microscopy
MTXM = magnetic transmission X-ray microscopy
SEMPA = scanning electron microscopy with polarization analysis
SNOM = scanning near field optical microscopy

SP-LEEM = spin polarized low energy electron microscopy
SP-STM = spin polarized scanning tunneling microscopy
STXM = scanning transmission X-ray microscopy
X-PEEM = X-ray photoemission electron microscopy
SHPM = scanning all probe microscopy

Which technics fits your need ?

The 1st parameter to check may be the size of your object...

Spatial scale

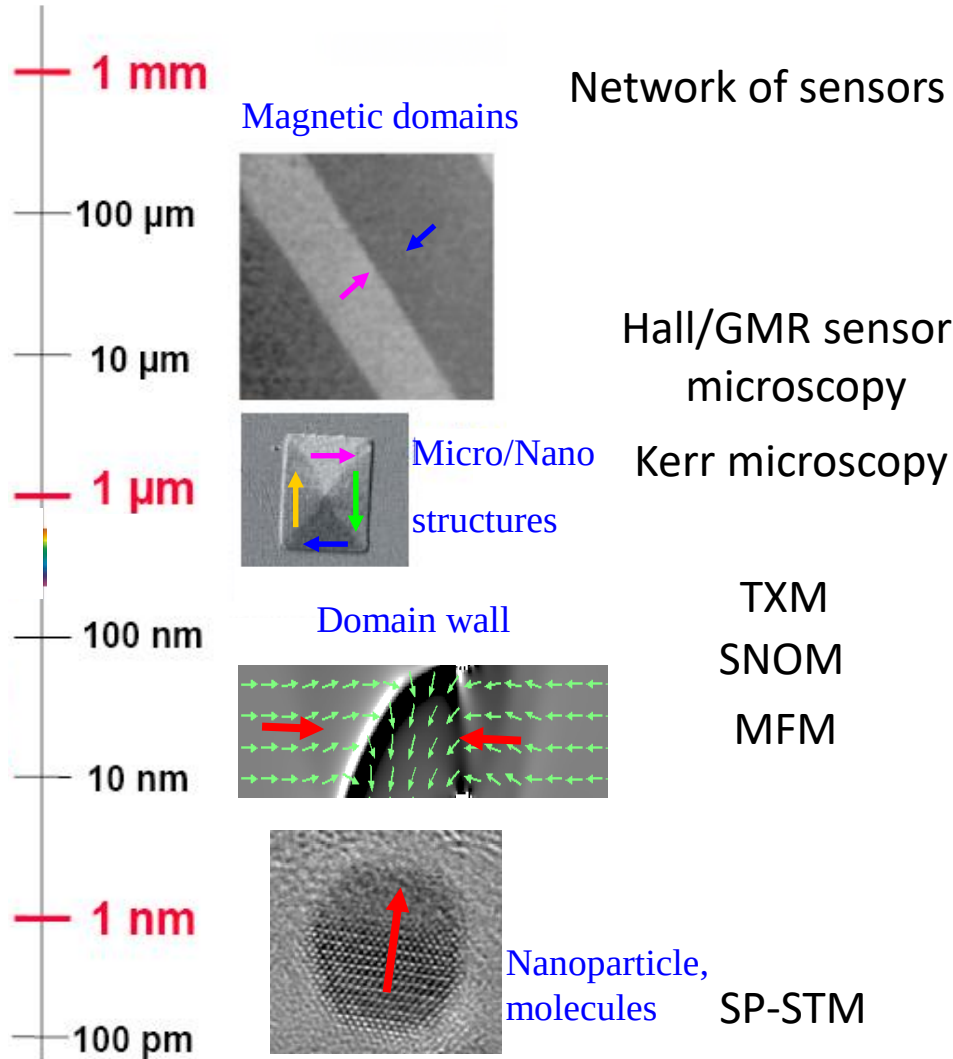


Which technics fits your need ?

The 1st parameter to check may be the size of your object...

Spatial scale

Microscopy techniques

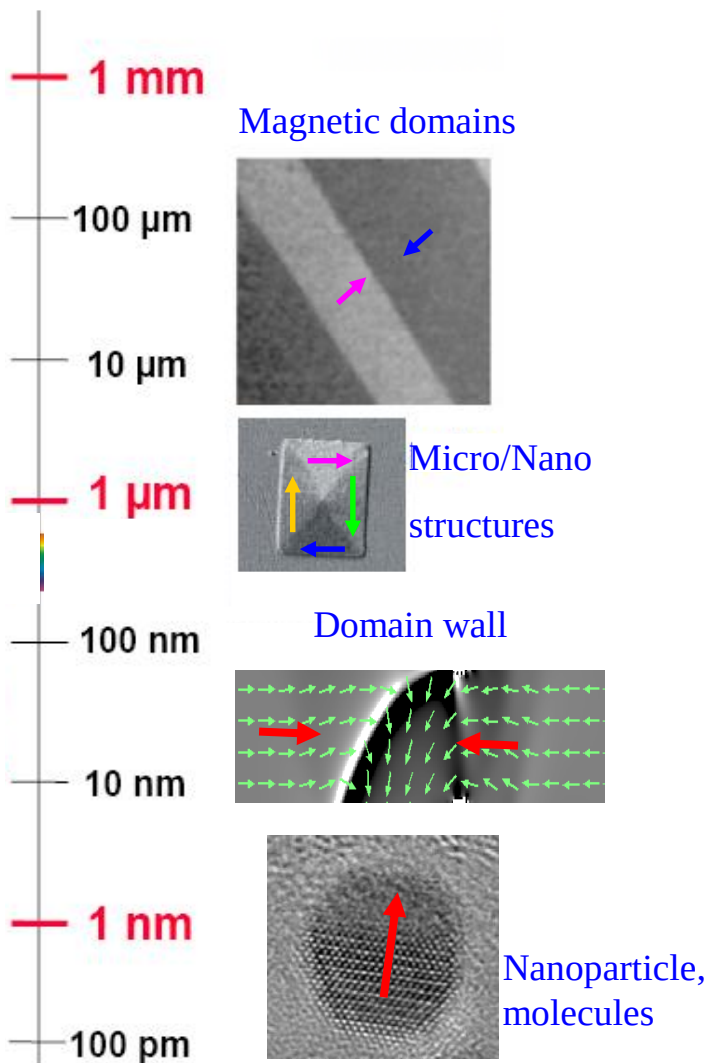


Technique	Probed Quantity	Spatial Resolution	Temporal Resolution	Info. Depth	Comments
Lorentz Microscopy	stray field + sample induction	10 nm	1 ns	sample average	Thin samples, Quantitative info. with differential phase contrast microscopy.
Electron Holography	stray field + sample induction	5 nm	10 ms	sample average	Quantitative info. through mathematical image reconstruction.
SEMPA	magnetization	20 nm	700 ps*	1 nm	Quantitative info., Long acquisitions, UHV required.
SP-STM	magnetization	atomic	120 ps*	surface	UHV required, Usually low temperature, Long acquisitions.
MFM	stray field	10-100 nm	low	1000 nm	Potentially invasive, Long acquisitions, Few sample requirements.
TXM	magnetization	25 nm	50 ps	sample average	Synchrotron technique, Quick overview images.
STXM	magnetization	25 nm	50 ps	sample average	Synchrotron technique, High repetition rates.
PEEM	magnetization	25 nm	50 ps	5 nm	Synchrotron technique, Discharges possible due to high potential.

Which technics fits your need ?

... But you also need to check other criteria...

Spatial scale



	Sp-STM	MFM	NV	BEMM	SEMPA	SPLEEM	TEM	XMCD-PEEM	XMCD-microscopy (Fresnel ZP)
Resolution	<1nm	15nm	5-10 nm	1-5nm	10nm	10nm	1-2nm	25nm $\rightarrow$ 10nm	15nm
Sensitivity	High	Med	High	Med	Med	High	Low	High	High
In-field	YES	Limited	Limited	YES	local	No?	Limited	No?	YES
Versatile*	No	YES	Yes	No	Yes	UHV	Limited	Yes	Limited
Dynamics	No	No	No	No	No	No	New	Yes	Yes
Element-sensitive	Limited	No	No	No	No	Limited	Limited	Yes	Yes
Probes	m_i	H_d	H_d	m_i	$\mathbf{m}$	$\mathbf{m}$	$m_{x,y}$	m_k	m_k

What is measured?

- ☐ Magnetization, induction, stray field?
- ☐ Elemental resolution
- ☐ Direct or indirect?
- ☐ Quantitative or not?

Environmental conditions

- ☐ Temperature
- ☐ Field: magnetic field, electric
- ☐ Electric current, light etc.
- ☐ Strain
- ☐ Additional measuring techniques

Which specifications?

- ☐ Magnetization: 1D, 2D, 3D
- ☐ Depth resolution: surface or volume?
- ☐ Lateral resolution
- ☐ Sensitivity
- ☐ Time/Spectral resolution

Versatility

- ☐ Sample preparation needed
- ☐ Time per one measurement
- ☐ In situ / ex situ
- ☐ Large-scale or in-lab?
- ☐ Expensive or cheap?

Outline

I. Few preliminary details about the sample environment

➡ Magnetic field, Temperature

II. Static macroscopic magnetometry techniques

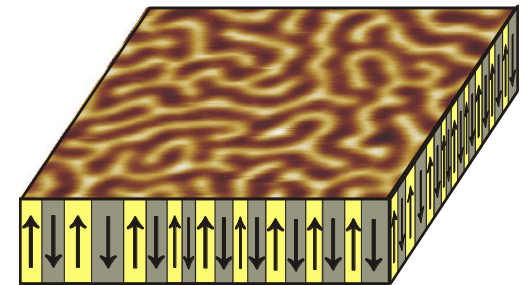
➡ VSM, SQUID, Torque, MOKE, XMCD

III. AC macroscopic magnetometry techniques

➡ AC susceptometry, FMR

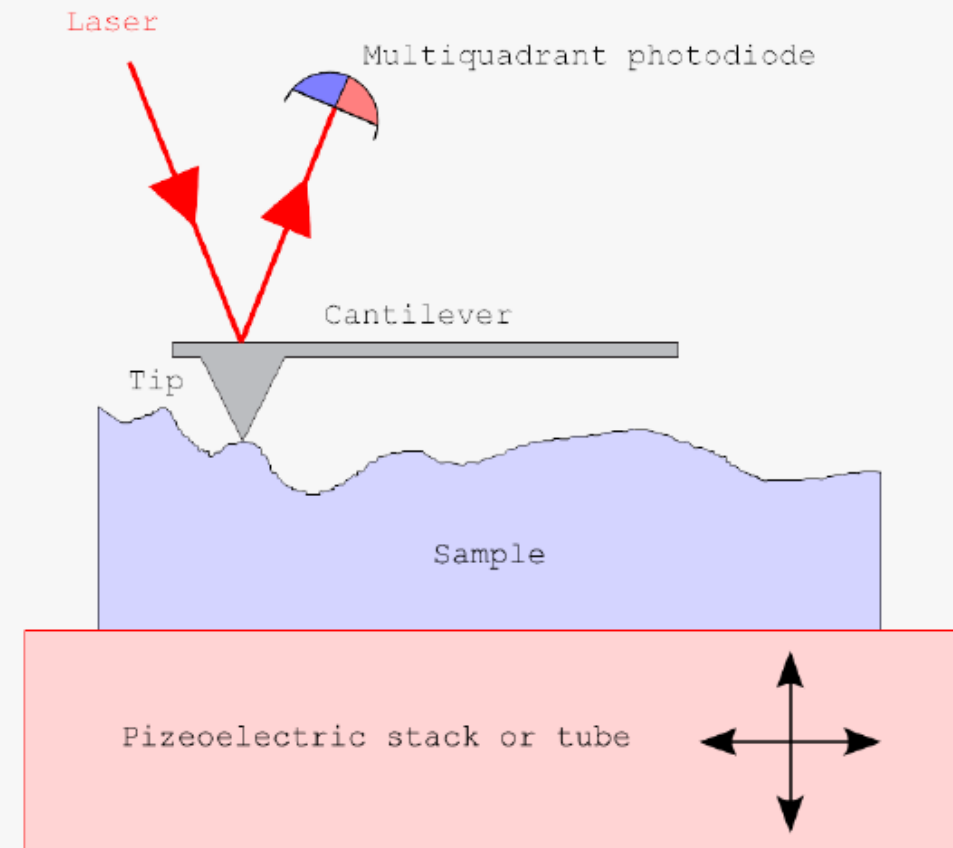
IV. Imaging techniques

➡ **Scanning probe microscopies**, Photon-out



Magnetic force microscopy

The Atomic Force Microscope (AFM)



G. Binnig et al., Phys. Rev. Lett. 56, 930 (1986)

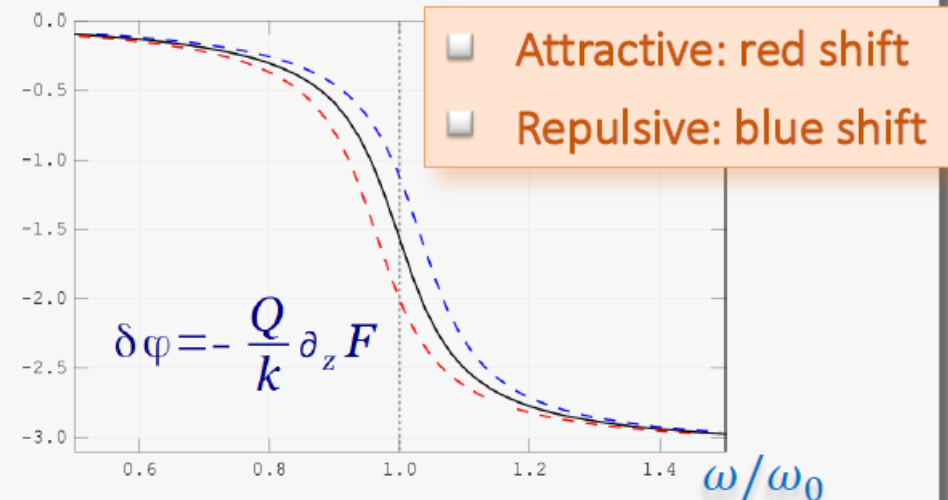
The cantilever as an oscillator

$$m \ddot{z} + \Gamma \dot{z} + k z = F(z)$$

$$\text{with: } F(z) = F(z_0) + (z - z_0) \partial_z F$$

More renormalization: $\omega_{o,eff} = \omega_0 \left(1 - \frac{1}{2k} \partial_z F \right)$

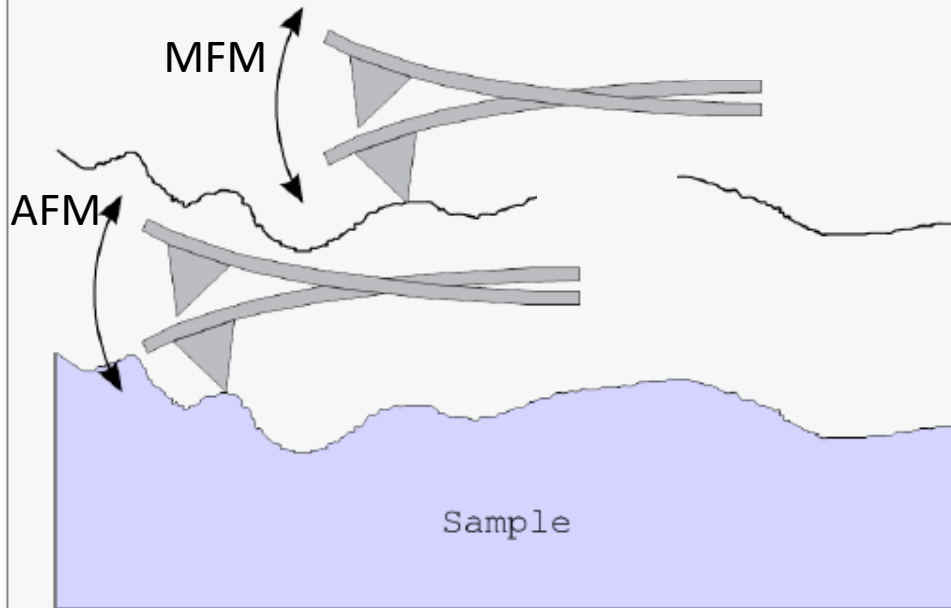
Probing forces with the phase shift



AFM characterizes topography

Magnetic force microscopy (MFM)

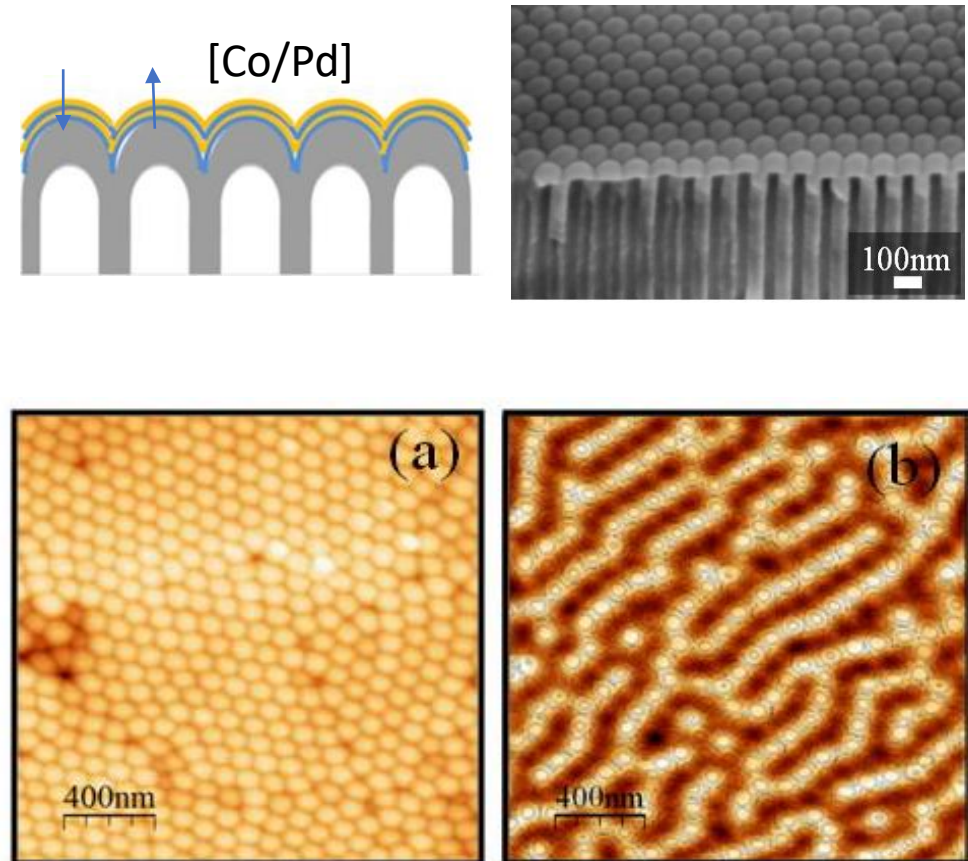
MFM : two-pass technique



- First pass: measure topography
 - Second pass: measure magnetism
- NB: other measurement modes exist

Y. Zhu Ed., Modern techniques for characterizing magnetic materials, Springer (2005)

Example: magnetic domain configuration of [Co/Pd] multilayer on patterned substrate



L. Piroux et al., APL 101, 013110 (2012)

Magnetic force microscopy : criteria

What is measured? ✓

- ☒ Stray field? ✓
- ☐ Indirect?
- ☐ Hardly quantitative

Environmental conditions ✓

- ☐ Temperature ✓
- ☐ Field: magnetic field, electric
- ☐ Electric current, light etc.
- ☐ Strain
- ☐ Additional measuring techniques

Which specifications? ✓

- ☐ Depth resolution: surface/volume
- ☐ Lateral resolution: 25-50nm
- ☐ Sensitivity: medium (1nm thickness)
- ☐ Time/Spectral resolution: slow

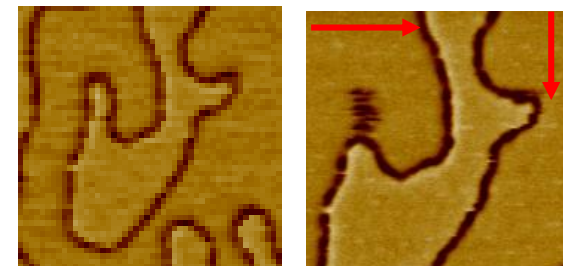
Versatility ✓

- ☐ No sample preparation needed
- ☐ Time per measurement: few mn
- ☐ Ex situ
- ☐ In-lab, cheap
- ☒ May influence sample ✓

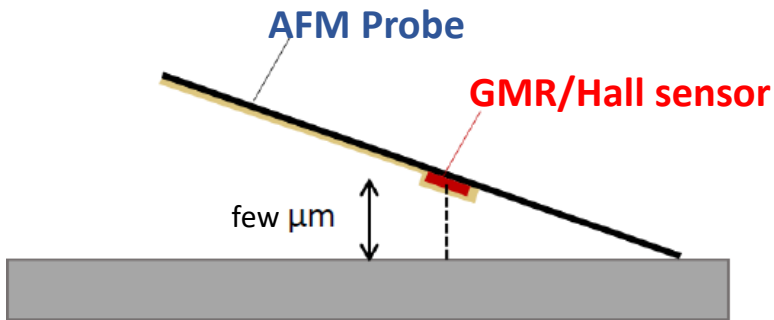
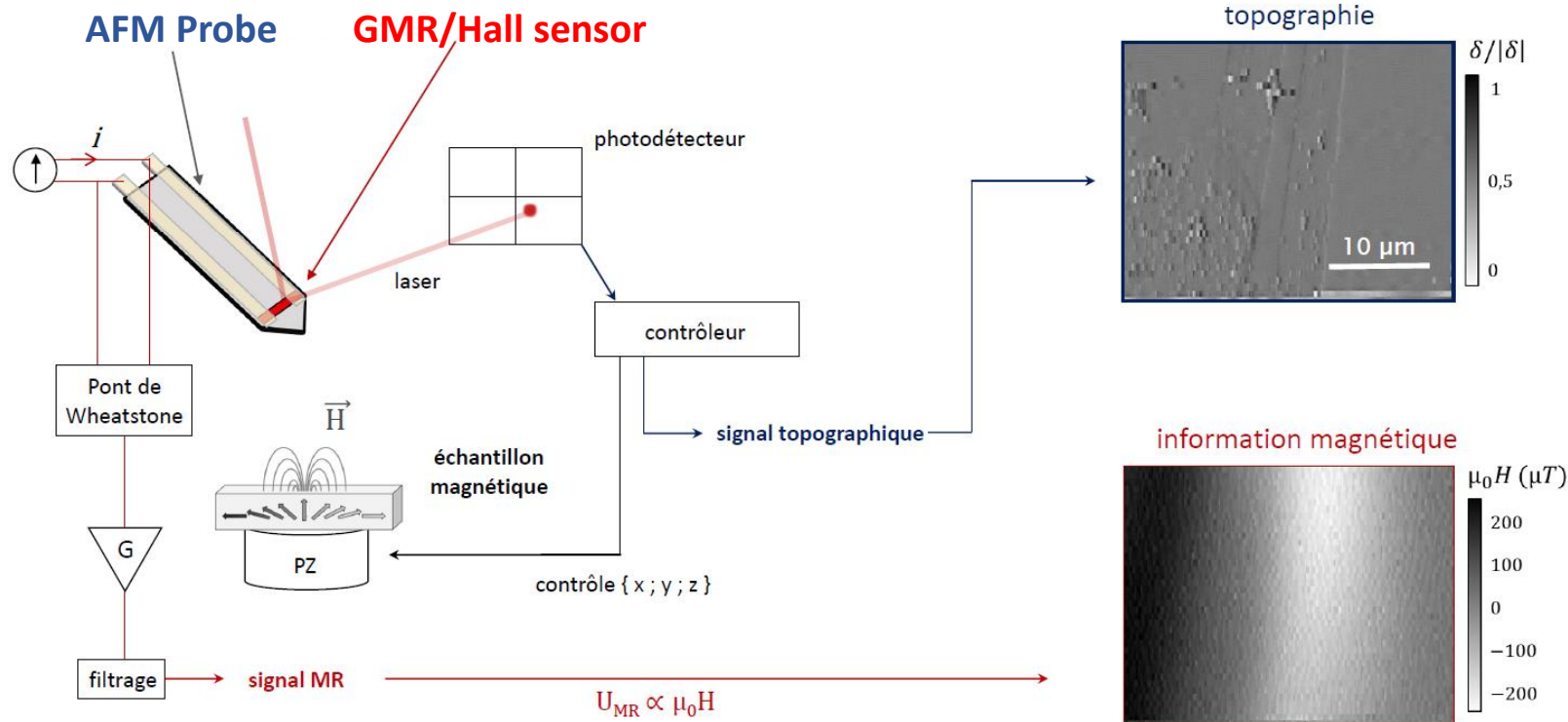


Tip-sample interactions can impact the magnetic configuration of your sample

scanning direction



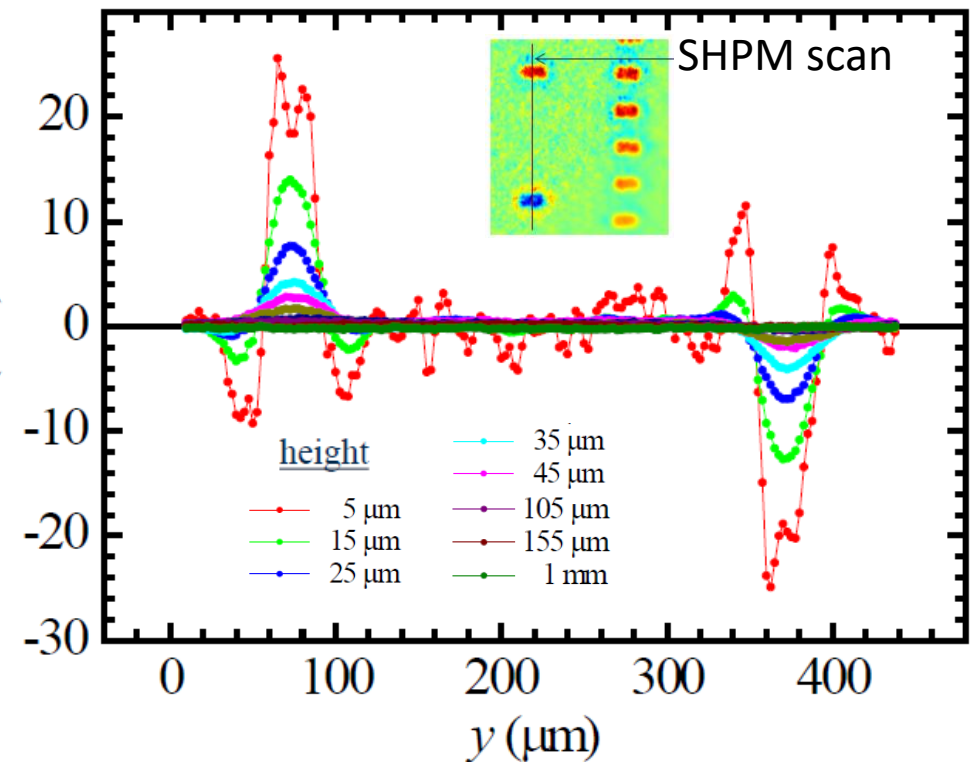
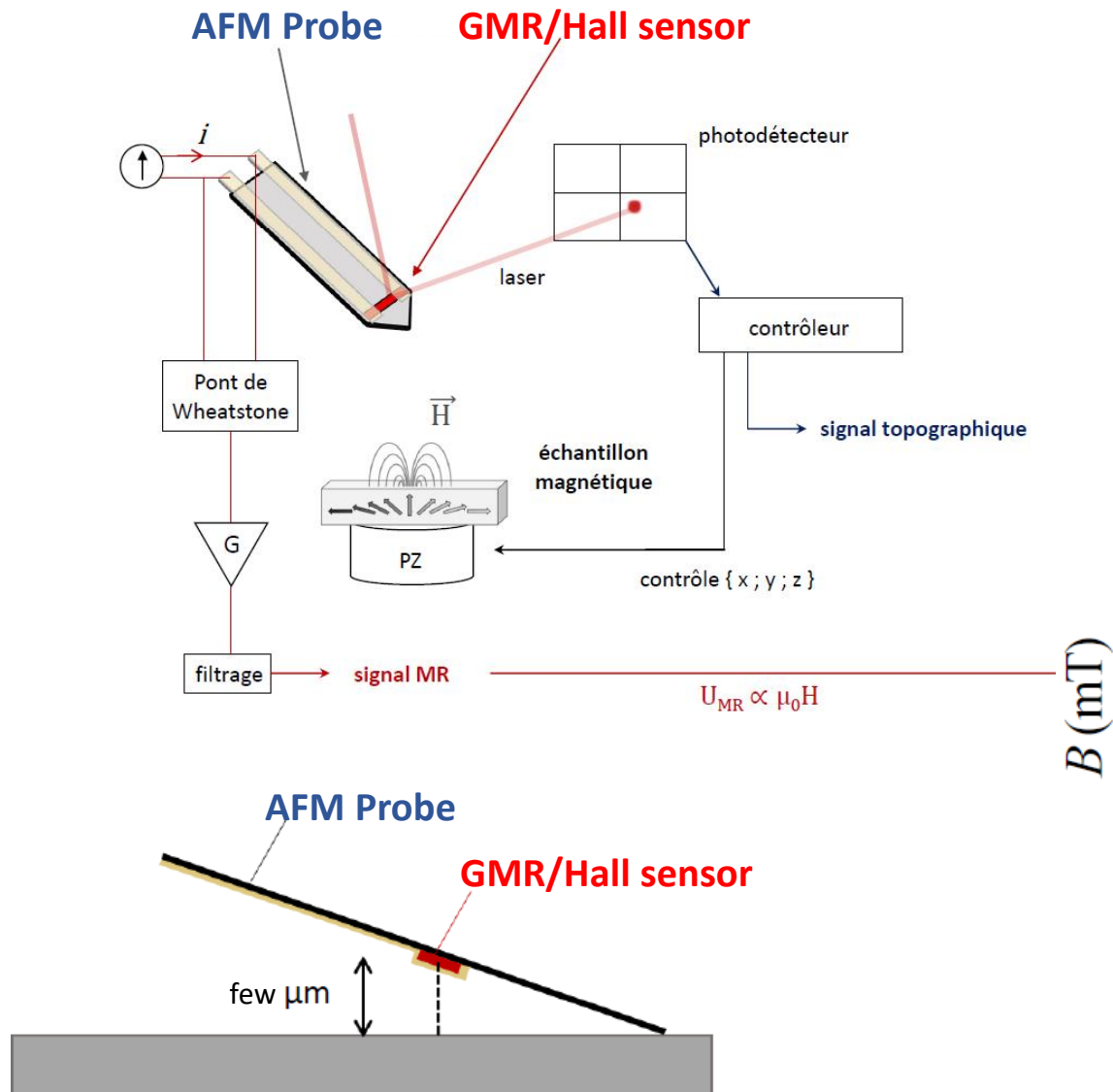
Scanning GMR/Hall probe microscopy



Advantage : To get a direct access to magnetic field instead of its second derivative as in MFM

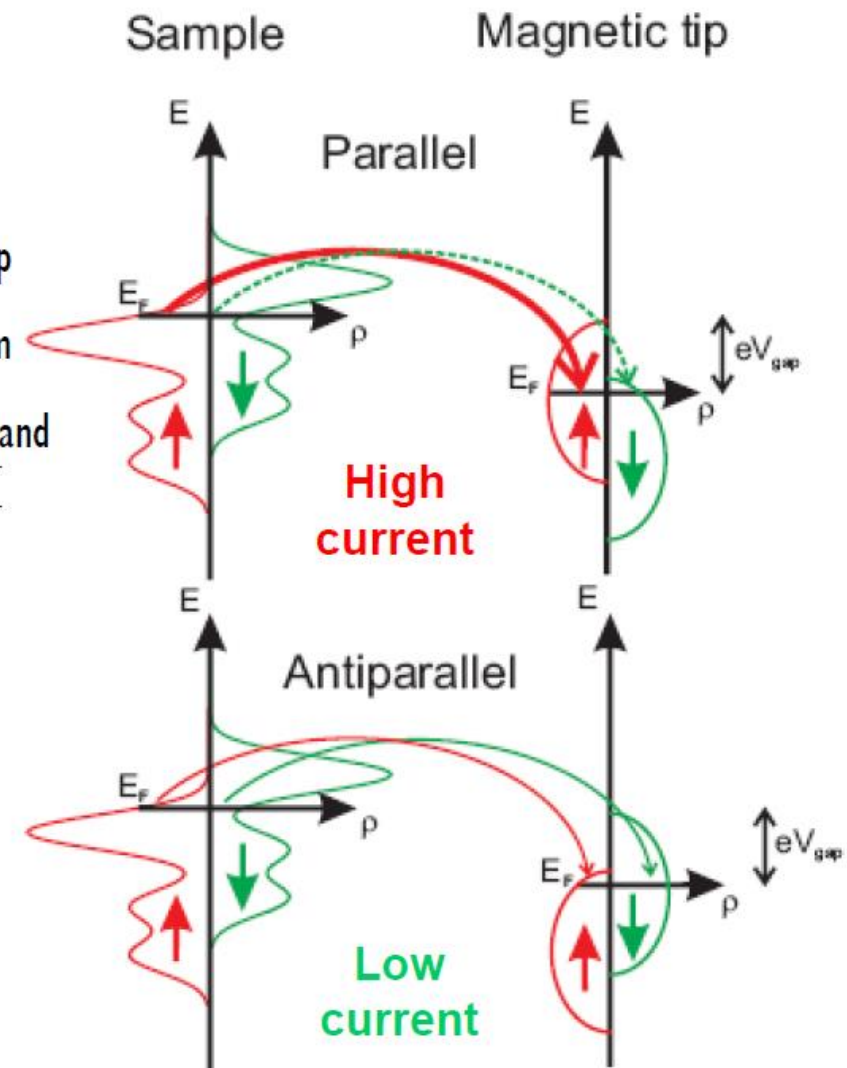
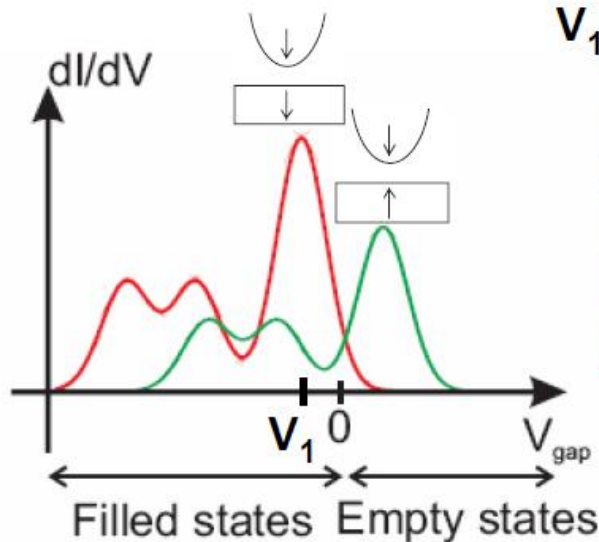
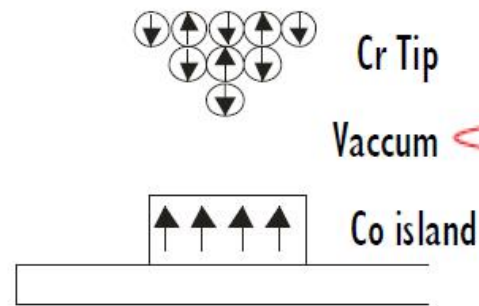
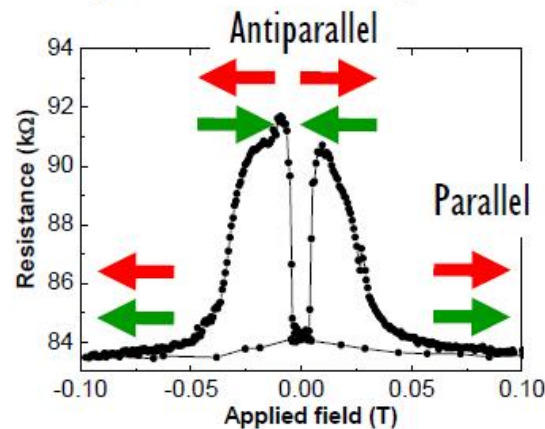
Scanning GMR/Hall probe microscopy

Advantage : To get a direct access to magnetic field instead of its second derivative as in MFM



Spin-polarized Scanning Transmission Microscope

Magnetic tunnel junction with vacuum



Bode, Getzlaff, Wiesendanger, Phys. Rev. Lett. 81, 4256 (1998).

Wulfhekel, Kirschner, Appl. Phys. Lett. 75, 1944 (1999)

Spin-polarized Scanning Transmission Microscope

What is measured?

- ☐ Related to magnetization and element
- ☐ Indirect?
- ☐ Not quantitative

Environmental conditions

- ☐ Low temperature only
- ☐ Field: magnetic field
- ☐ Light

Which specifications?

- ☐ Magnetization: 3D
- ☐ Depth resolution: surface.
- ☐ Lateral resolution: atom
- ☐ Sensitivity: high
- ☐ Time/Spectral resolution: emerging

Versatility

- ☐ Ultra-high vacuum and single crystal
- ☐ Time per measurement: minutes
- ☐ Mid-scale in-lab.

Outline

I. Few preliminary details about the sample environment

➡ Magnetic field, Temperature

II. Static macroscopic magnetometry techniques

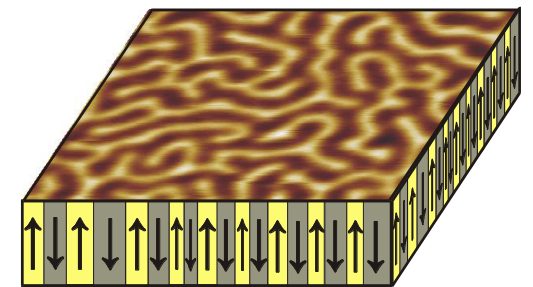
➡ VSM, SQUID, Torque, MOKE, XMCD

III. AC macroscopic magnetometry techniques

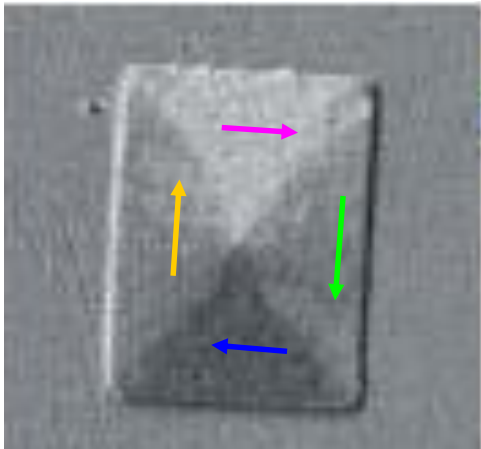
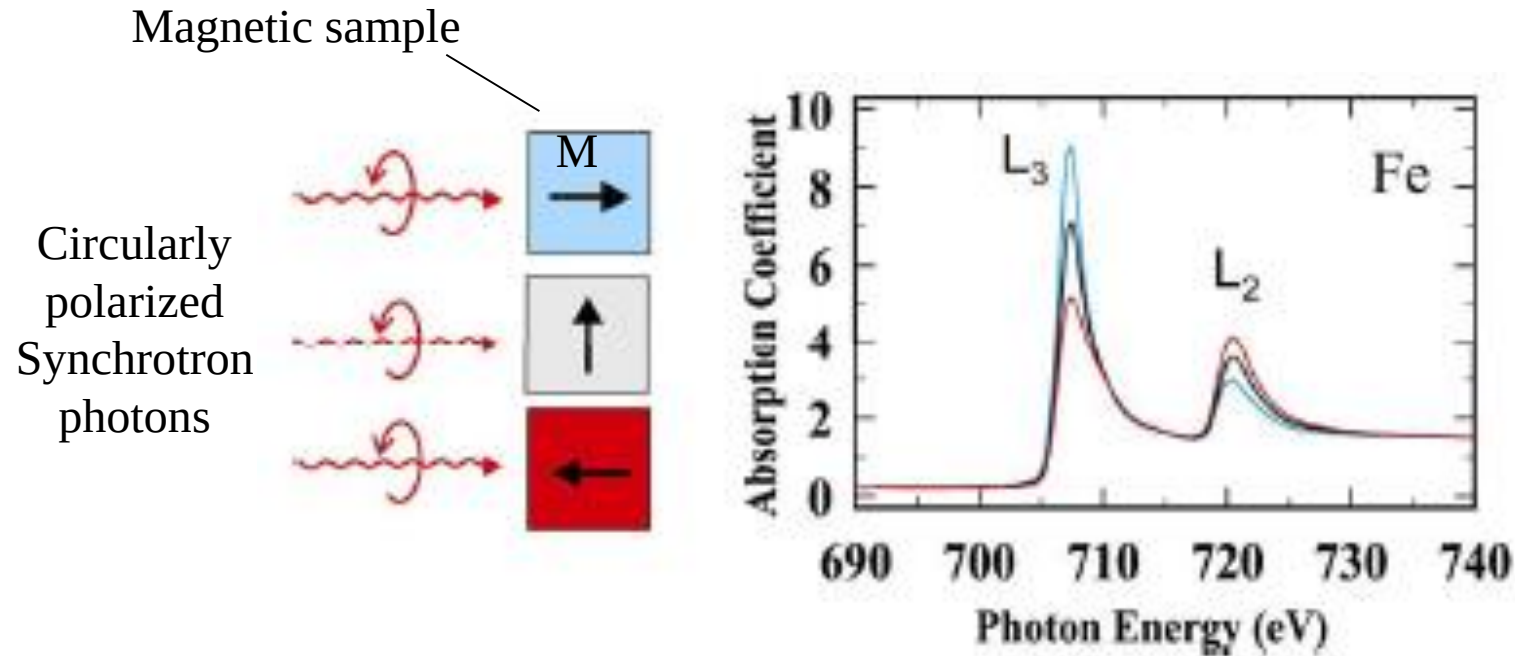
➡ AC susceptometry

IV. Imaging techniques

➡ Scanning probe microscopies, **Photon-out**



Using XMCD contrast to image



X-ray absorption depends on the angle of incidence regarding to the magnetic moment direction

=> **Magnetic contrast**

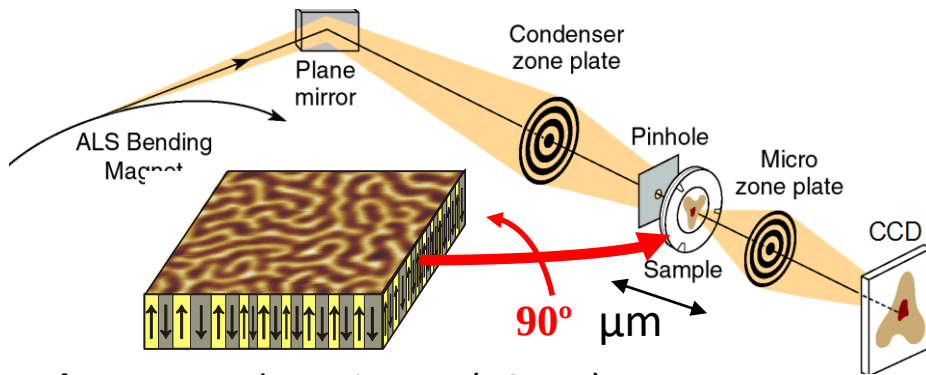
BONUS : Absorption depends on electronic transitions

=> **Chemical selectivity**

X-ray microscopy

Transmission X-ray microscopy (TXM)

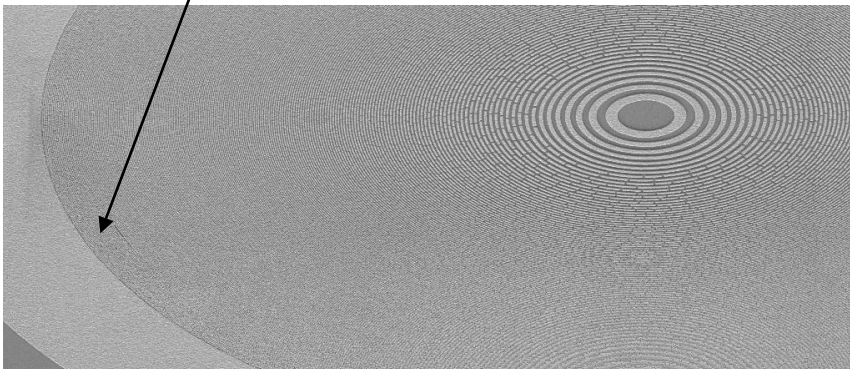
(ALS, SLS, BESSY II, ANKA)



Advantages : large image (10 μm)
with good, 50ps time resolution

Disadvantages : mostly 300K, small field, lenses

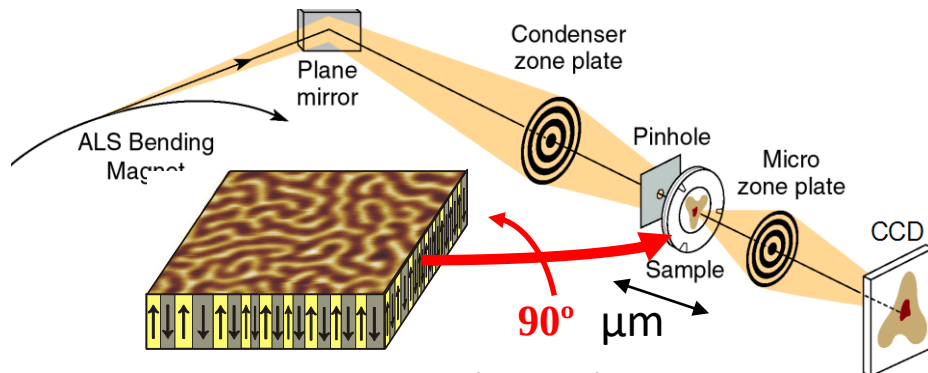
Distance between 2 circles => resolution (here 15 nm)



X-ray microscopy

Transmission X-ray microscopy (TXM)

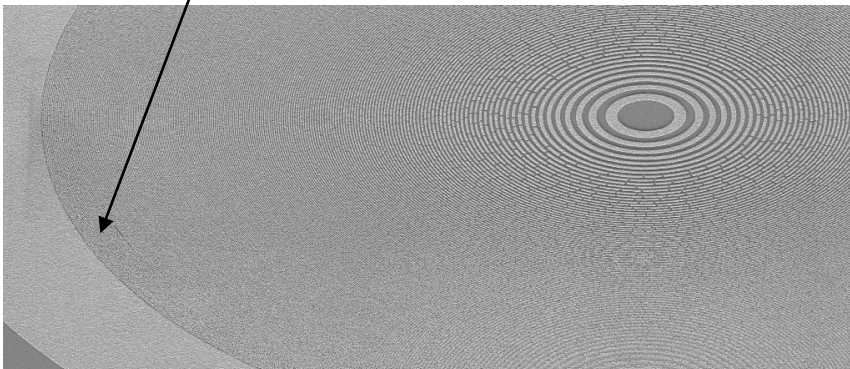
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with good, 50ps time resolution

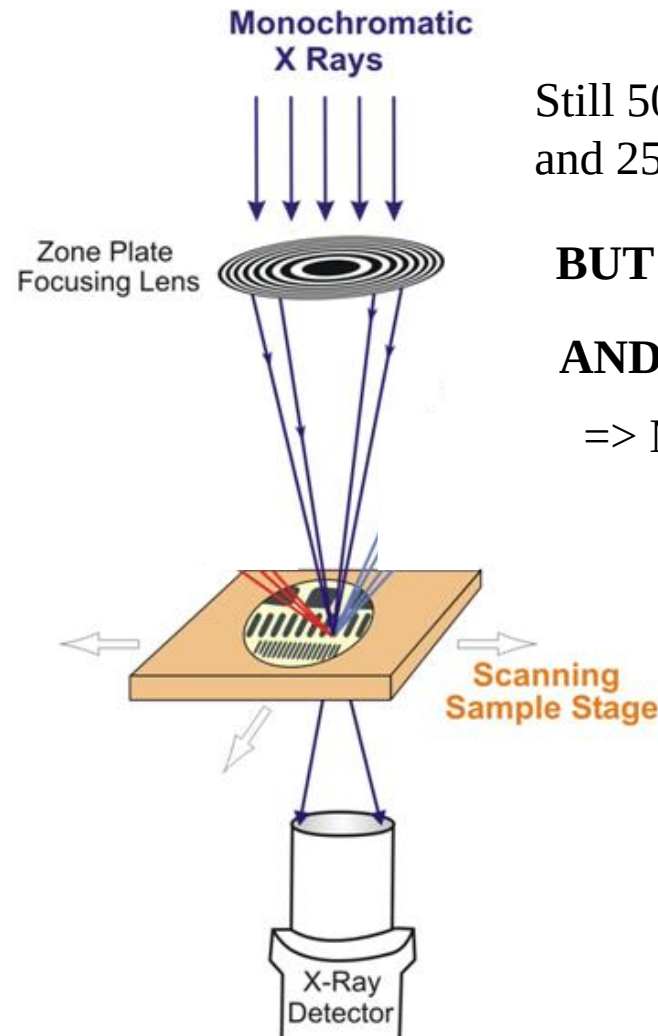
Disadvantages : mostly 300K, small field, lenses

Distance between 2 circles => resolution (here 15 nm)



Scanning TXM

(ALS, SSRL, SLS, Soleil)



Still 50 ps time resolution
and 25 nm resolution

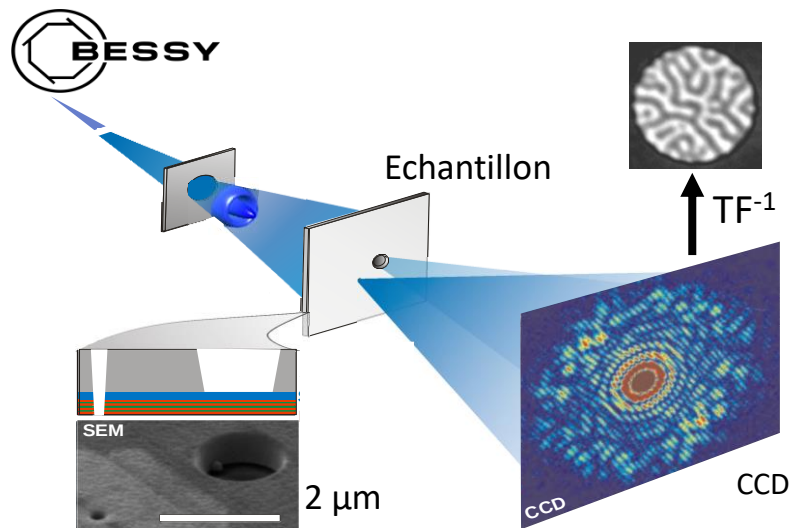
BUT Only one lense

AND Scanning

=> More flux locally

X-ray microscopy

X-ray Holography



Advantage : 400K-10K, more space around the sample

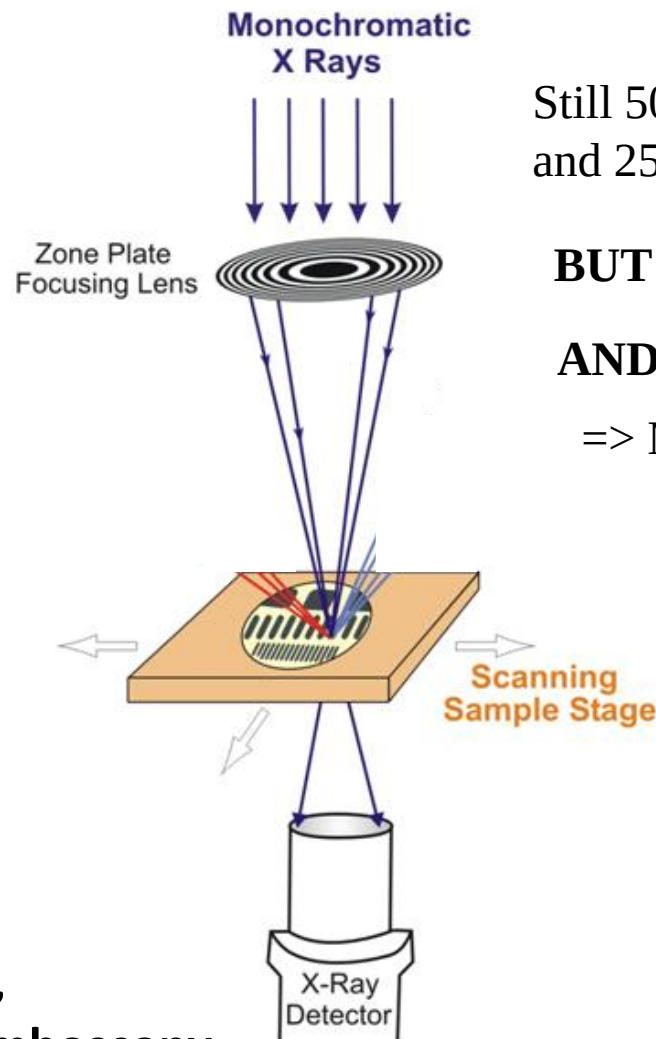
Disadvantage : sample preparation,
limited image size ($< 2 \mu\text{m}$)
Loss in resolution (50nm)
Phase retrieval



**Dynamics in MTXM, STXM,
Holography requieres stromboscopy**

Scanning TXM

(ALS, SSRL, SLS, Soleil)



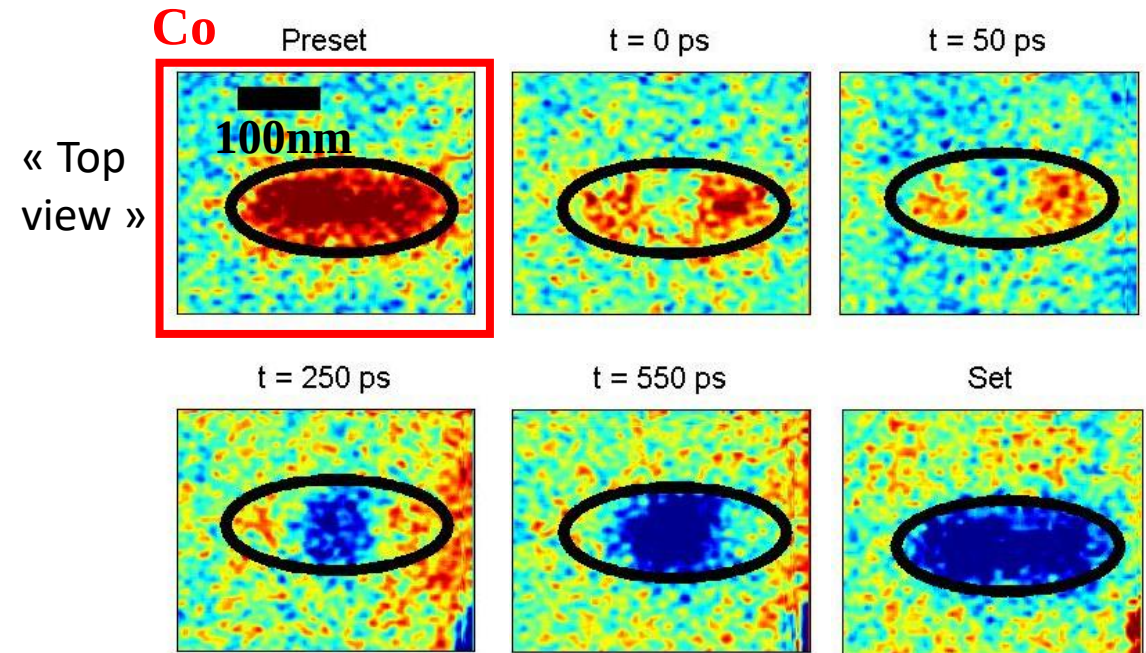
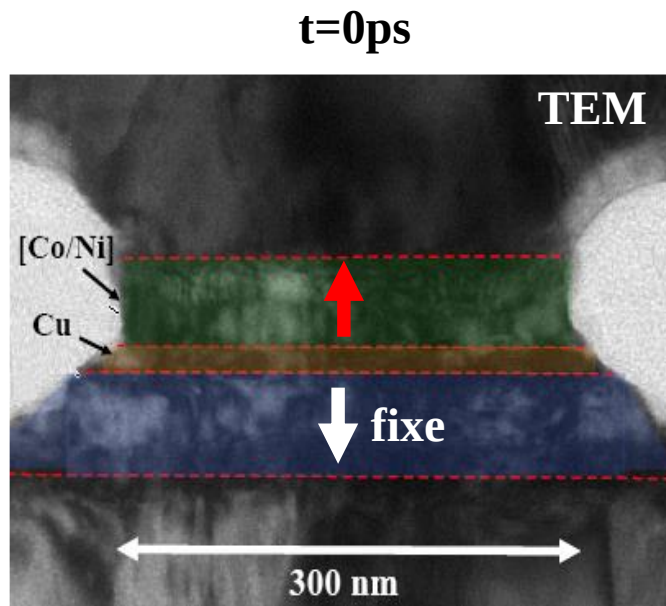
Still 50 ps time resolution
and 25 nm resolution

BUT Only one lense

AND Scanning

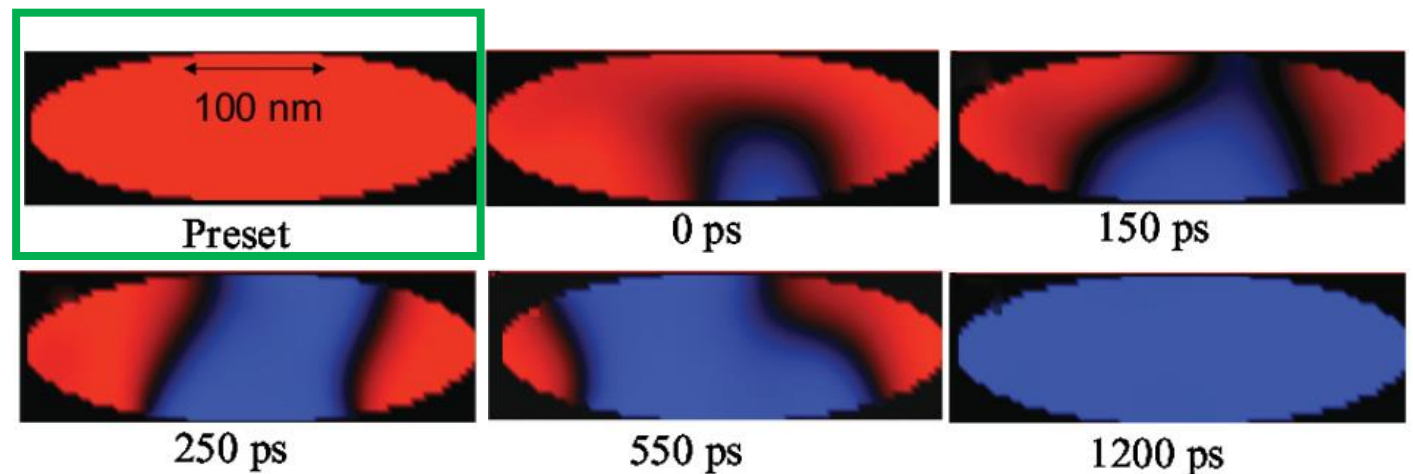
=> More flux locally

Example : STT-induced switching by STXM

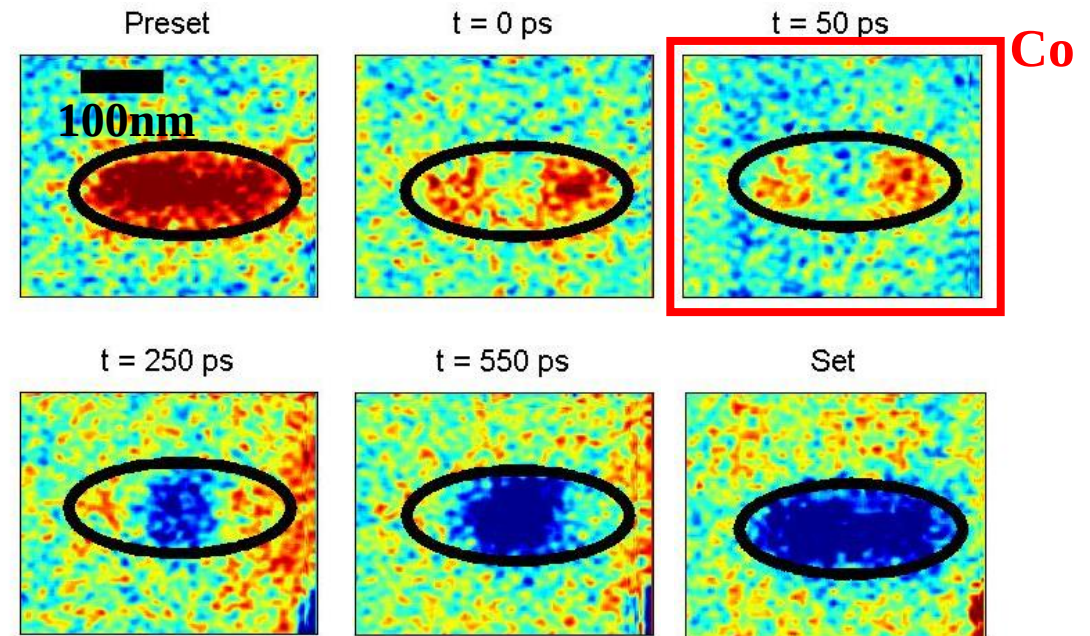
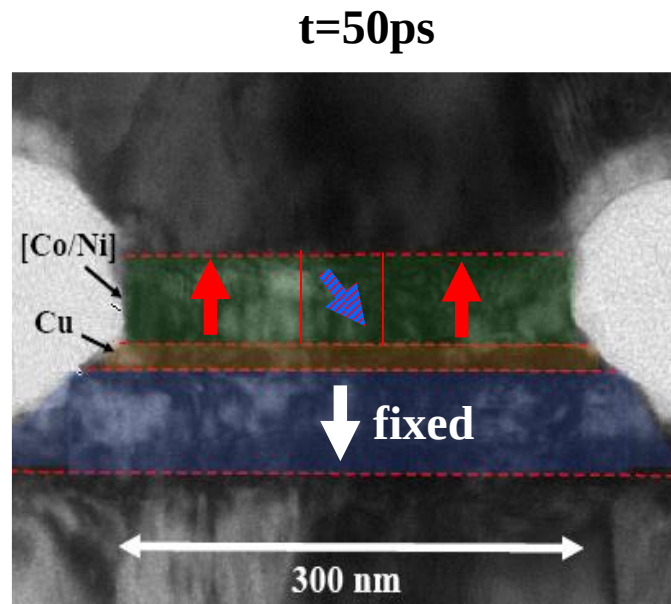


Excitation : Current pulsed at t=0ps

Micromagnetic simulation
(Scheinfel code)

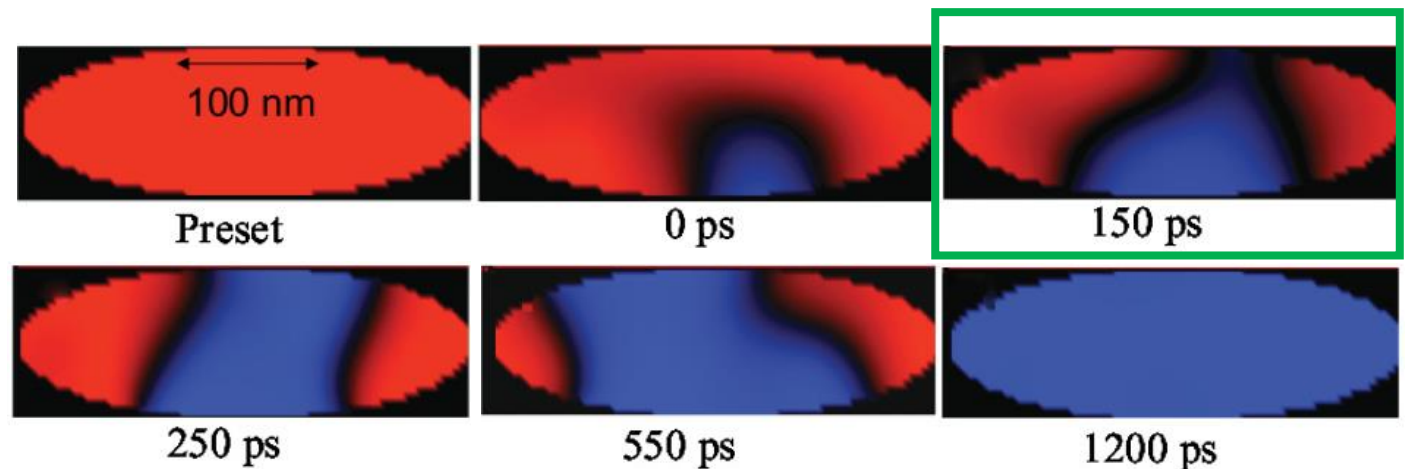


Example : STT-induced switching by STXM

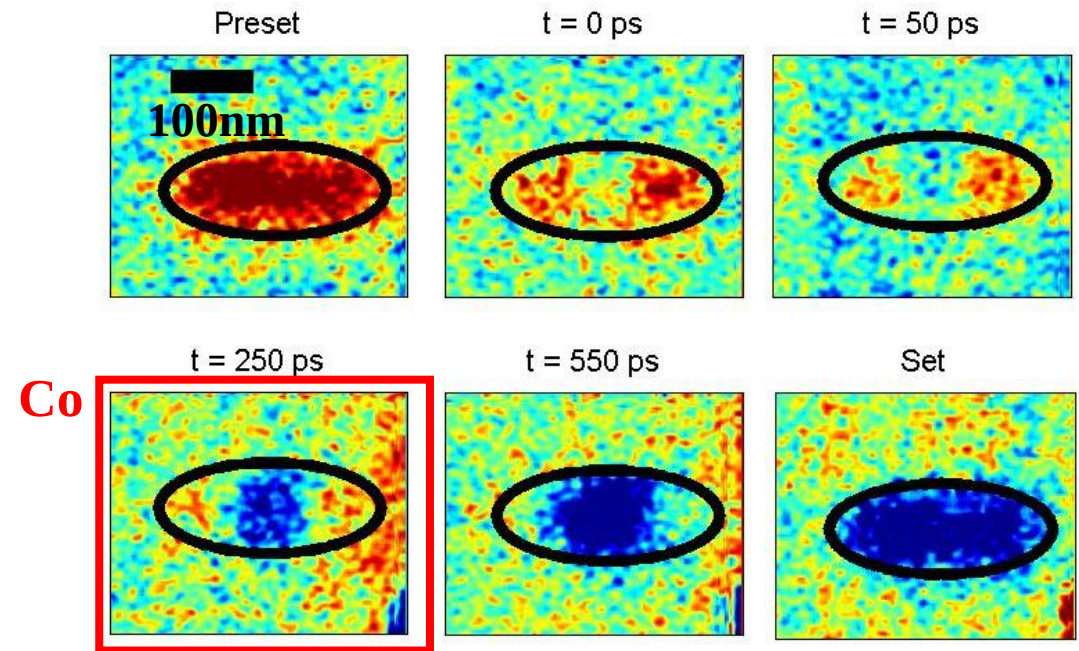
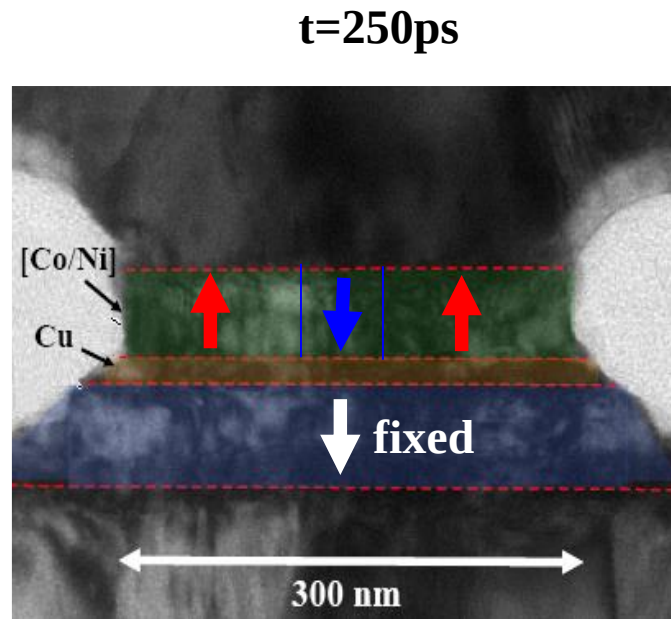


Excitation : Current pulsed at $t=0\text{ps}$

Micromagnetic simulation
(Scheinfel code)

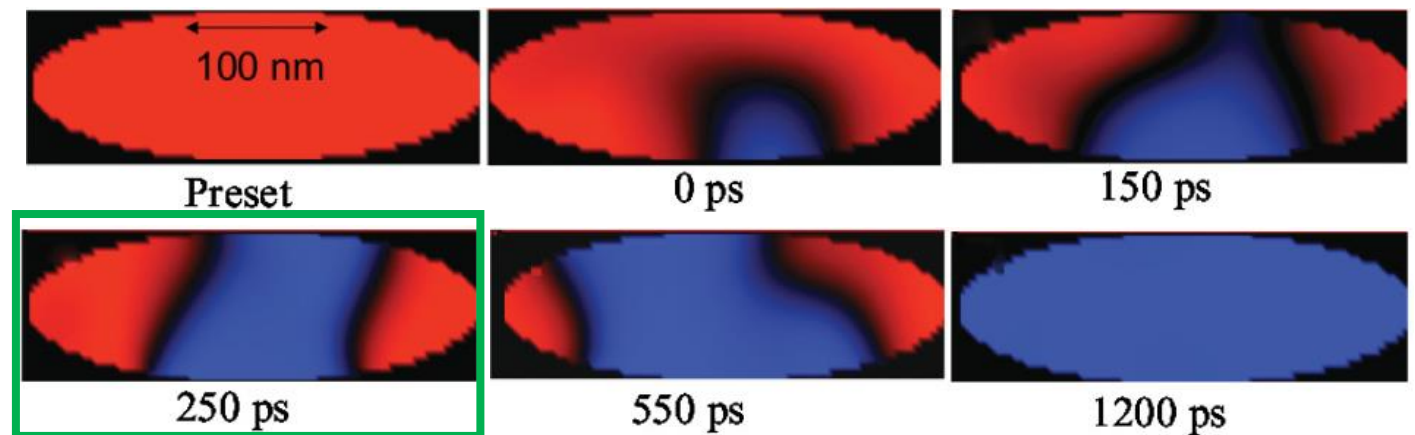


Example : STT-induced switching by STXM

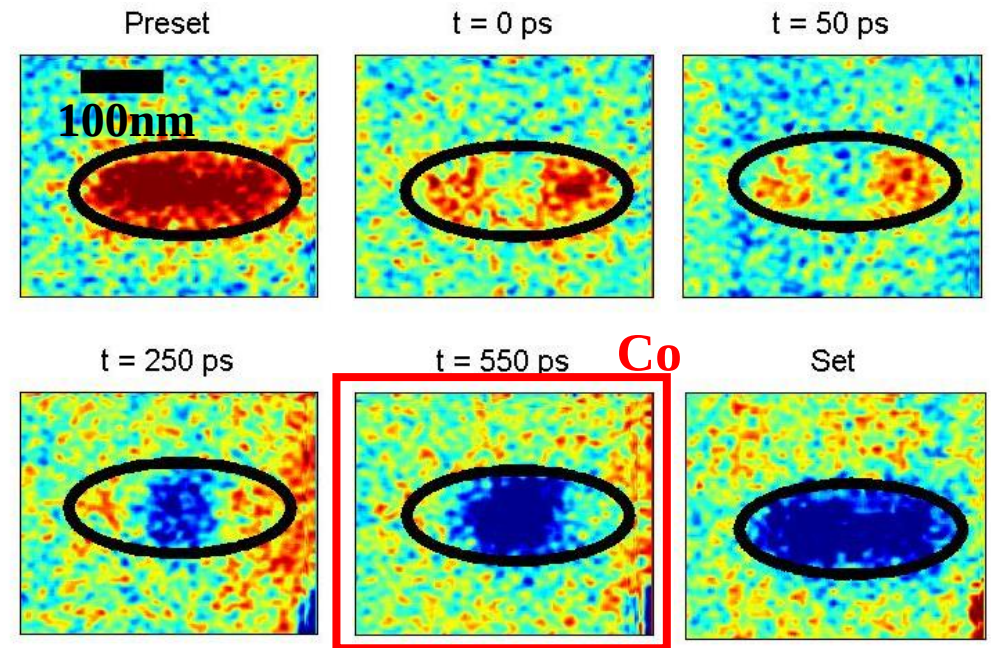
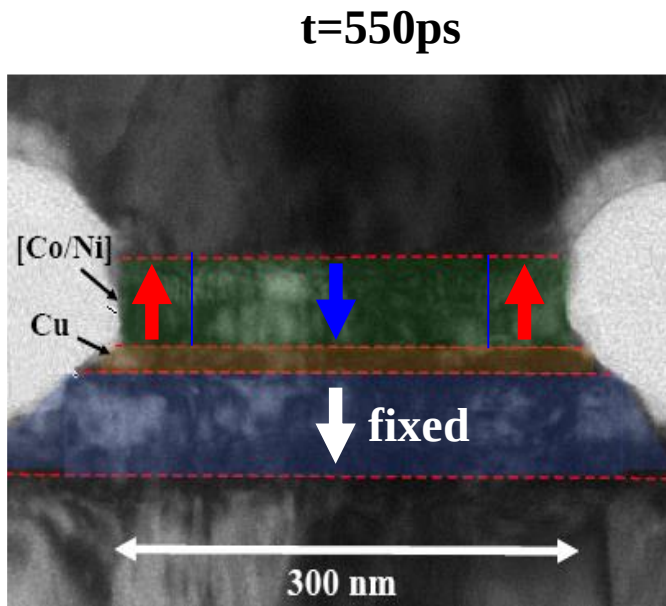


Excitation : Current pulsed at $t=0\text{ps}$

Micromagnetic simulation
(Scheinfel code)

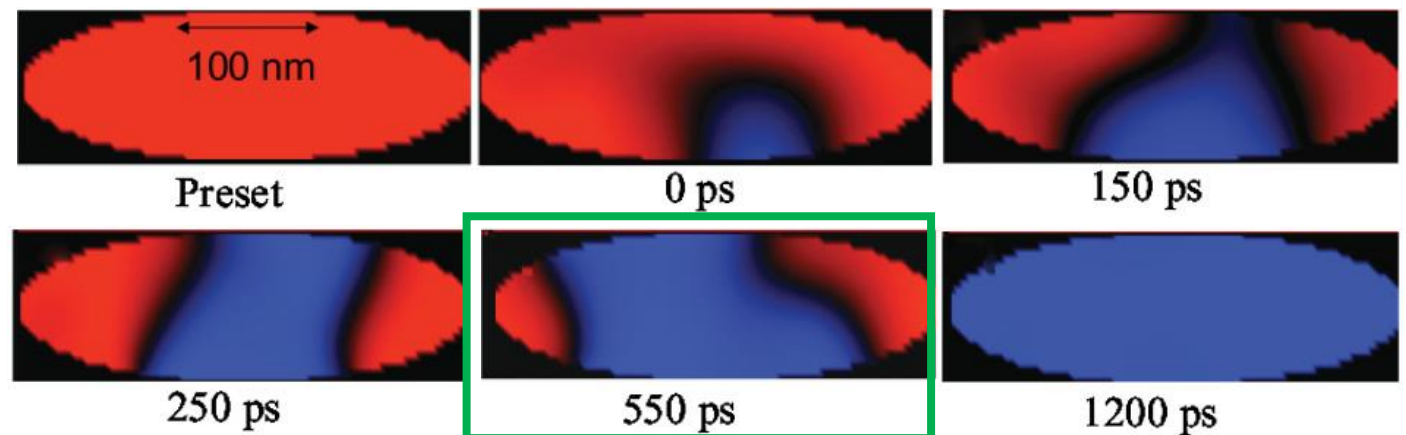


Example : STT-induced switching by STXM

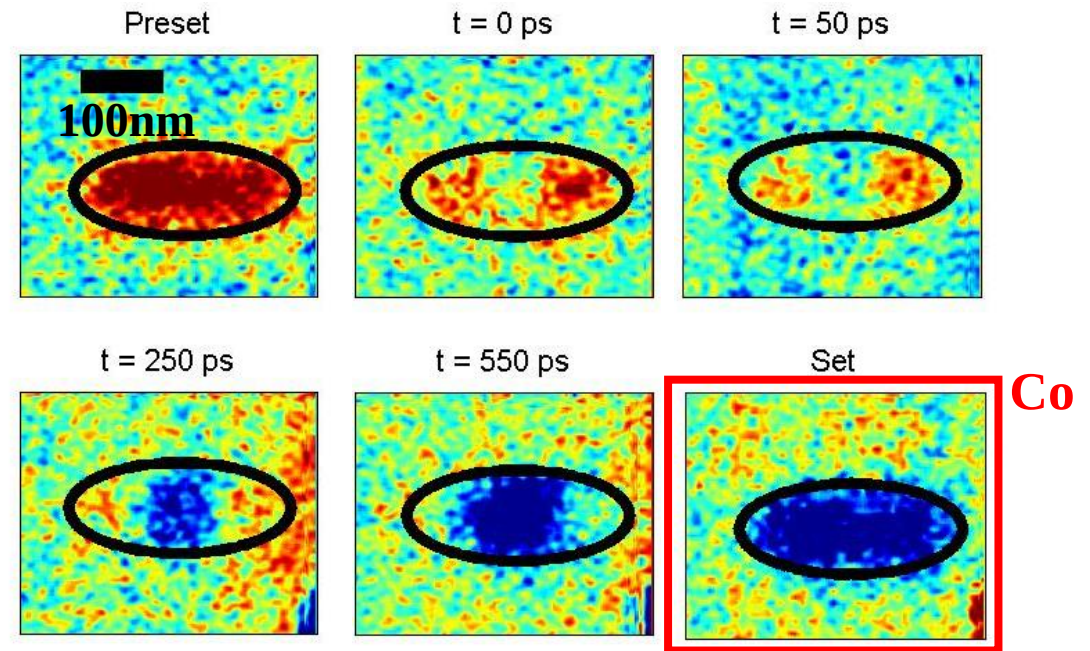
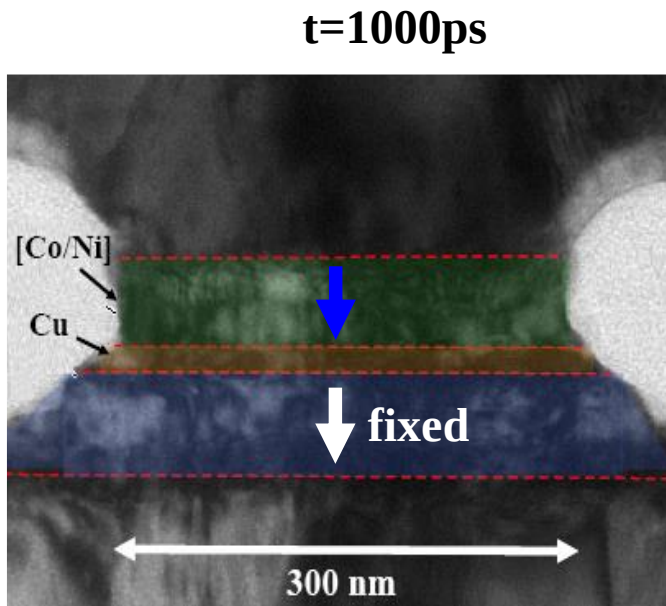


Excitation : Current pulsed at $t=0\text{ps}$

Micromagnetic simulation
(Scheinfel code)

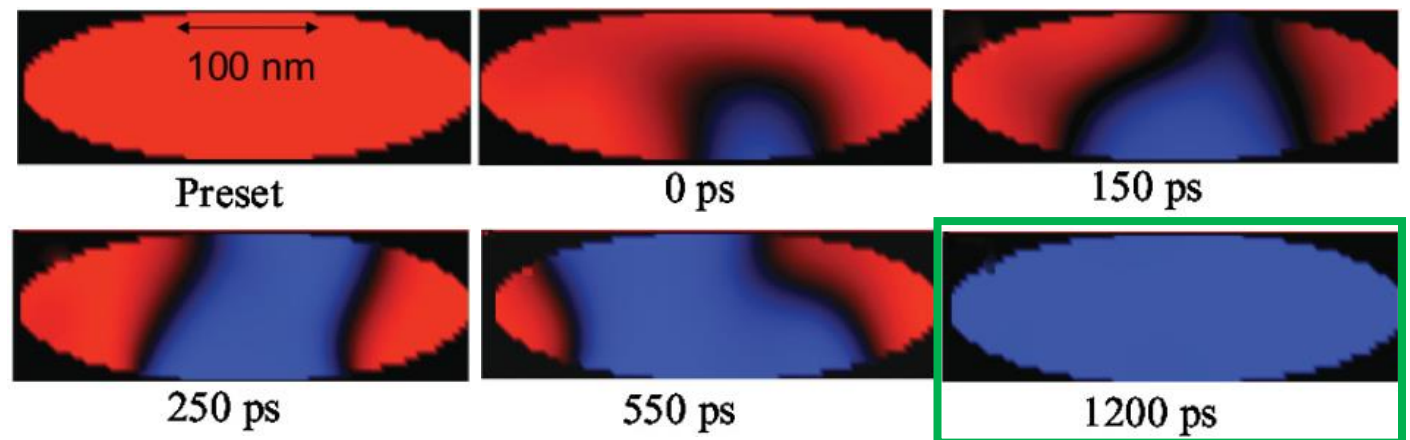


Example : STT-induced switching by STXM



Excitation : Current pulsed at $t=0\text{ps}$

Micromagnetic simulation
(Scheinfel code)



X-ray microscopy : criteria

What is measured?

- ☐ Magnetization component
- ☐ Elemental resolution
- ☐ Direct
- ☐ Quantitative

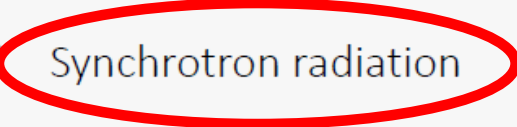
Environmental conditions

- ☐ Temperature 
- ☐ Field: magnetic field (not PEEM) 
- ☐ Electric current, light etc. 
- ☐ Strain 
- ☐ Additional measuring techniques

Which specifications?

- ☐ Magnetization: 1D, 2D 
- ☐ Depth resolution: surface/volume 
- ☐ Lateral resolution 25 nm 
- ☐ Sensitivity: <single layer 
- ☐ Time/Spectral resolution 

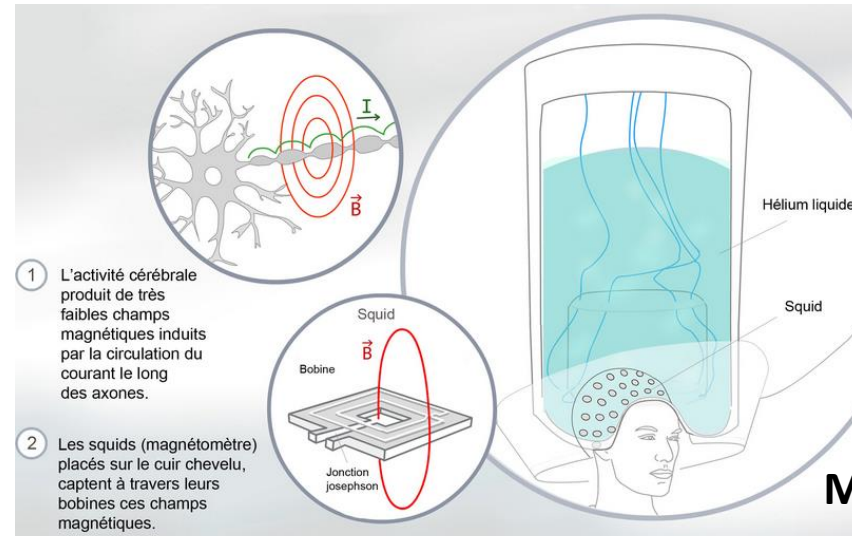
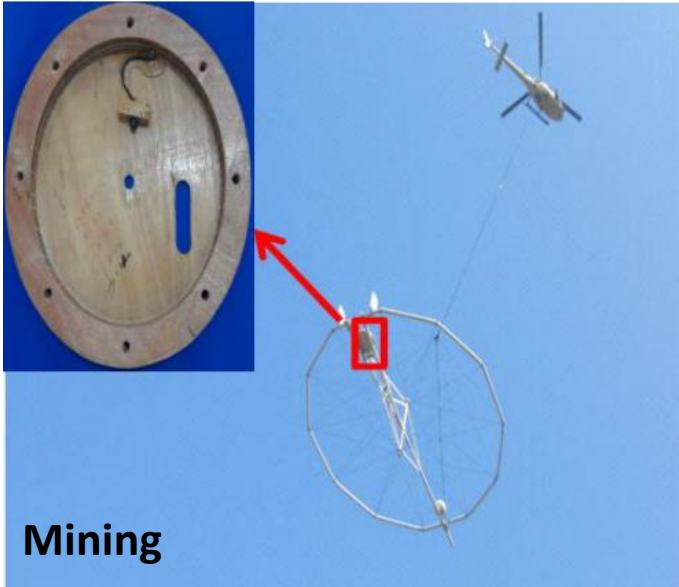
Versatility

- ☐ No sample preparation
- ☐ Time per measurement: s – min
- ☐ In situ
- ☐ Synchrotron radiation 

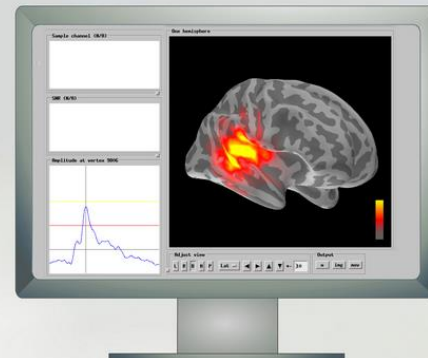
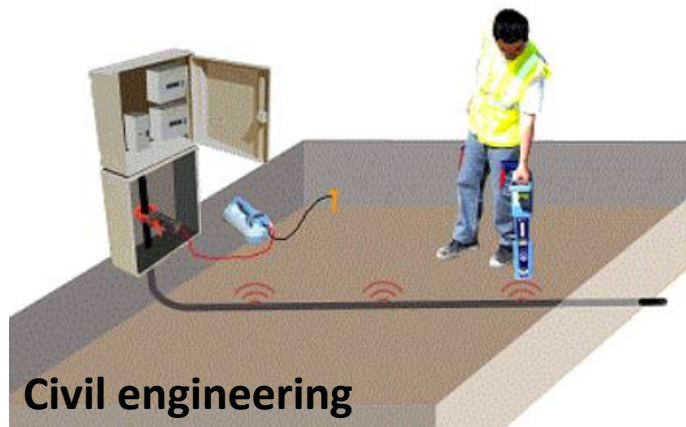
e-ESM, an online
higher-education Magnetism event

Magnetometers are not only lab tools

Here I focused on material characterization in lab but magnetometers can be used in many ways



Medecine



Metallurgy



Few references

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And many more at : <http://magnetism.eu/esm/repository-topics.html>

